

TEST REPORT

Applicant Name: AGM MOBILE LIMITED
Address: FLAT/RM 2253 22/F HOI TAI FACTORY ESTATE TSING YEUNG
CIRCUIT TUEN MUN NT HONG KONG CHINA
Report Number: 2501X79543E-RF-07A

Test Standard (s)

Item 19 of Article 2 Paragraph 1

Sample Description

Product Type: TWS Bluetooth Headset
Model No.: AGM BUDS 9
Multiple Model(s) No.: N/A
Trade Mark: N/A
Date Received: 2025-09-28
Issue Date: 2026-01-13

Test Result:

Pass▲

▲ In the configuration tested, the EUT complied with the standards above.

Prepared and Checked By:

Allen Bai

Allen Bai
RF Engineer

Approved By:

Nancy Wang

Nancy Wang
RF Supervisor

Note: The information marked * is provided by the applicant, the laboratory is not responsible for its authenticity and this information can affect the validity of the result in the test report. Customer model name, addresses, names, trademarks etc. are included.

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DOCUMENT REVISION HISTORY

Revision Number	Report Number	Description of Revision	Date of Revision
0	2501X79543E-RF-07A	Original Report	2026-01-13

GENERAL INFORMATION

Product Description for Equipment under Test (EUT)

Technical Parameters	Radio Type	Bluetooth
	Modulation Type	GFSK, $\pi/4$ -DQPSK, 8DPSK
	Frequency Range	2402-2480MHz
	Rated Output Power	0.01 mW/MHz for BDR/EDR Mode
	Antenna Gain[#]	2.78 dBi (It is provided by the applicant)
Nominal Power Supply		DC 5V from Charging case or DC 3.7V from battery
Sample serial number		3AO6-3 (Assigned by BACL, Shenzhen)
Sample/EUT Status		Good condition
Adapter Information		N/A
Note: The left ear bud and right ear bud are the same, so left ear bud was selected for fully testing		

Objective

The objective of the manufacturer is to demonstrate compliance with Certification Ordinance Article 2-1-19, rules and limits for this device including:

- Frequency Error
- Occupied Bandwidth and Spreading Bandwidth
- Transmitter Spurious Emission and Unwanted Emission Intensity
- Antenna Output Power And Output Power Tolerance
- Receiver Spurious Emission Strength
- Frequency Hopping Dwell Time
- Interference Prevention Function
- Construction Protection Confirmation

Test Method

MIC Notice No.88 Appendix No.43

Measurement Uncertainty

Item	Expanded Measurement uncertainty
Frequency Error	56.6Hz(k=2, 95% level of confidence)
Occupied Channel Bandwidth	109.2kHz(k=2, 95% level of confidence)
RF output power, conducted	0.86dB(k=2, 95% level of confidence)
Unwanted Emission, conducted	1.60dB(k=2, 95% level of confidence)
Duty Cycle	±1%
Temperature	±1°C
Supply voltages	±0.4%
Humidity	±1%

Note: The extended uncertainty given in this report is obtained by combining the standard uncertainty times the coverage factor K with the 95% confidence interval. Otherwise required by the applicant or Product Regulations, Decision Rule in this report did not consider the uncertainty.

Test Facility

The Test site used by Bay Area Compliance Laboratories Corp. (Shenzhen) to collect test data is located on the 5F(B-West) , 6F, 7F, the 3rd Phase of Wan Li Industrial Building D, Shihua Rd, FuTian Free Trade Zone, Shenzhen, China.

Each test item follows test standards and with no deviation.

EUT TEST CONFIGURATION

Description of Test Configuration

The system was configured for testing in a testing mode which was selected by manufacturer.

Normal/Extreme Voltage Condition[#]

NV	Normal Voltage	3.7V _{DC}
LV	Low Voltage	3.33V _{DC}
HV	High Voltage	4.07V _{DC}
Note: extreme voltage test conditions were declared by manufacturer.		

EUT Exercise Software

Exercise Software [#]	FCC_assist_1.0.2.2
Power Level [#]	5

Equipment Modifications

No modification was made to the EUT tested.

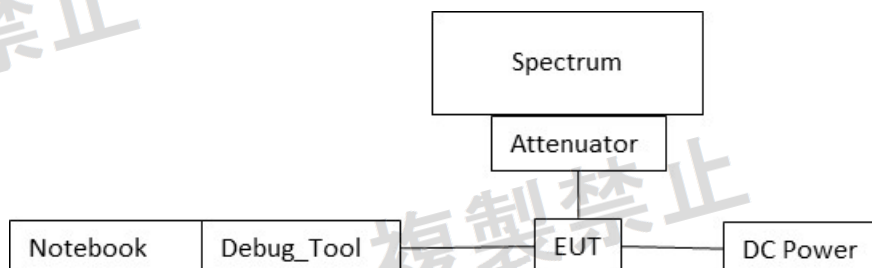
Support Equipment List and Details

Manufacturer	Description	Model	Serial Number
Unknown	Debug_Tool	Unknown	Unknown
Dell	Notebook	Latitude E5430	SGJ8NK1
instek	DC Power	GPS-3030DD	EM832096

External I/O Cable

Cable Description	Length(m)	From/Port	To
Unshielded Detachable Dupont cable	0.1	EUT	Debug_Tool
Unshielded Un-detachable RF cable	0.1	EUT	Attenuator
Unshielded Detachable DC cable	1.5	EUT	DC Power

Configuration of Test Setup



SUMMARY OF TEST RESULTS

MIC Notice No.88 Appendix No.43 Article 2, Paragraph 1, Item 19	Description of Test	Result
1	Frequency Error	Compliant
2	Occupied Bandwidth and Spreading Bandwidth	Compliant
3	Transmitter Spurious Emission and Unwanted Emission Intensity	Compliant
4	Antenna Output Power and Output Power Tolerance	Compliant
5	Receiver Spurious Emission and Unwanted Emission Intensity	Compliant
6	Transmission Antenna Gain	Not Applicable
7	Transmission Radiation Angle Width	Not Applicable
8	Frequency Hopping Dwell Time	Compliant
9	Interference Prevention Function	Compliant
10	Construction Protection Confirmation	Compliant

Not Applicable - This test item was not required for the output power less than 6.91 dBm/MHz (E.I.R.P)

TEST EQUIPMENT LIST

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date	Calibration Authority	Calibration Method
JD	JD Auto TestSystem	NA	1.0.0.3769	NCR	NCR	/	/
Unknown	6dB Attenuator	Unknown	F-03-EM123	2025/06/26	2026/06/25	BACL	d)
Rohde & Schwarz	Spectrum Analyzer	FSV40	101473	2025/09/01	2026/08/31	CCIC	c)
Rohde & Schwarz	Spectrum Analyzer	FSU26	200120	2024/12/04	2025/12/03	BACL Cal	c)
Tonscend	RF control Unit	JS0806-2	19D8060154	2025/07/18	2026/07/17	BACL Cal	c)
instek	DC Power Supply	GPS-3030DD	EM832096	NCR	NCR	/	/
Fluke	Digital Multimeter	287	19000011	2025/04/29	2026/04/28	BACL Cal	c)
Rohde&Schwarz	Wideband Radio Communication Tester	CMW500	141718	2025/07/18	2026/07/17	BACL Cal	c)

Note: Calibration Method

a) Calibration conducted by the National Institute of Information and Communications Technology (NICT) or a designated calibration agency under Article 102-18 paragraph (1)

b) Correction conducted pursuant to the provisions of Article 135 or Article 144 of the Measurement Law (Law No. 51 of 1992) ~Japan Calibration Service System~

c) Calibration conducted in foreign countries, which shall be equivalent to the calibration conducted by the NICT or a designated calibration agency under Article 102-18 paragraph (1)

d) Calibration conducted by using other equipment that listed above from a) to c)

*** Statement of Traceability:** Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to requirements that traceable to National Primary Standards and International System of Units (SI).

REQUIREMENTS AND TEST PROCEDURES

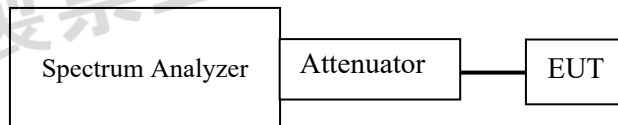
Frequency Error

Limit

50 ppm or below

Test Procedure

Measurement System Diagram



Conditions of Application Equipment (EUT)

- Set the application equipment (EUT) to the measurement frequency.
- The modulation state shall be “continuous carrier wave without modulation” by stopping frequency-hopping mode.

Spectrum Analyzer Conditions

- Center Frequency: Frequency to measure (2402 MHz, 2441MHz, and 2480MHz)
- RBW: 1 kHz, VBW: 1 kHz
- Span: 300kHz
- Sweep time: Auto
- Log scale: 10dB/Div, Data points: 400 points or more
- Reference level: Enough level for maximum dynamic range
- Detection: Positive Peak
- Sweep mode: Single Sweep
- Marker: Spot

If the EUT can't set at un-modulation mode, measure the 10dBc center frequency.

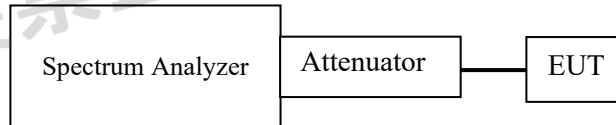
Occupied Bandwidth and Spreading Bandwidth

Limit

- Occupied bandwidth: FH $\leq$ 83.5 MHz; OFDM, DS $\leq$ 26 MHz; Others $\leq$ 26 MHz
- Spread Bandwidth: $\geq$ 500 kHz (FH,DS), Spread factor $>$ 5.

Test Procedure

Measurement System Diagram



Conditions of Application Equipment (EUT)

- The modulation state shall be “continuous frequency-hopping mode” by spread spectrum.

Spectrum Analyzer Conditions

- RBW: 300 kHz
- VBW: 300 kHz
- Sweep time: Auto(Minimum time to ensure measurement accuracy.)
- Log scal: 10dB/Div
- Data points : 400 points or more
- Reference level: Enough level for maximum dynamic range
- Detection: Positive Peak, Sweep mode: Continuous

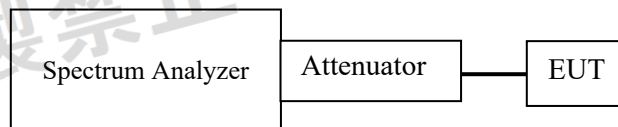
Transmitter Spurious Emission Strength and Unwanted Emission Intensity

Limit

- $f < 2387 \text{ MHz}$, $f > 2496.5 \text{ MHz}$: $\leq 2.5 \mu\text{W/MHz}$
- $2387 \text{ MHz} \leq f \leq 2400 \text{ MHz}$; $2483.5 \text{ MHz} < f \leq 2496.5 \text{ MHz}$: $\leq 25 \mu\text{W/MHz}$

Test Procedure

Measurement System Diagram



Conditions of Application Equipment (EUT)

- The modulation state shall be in continuously transmitting mode.

Spectrum Analyzer Conditions

- Span: Measuring Frequency Range
- RBW: 1MHz (frequency range; 1GHz over), 100kHz (frequency range; 30MHz to 1GHz)
- VBW: Same as RBW (1MHz or 100kHz)
- Sweep time: Auto(Minimum time to ensure measurement accuracy.)
- Data points : 400 points or more
- Reference level: Enough level for maximum dynamic range
- Detection: Positive Peak

If the measured value is under the technical standard value, do not need to measure more detail.

Note: $2.5 \mu\text{W/MHz} = 0.25 \mu\text{W}/100\text{kHz}$

Antenna Output Power and Antenna Power Tolerance

Limit

- $\leq 3 \text{ mW /MHz}$ (FHSS from 2402-2480 MHz)
- $\leq 10 \text{ mW/MHz}$ (OFDM, DSSS from 2400-2483.5 MHz)
- $\leq 10 \text{ mW}$ (other from 2400-2483.5 MHz)
- EIRP: $\leq 6.91 \text{ dBm/MHz}$

The Output Power Tolerance must be within +20%, -80%.

Test Procedure

For FHSS UUT:

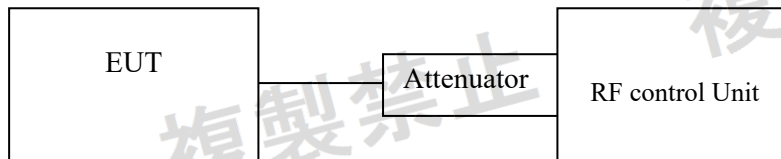
Step 1: Measure the total power by Power Meter in a state of hopping mode

Step 2: Set the power meter to trace average across the pulse on period, record the reading level on power meter.

Step 3: Calculate the mean power per 1MHz by dividing the reading level by spread bandwidth.

Output Power Density (mW/MHz) = Reading (mW) / Spread Bandwidth (MHz)

Test Setup Block diagram



Note: the power meter was integrated in the RF control Unit.

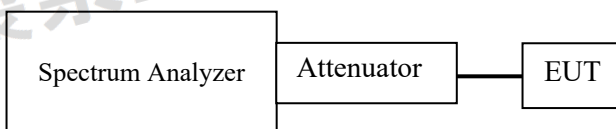
Receiver Spurious Emission and Unwanted Emission Intensity

Limit

- $\leq 4 \text{ nW}$ ($30 \text{ MHz} \leq f \leq 1000 \text{ MHz}$)
- $\leq 20 \text{ nW}$ ($1 \text{ GHz} \leq f \leq 12.5 \text{ GHz}$)

Test Procedure

Measurement System Diagram



Conditions of Application Equipment (EUT)

- The modulation state shall be “continuous receiving mode”.

Spectrum Analyzer Conditions

- Start Frequency: Start Frequency of frequency range to measure (30MHz or 1GHz)
- Stop Frequency: Stop Frequency of frequency range to measure (1GHz or 12.5GHz)
- Span: AUTO (Measurement Range)
- RBW: 100 kHz, VBW: 100 kHz for Frequency < 1 GHz
- RBW: 1MHz, VBW: 1MHz for Frequency > 1 GHz
- Sweep time: AUTO or more
- Sweep mode: Auto Sweep
- Detection: Positive Peak
- Reference Level: Enough level for maximum dynamic range

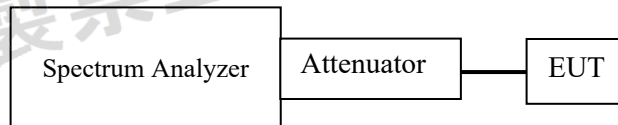
Frequency Hopping Dwell Time

Applicable Standard

According to Radio Law Radio Equipment Regulations Article 49-20, frequency dwell time is 0.4 seconds or below.

Test Procedure

Measurement System Diagram



Conditions of Application Equipment (EUT)

- Set the application equipment (EUT) to the measurement frequency.
- The modulation state shall be “continuous (burst) transmission mode”. If impossible, it shall be “continuous frequency-hopping mode”.

Spectrum Analyzer Conditions

- Step 1:
 - Center Frequency: 2441.0 MHz
 - Span: ZERO SPAN
 - RBW: 10MHz, VBW: 10MHz
 - Log scale: 10dB/Div, Data points: 601points (400 points or more)
 - Reference level: Enough level for maximum dynamic range
 - Detection: Positive Peak,
 - Sweep mode: Single
 - Duty cycle= Ton/(Ton+Toff)
- Step 2:
 - Center Frequency: 2441.0 MHz
 - RBW: 1MHz, VBW: 1MHz
 - Span: ZERO SPAN
 - Reference level: Enough level for maximum dynamic range
 - Detection: Positive Peak,
 - Sweep mode: Single
 - Sweep time: $0.4 \times \text{SBW}[\text{second}]$

Dwell time = Time per one hopping (On time) * hopping numbers

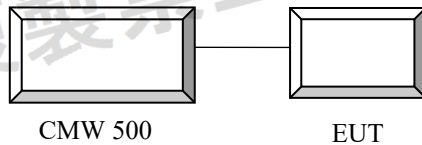
Interference Prevention Function

Requirement

The EUT shall have the interference prevention capability to transmit or to receive the identification automatically, so that sender and receiver shall exclude other equipment.

Test Procedure

Measurement System Diagram



In the case that the EUT has the function of automatically transmitting the identification code:

1. Transmit the predetermined identification codes from EUT
2. Check the transmitted identification codes with CMW500.

In the case of receiving the identification codes:

1. Transmit the predetermined identification codes from the counterpart.
2. Check if communication is normal
3. Transmit the signal other than predetermined ID codes from the counterpart.
4. Check if the EUT stops the transmission, or if it displays that identification codes are different from the predetermined ones.

TEST DATA AND RESULTS**Test Information:**

Sample No.:	3AO6-3	Test Date:	2025/10/10-2025/11/27
Test Site:	RF	Test Mode:	Transmitting
Tester:	Lee Li&Cheeb Huang	Test Result:	Pass

Environmental Conditions:

Temperature: (°C)	24.6-26.1	Relative Humidity: (%)	46-55	ATM Pressure: (kPa)	100.2-101.1
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Frequency Error**Test Condition: HV**

Mode	Frequency (MHz)	Measure Frequency (MHz)	Frequency Tolerance (ppm)	Limit (ppm)	Verdict
Single Carrier	2402	2401.96760	-13.49	± 50	Pass
	2441	2440.96760	-13.27		Pass
	2480	2479.96760	-13.06		Pass

Test Condition: LV

Mode	Frequency (MHz)	Measure Frequency (MHz)	Frequency Tolerance (ppm)	Limit (ppm)	Verdict
Single Carrier	2402	2401.96850	-13.11	± 50	Pass
	2441	2440.96730	-13.40		Pass
	2480	2479.96730	-13.19		Pass

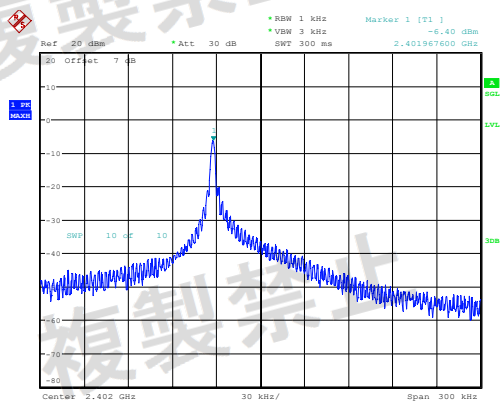
Test Condition: NV

Mode	Frequency (MHz)	Measure Frequency (MHz)	Frequency Tolerance (ppm)	Limit (ppm)	Verdict
Single Carrier	2402	2401.96700	-13.74	± 50	Pass
	2441	2440.96700	-13.52		Pass
	2480	2479.96760	-13.06		Pass

Frequency Tolerance = (Measure Frequency - Frequency)/Frequency*10⁶

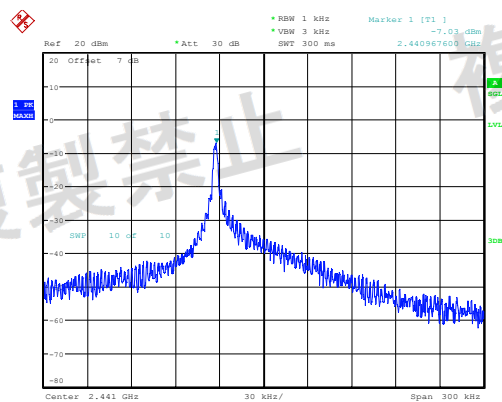
Test Condition: HV

2402MHz



ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 06:02:15

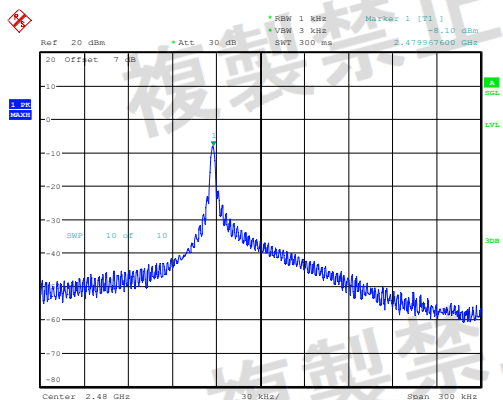
2441MHz



ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 06:02:46

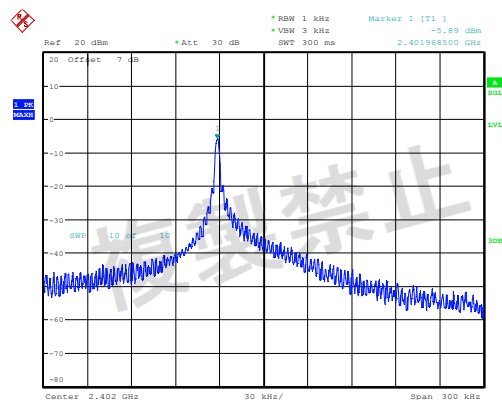
Test Condition: LV

2480MHz



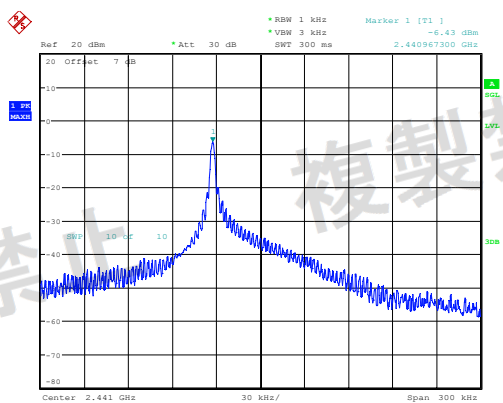
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 06:03:14

2402MHz



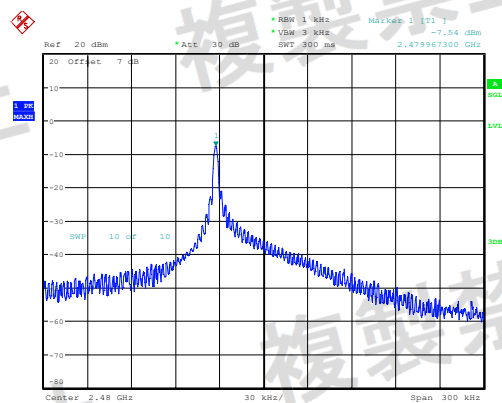
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 04:35:30

2441MHz



ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 04:36:05

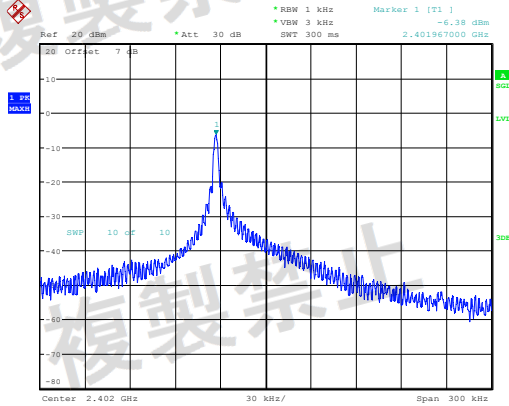
2480MHz



ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 04:36:42

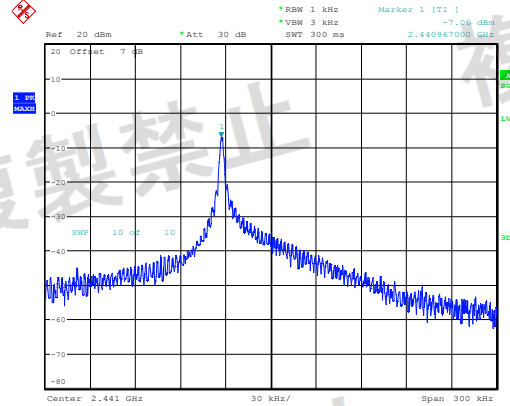
Test Condition: NV

2402MHz



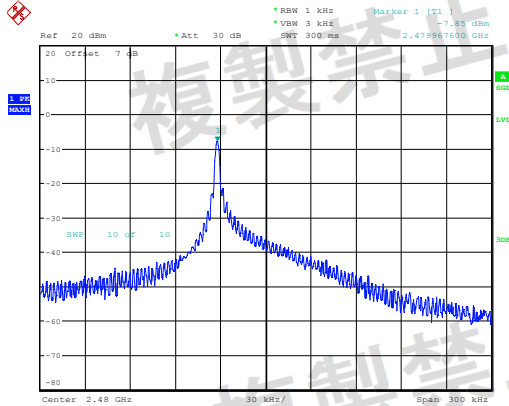
ProjectNo.:2501X79543E-RF Tester:Lee Li
 Date: 10.OCT.2025 03:18:25

2441MHz



ProjectNo.:2501X79543E-RF Tester:Lee Li
 Date: 10.OCT.2025 03:19:14

2480MHz



ProjectNo.:2501X79543E-RF Tester:Lee Li
 Date: 10.OCT.2025 03:19:36

Occupied Bandwidth and Spreading Bandwidth**Test Condition: HV**

Mode	Packet Type	Occupied bandwidth (MHz)		Spreading bandwidth (MHz)		Spreading factor		Result
		Measured	Limit	Measured	Limit	Measured	Limit	
GFSK	DH1	78.2	≤ 83.5	70.6	≥ 0.5	70.6	> 5	Pass
	DH3	78.2	≤ 83.5	70.8	≥ 0.5	70.8	> 5	Pass
	DH5	78.2	≤ 83.5	70.8	≥ 0.5	70.8	> 5	Pass
$\pi/4$ -DQPSK	2DH1	78.2	≤ 83.5	71.0	≥ 0.5	71.0	> 5	Pass
	2DH3	78.2	≤ 83.5	71.0	≥ 0.5	71.0	> 5	Pass
	2DH5	78.4	≤ 83.5	70.8	≥ 0.5	70.8	> 5	Pass
8DPSK	3DH1	78.2	≤ 83.5	71.0	≥ 0.5	71.0	> 5	Pass
	3DH3	78.2	≤ 83.5	70.8	≥ 0.5	70.8	> 5	Pass
	3DH5	78.4	≤ 83.5	70.8	≥ 0.5	70.8	> 5	Pass

Test Condition: LV

Mode	Packet Type	Occupied bandwidth (MHz)		Spreading bandwidth (MHz)		Spreading factor		Result
		Measured	Limit	Measured	Limit	Measured	Limit	
GFSK	DH1	78.2	≤ 83.5	70.4	≥ 0.5	70.4	> 5	Pass
	DH3	78.2	≤ 83.5	70.8	≥ 0.5	70.8	> 5	Pass
	DH5	78.2	≤ 83.5	70.8	≥ 0.5	70.8	> 5	Pass
$\pi/4$ -DQPSK	2DH1	78.2	≤ 83.5	71.0	≥ 0.5	71.0	> 5	Pass
	2DH3	78.4	≤ 83.5	71.2	≥ 0.5	71.2	> 5	Pass
	2DH5	78.6	≤ 83.5	71.0	≥ 0.5	71.0	> 5	Pass
8DPSK	3DH1	78.4	≤ 83.5	71.2	≥ 0.5	71.2	> 5	Pass
	3DH3	78.4	≤ 83.5	70.6	≥ 0.5	70.6	> 5	Pass
	3DH5	78.4	≤ 83.5	71.4	≥ 0.5	71.4	> 5	Pass

Test Condition: NV

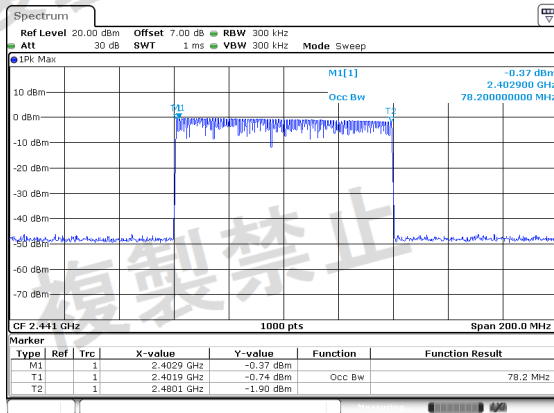
Mode	Packet Type	Occupied bandwidth (MHz)		Spreading bandwidth (MHz)		Spreading factor		Result
		Measured	Limit	Measured	Limit	Measured	Limit	
GFSK	DH1	78.2	≤ 83.5	70.4	≥ 0.5	70.4	> 5	Pass
	DH3	78.2	≤ 83.5	70.6	≥ 0.5	70.6	> 5	Pass
	DH5	78.2	≤ 83.5	70.6	≥ 0.5	70.6	> 5	Pass
$\pi/4$ -DQPSK	2DH1	78.2	≤ 83.5	70.8	≥ 0.5	70.8	> 5	Pass
	2DH3	78.2	≤ 83.5	71.0	≥ 0.5	71.0	> 5	Pass
	2DH5	78.4	≤ 83.5	70.8	≥ 0.5	70.8	> 5	Pass
8DPSK	3DH1	78.2	≤ 83.5	71.0	≥ 0.5	71.0	> 5	Pass
	3DH3	78.2	≤ 83.5	70.8	≥ 0.5	70.8	> 5	Pass
	3DH5	78.4	≤ 83.5	71.0	≥ 0.5	71.0	> 5	Pass

Note: Spread Factor = Spread Bandwidth/modulation rate. The modulation rate: MR=1

Test Condition: HV

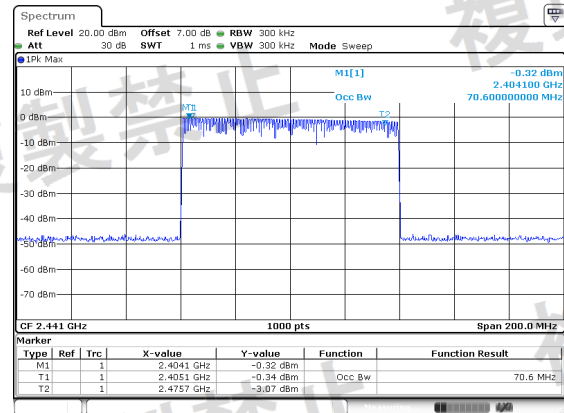
GFSK_Hopping_DH1

Occupied Bandwidth



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 17:57:11

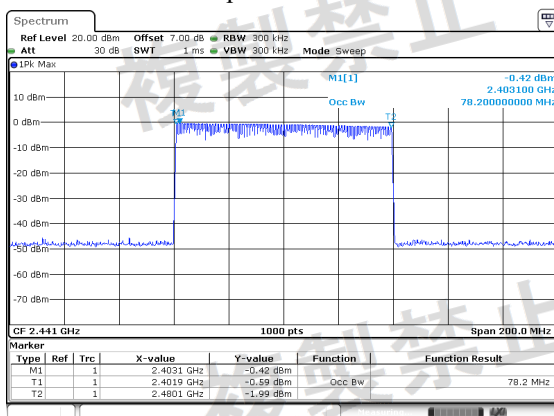
Spreading Bandwidth



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 17:58:07

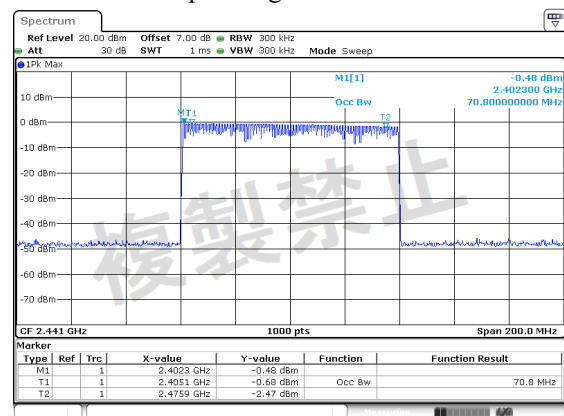
GFSK_Hopping_DH3

Occupied Bandwidth



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 17:59:33

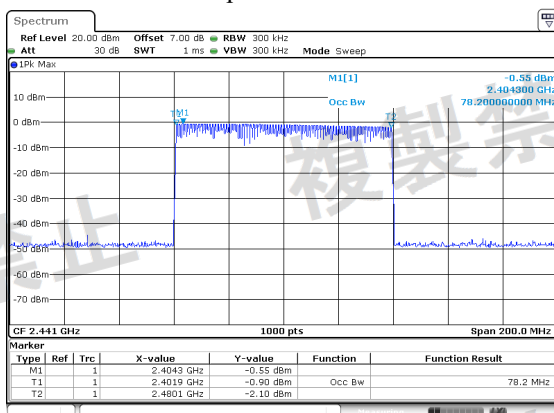
Spreading Bandwidth



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 18:00:23

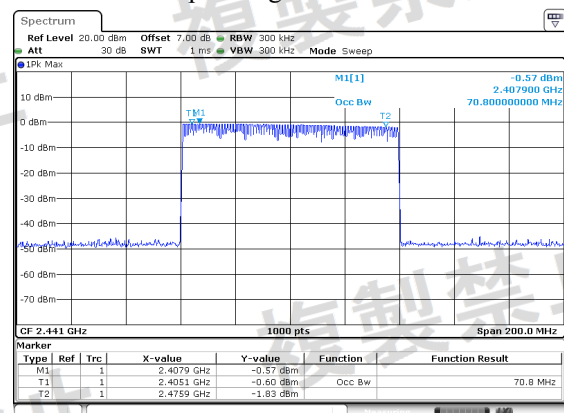
GFSK_Hopping_DH5

Occupied Bandwidth



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 18:01:11

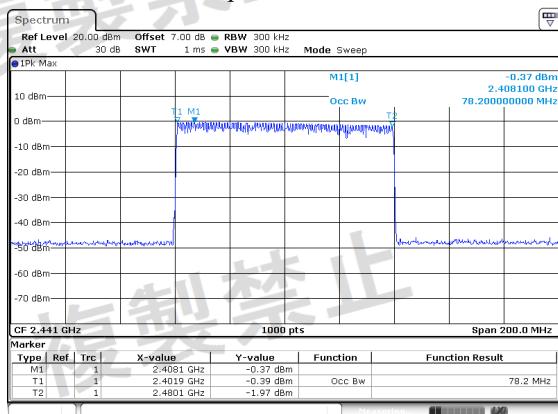
Spreading Bandwidth



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 18:01:55

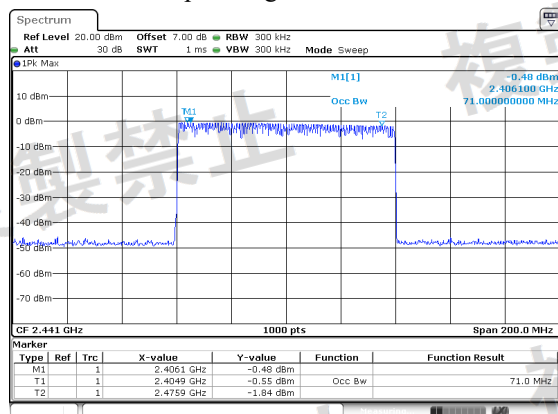
$\pi/4$ -DQPSK_Hopping_2DH1

Occupied Bandwidth



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 18:03:12

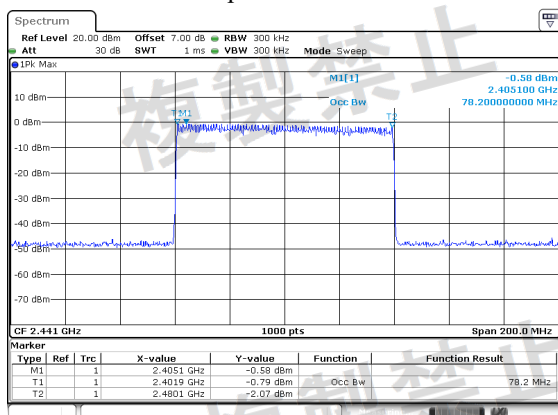
Spreading Bandwidth



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 18:05:26

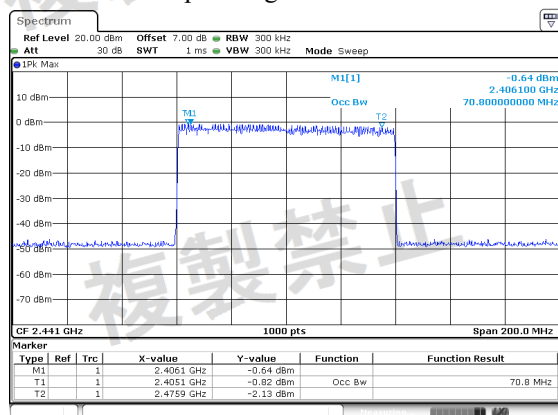
 $\pi/4$ -DQPSK_Hopping_2DH3

Occupied Bandwidth



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 18:06:28

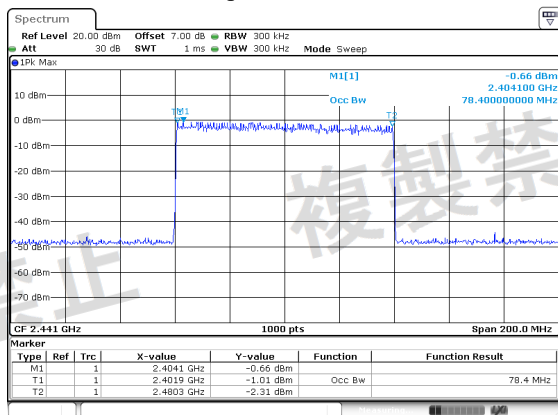
Spreading Bandwidth



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 18:07:11

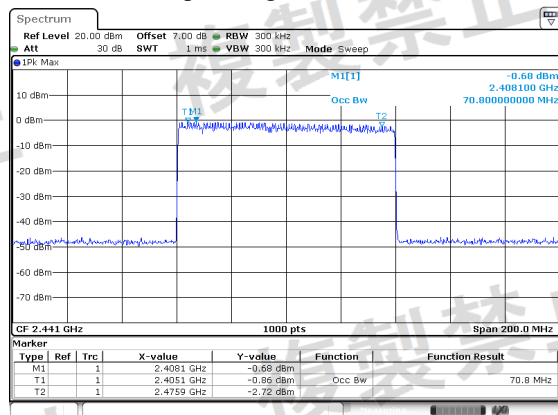
 $\pi/4$ -DQPSK_Hopping_2DH5

Occupied Bandwidth



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 18:08:09

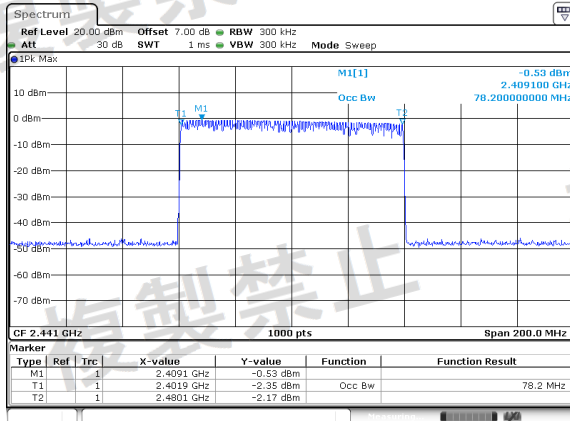
Spreading Bandwidth



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 18:08:56

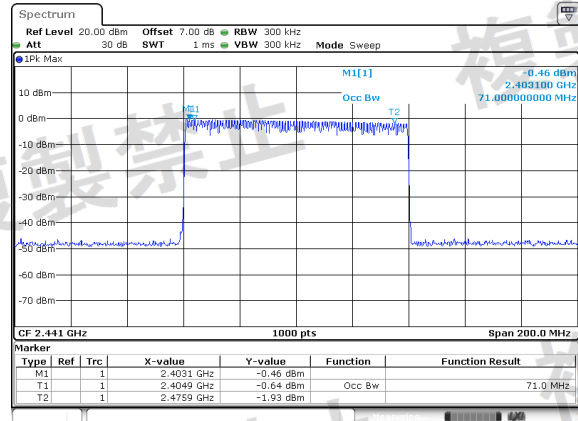
8DPSK_Hopping_3DH1

Occupied Bandwidth



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 18:10:08

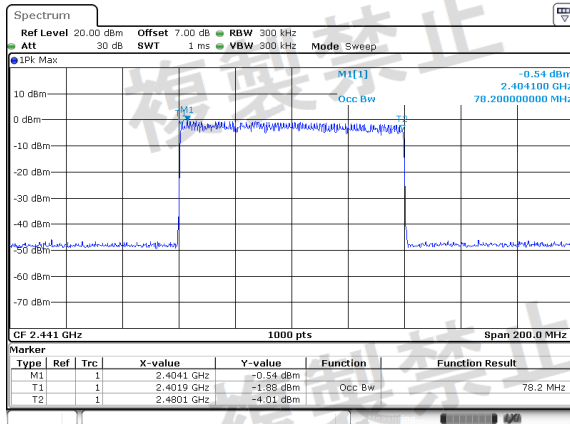
Spreading Bandwidth



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 18:11:06

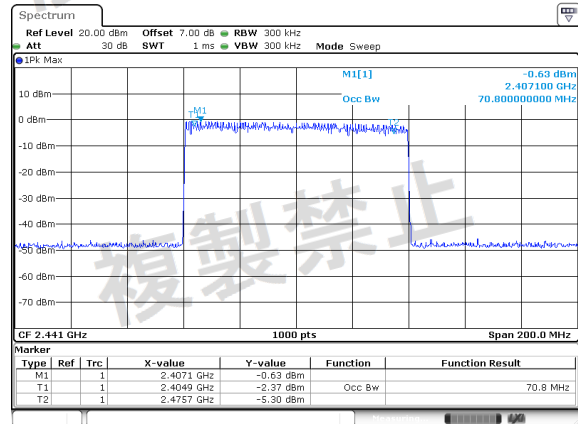
8DPSK_Hopping_3DH3

Occupied Bandwidth



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 18:12:16

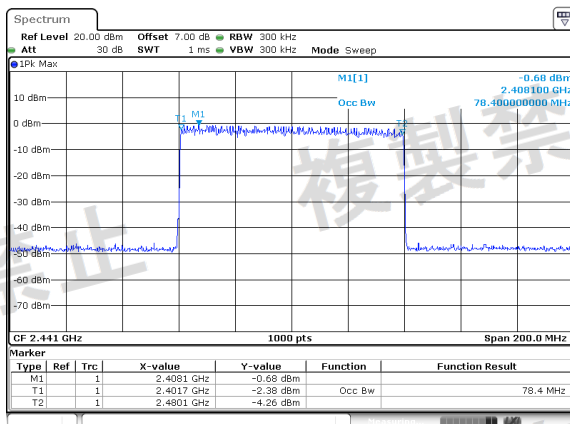
Spreading Bandwidth



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 18:13:03

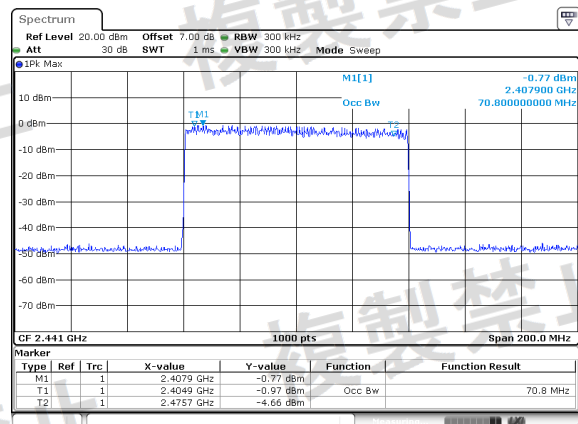
8DPSK_Hopping_3DH5

Occupied Bandwidth



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 18:14:20

Spreading Bandwidth

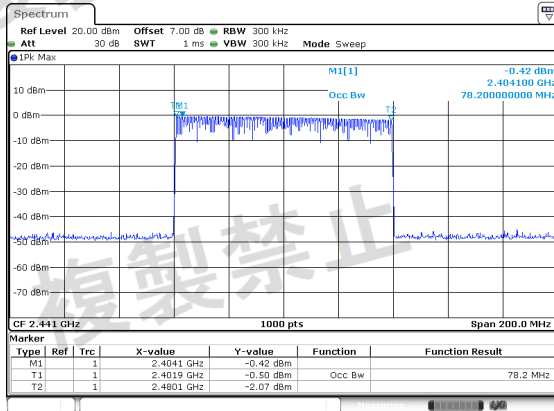


ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 18:14:58

Test Condition: LV

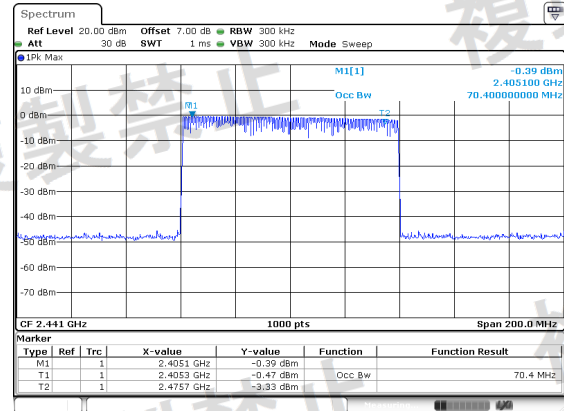
GFSK_Hopping_DH1

Occupied Bandwidth



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 17:16:41

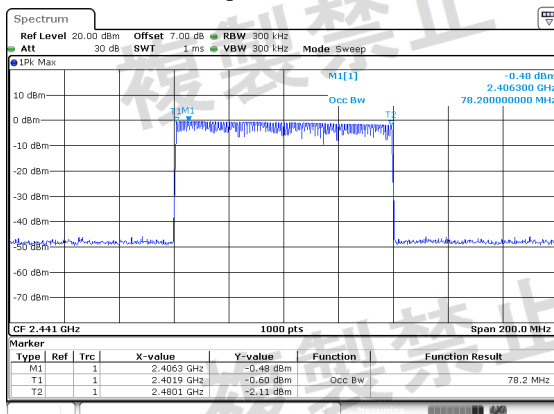
Spreading Bandwidth



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 17:17:41

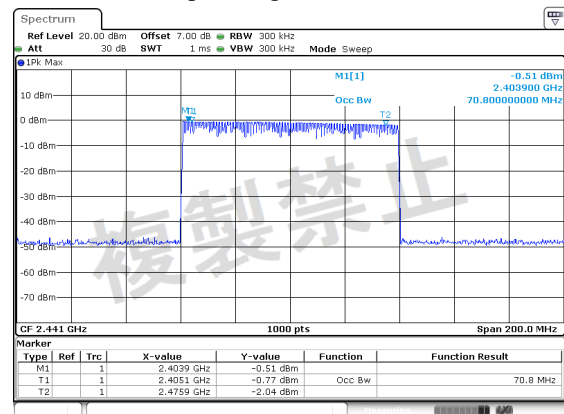
GFSK_Hopping_DH3

Occupied Bandwidth



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 17:18:17

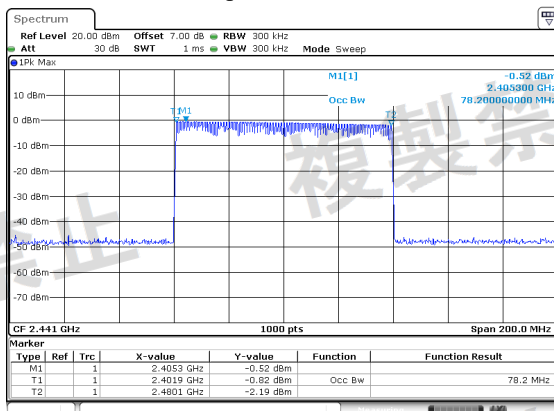
Spreading Bandwidth



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 17:19:17

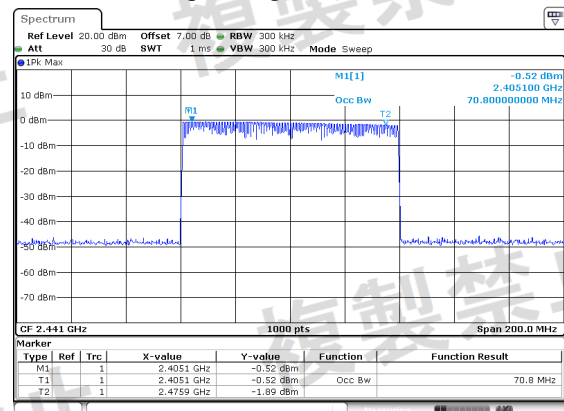
GFSK_Hopping_DH5

Occupied Bandwidth



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 17:20:20

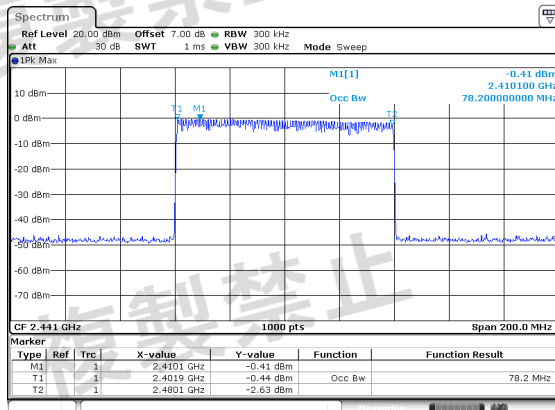
Spreading Bandwidth



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 17:21:03

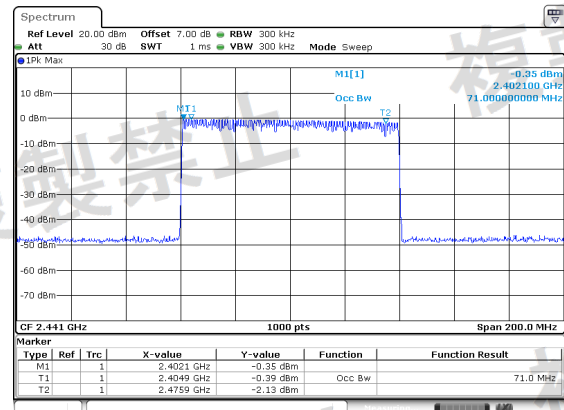
$\pi/4$ -DQPSK_Hopping_2DH1

Occupied Bandwidth



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 17:22:13

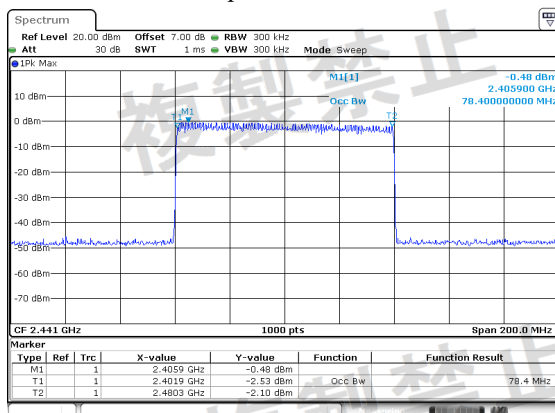
Spreading Bandwidth



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 17:23:11

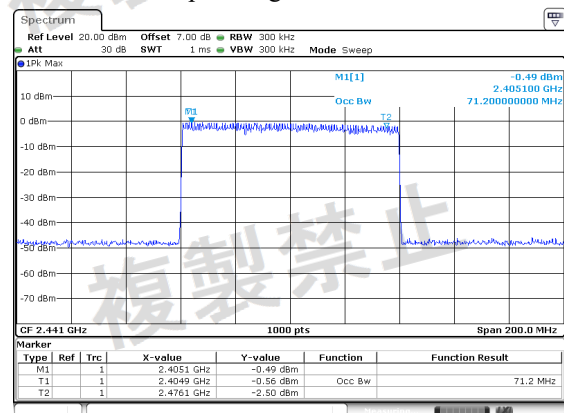
 $\pi/4$ -DQPSK_Hopping_2DH3

Occupied Bandwidth



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 17:24:16

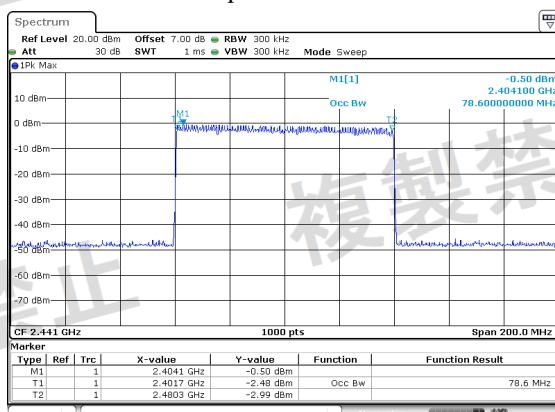
Spreading Bandwidth



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 17:25:09

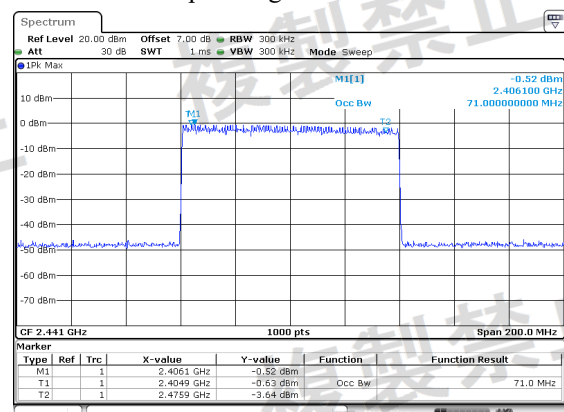
 $\pi/4$ -DQPSK_Hopping_2DH5

Occupied Bandwidth



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 17:26:20

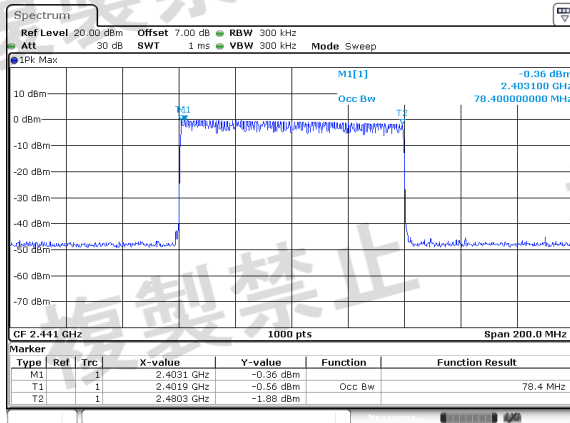
Spreading Bandwidth



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 17:27:14

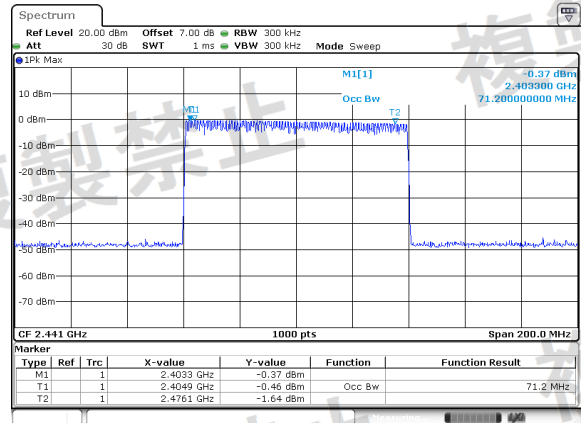
8DPSK_Hopping_3DH1

Occupied Bandwidth



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 17:28:30

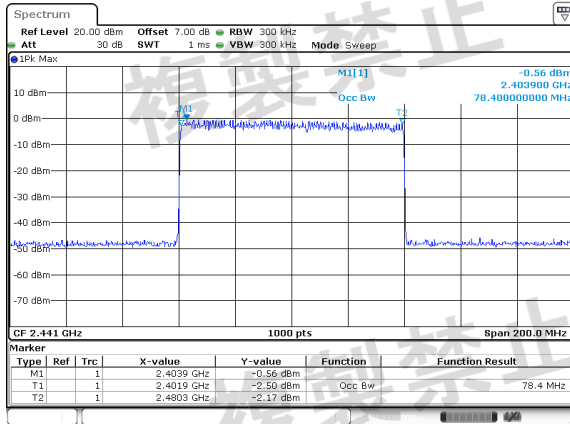
Spreading Bandwidth



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 17:29:27

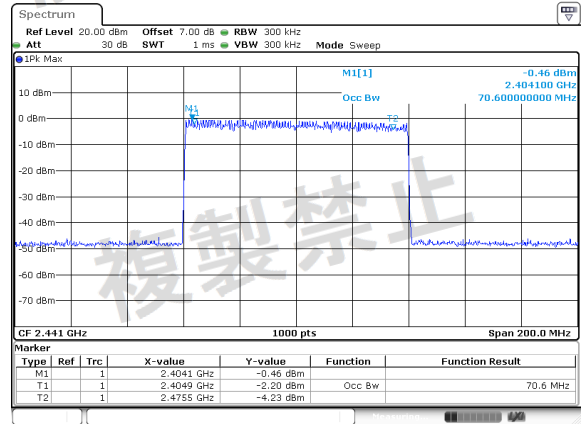
8DPSK_Hopping_3DH3

Occupied Bandwidth



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 17:30:21

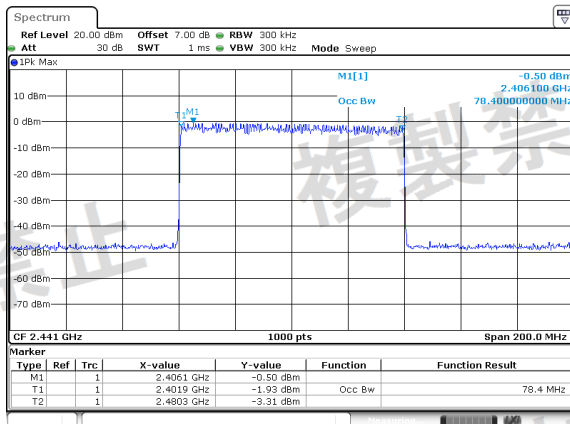
Spreading Bandwidth



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 17:31:10

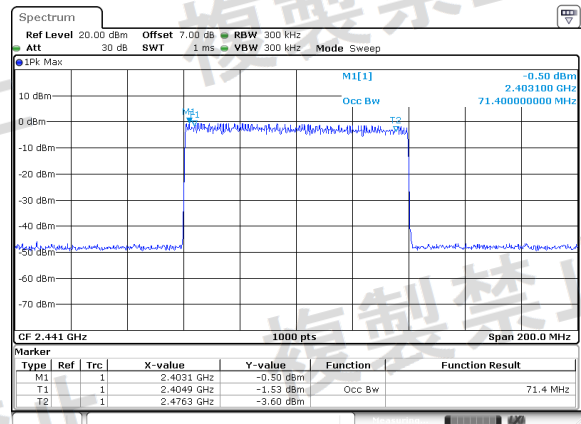
8DPSK_Hopping_3DH5

Occupied Bandwidth



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 17:32:13

Spreading Bandwidth

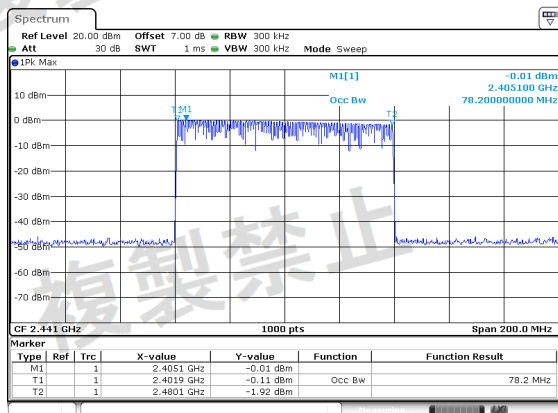


ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 17:32:53

Test Condition: NV

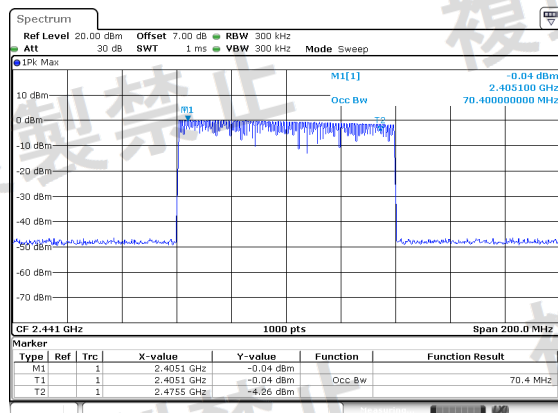
GFSK_Hopping_DH1

Occupied Bandwidth



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 5.NOV.2025 16:33:07

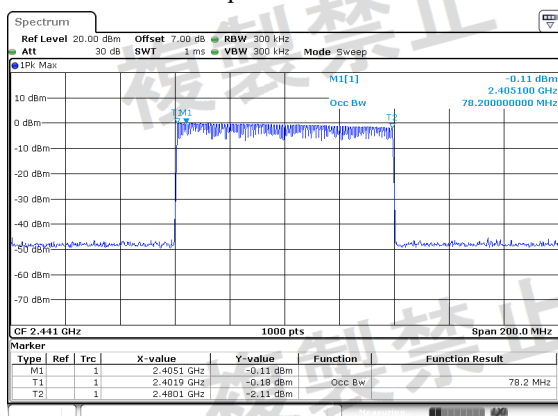
Spreading Bandwidth



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 5.NOV.2025 16:34:00

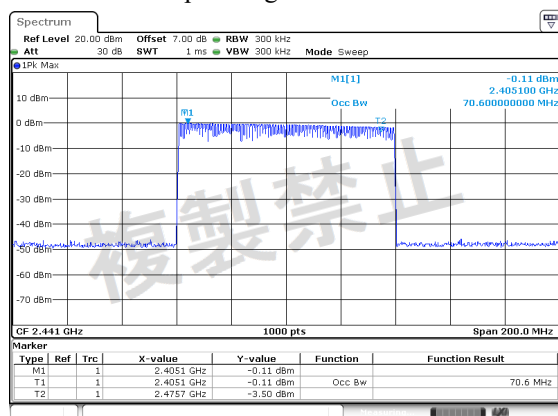
GFSK_Hopping_DH3

Occupied Bandwidth



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 5.NOV.2025 16:35:04

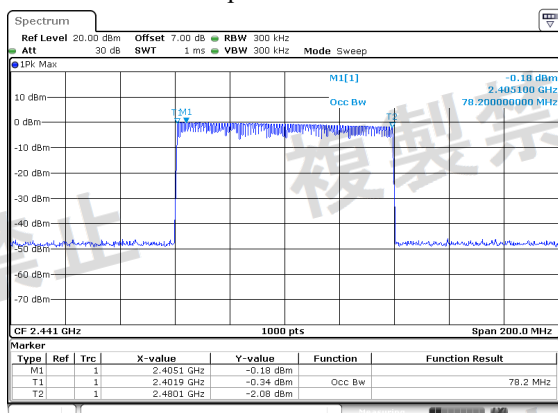
Spreading Bandwidth



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 5.NOV.2025 16:35:19

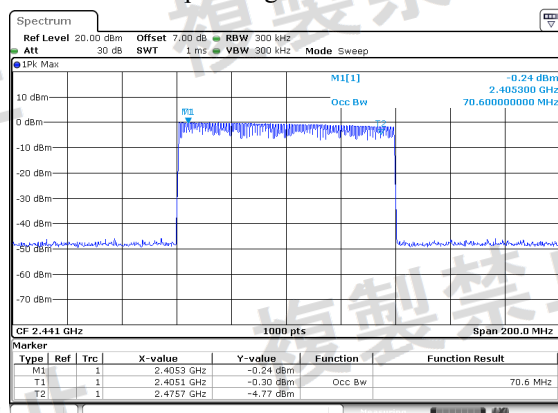
GFSK_Hopping_DH5

Occupied Bandwidth



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 5.NOV.2025 16:36:57

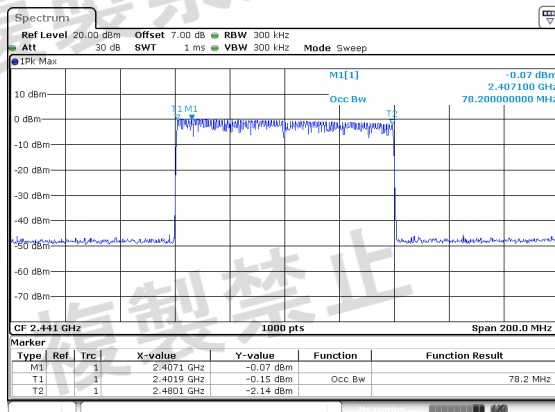
Spreading Bandwidth



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 5.NOV.2025 16:37:13

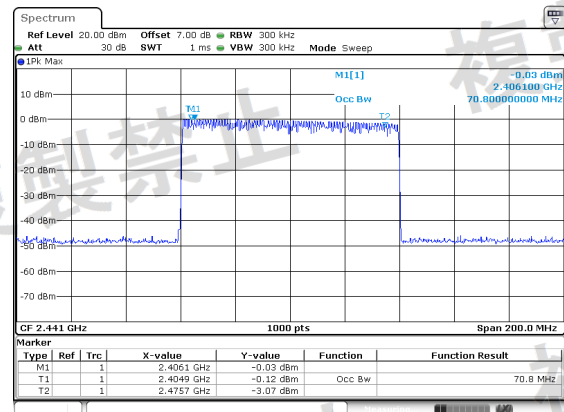
$\pi/4$ -DQPSK_Hopping_2DH1

Occupied Bandwidth



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 5.NOV.2025 16:38:55

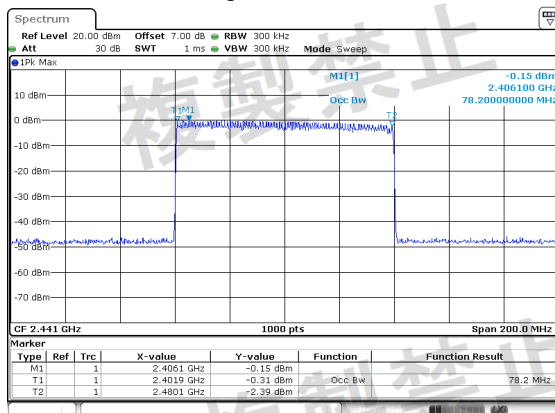
Spreading Bandwidth



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 5.NOV.2025 16:39:49

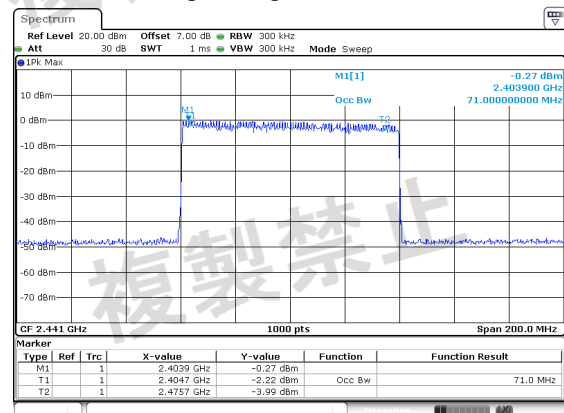
 $\pi/4$ -DQPSK_Hopping_2DH3

Occupied Bandwidth



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 5.NOV.2025 16:41:06

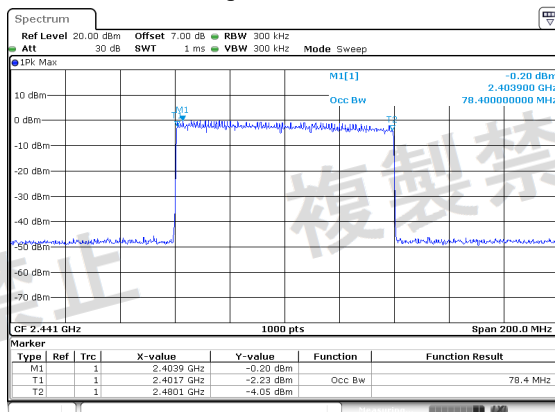
Spreading Bandwidth



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 5.NOV.2025 16:41:49

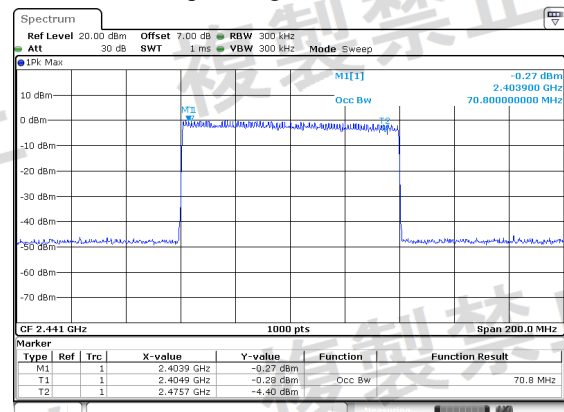
 $\pi/4$ -DQPSK_Hopping_2DH5

Occupied Bandwidth



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 5.NOV.2025 16:42:53

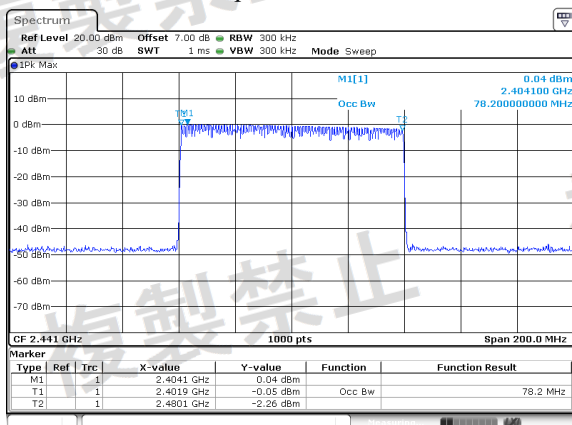
Spreading Bandwidth



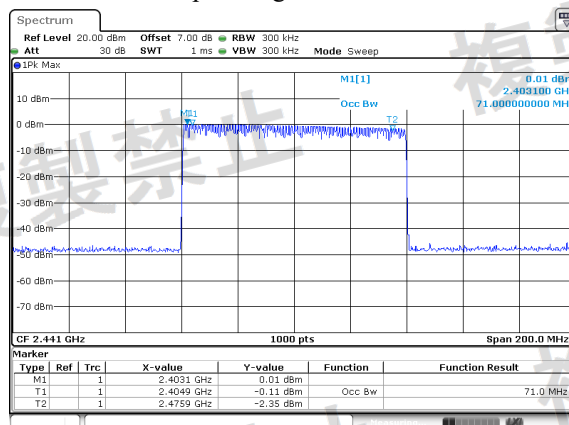
ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 5.NOV.2025 16:43:55

8DPSK_Hopping_3DH1

Occupied Bandwidth

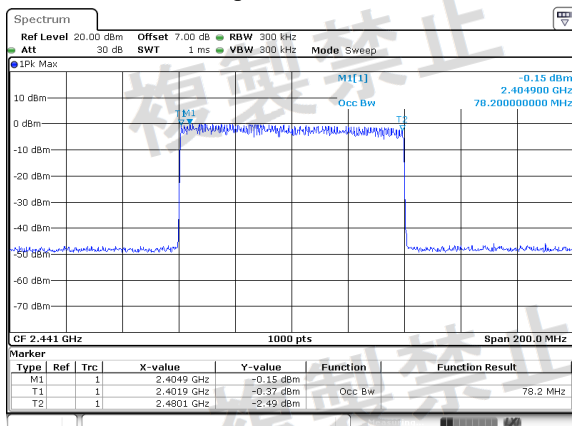


Spreading Bandwidth

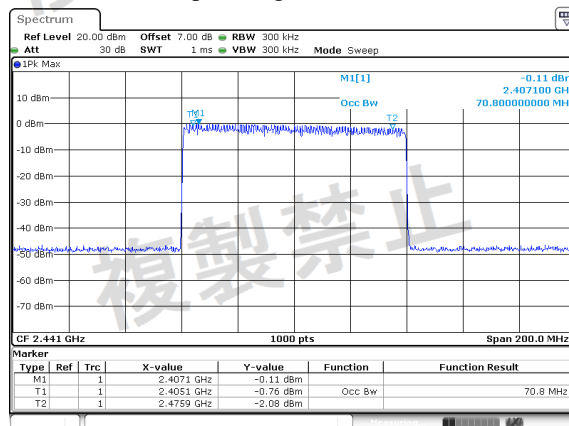


8DPSK_Hopping_3DH3

Occupied Bandwidth

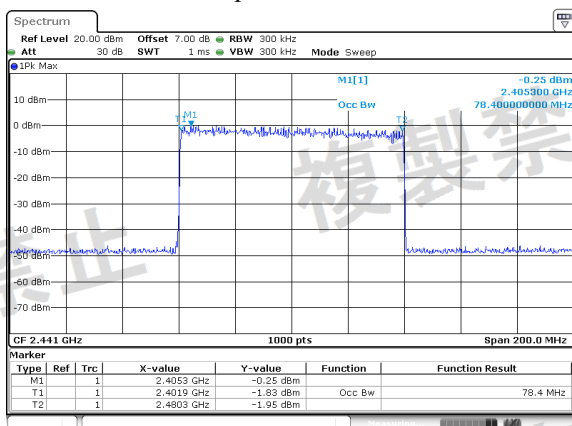


Spreading Bandwidth

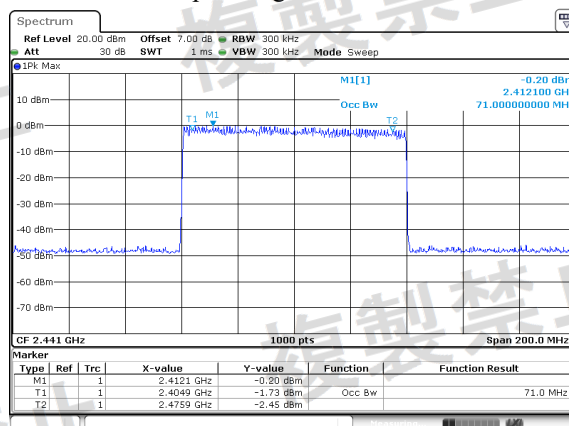


8DPSK_Hopping_3DH5

Occupied Bandwidth



Spreading Bandwidth



Antenna Output Power and Output Power Tolerance**Test Condition: LV/NV/HV**

Mode	Antenna gain (dBi)	Declared power (mW/MHz)
GFSK	2.78	0.01
$\pi/4$ DQPSK		0.01
8DPSK		0.01

Test Condition	Mode	Antenna output power (dBm)	Spread bandwidth (MHz)	Antenna output power (mW/MHz)		Antenna output power tolerance(%)		EIRP (dBm/MHz)		Verdict
				Result	Limit	Result	Limit	Result	Limit	
HV	GFSK	-2.047	70.6	0.0088	≤ 3	-11.59	-80~+20	-17.76	≤ 6.91	Pass
	$\pi/4$ -DQPSK	-3.146	71.0	0.0068	≤ 3	-31.74	-80~+20	-18.88	≤ 6.91	Pass
	8DPSK	-3.329	71.0	0.0065	≤ 3	-34.56	-80~+20	-19.06	≤ 6.91	Pass
LV	GFSK	-2.031	70.4	0.0089	≤ 3	-11.01	-80~+20	-17.73	≤ 6.91	Pass
	$\pi/4$ -DQPSK	-3.156	71.0	0.0068	≤ 3	-31.90	-80~+20	-18.89	≤ 6.91	Pass
	8DPSK	-3.332	71.2	0.0065	≤ 3	-34.79	-80~+20	-19.08	≤ 6.91	Pass
NV	GFSK	-1.986	70.4	0.0090	≤ 3	-10.09	-80~+20	-17.68	≤ 6.91	Pass
	$\pi/4$ -DQPSK	-3.043	70.8	0.0070	≤ 3	-29.91	-80~+20	-18.76	≤ 6.91	Pass
	8DPSK	-3.228	71.0	0.0067	≤ 3	-33.02	-80~+20	-18.96	≤ 6.91	Pass

Note:

Antenna output power(mW) = $10^{\{\text{Antenna output power(dBm)} / 10\}}$

Antenna output power(mW/MHz) = Antenna output power(mW) / Spread bandwidth(MHz)

Antenna output power Tolerance(%) = (Antenna output power - Declared power) / Declared power * 100%

Antenna output power(dBm/MHz) = $10 * \log_{10}\{\text{Antenna output power(mW/MHz)}\}$

EIRP(dBm/MHz) = Antenna output power(dBm/MHz) + Antenna gain.

Transmitter Spurious Emission and Unwanted Emission Intensity**Test Condition: HV, GFSK**

Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm/RBW)	Result (μW/RBW)	Limit (μW/RBW)	Verdict
		Start(MHz)	Stop(MHz)					
Low	Band I (100kHz)	30	1000	631.885	-46.45	0.023	0.25	Pass
	Band II (1MHz)	1000	2387	2384.226	-42.17	0.061	2.50	Pass
	Band III (1MHz)	2387	2400	2400	-23.86	4.111	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2486.594	-40.98	0.080	25	Pass
	Band V (1MHz)	2496.5	12500	9608.9885	-38.02	0.158	2.50	Pass
Middle	Band I (100kHz)	30	1000	97.415	-46.17	0.024	0.25	Pass
	Band II (1MHz)	1000	2387	2310.715	-41.96	0.064	2.50	Pass
	Band III (1MHz)	2387	2400	2394.41	-40.62	0.087	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2489.441	-40.97	0.080	25	Pass
	Band V (1MHz)	2496.5	12500	9764.04275	-37.60	0.174	2.50	Pass
High	Band I (100kHz)	30	1000	175.5	-46.89	0.020	0.25	Pass
	Band II (1MHz)	1000	2387	2287.8295	-40.26	0.094	2.50	Pass
	Band III (1MHz)	2387	2400	2397.4845	-41.17	0.076	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2493.6335	-40.27	0.094	25	Pass
	Band V (1MHz)	2496.5	12500	9919.097	-36.96	0.201	2.50	Pass

Test Condition: HV, $\pi/4$ -DQPSK

Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm/RBW)	Result (μ W/RBW)	Limit (μ W/RBW)	Verdict
		Start(MHz)	Stop(MHz)					
Low	Band I (100kHz)	30	1000	238.55	-46.47	0.023	0.25	Pass
	Band II (1MHz)	1000	2387	2177.563	-41.51	0.071	2.50	Pass
	Band III (1MHz)	2387	2400	2400	-21.96	6.368	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2494.1405	-40.95	0.080	25	Pass
	Band V (1MHz)	2496.5	12500	9608.9885	-38.18	0.152	2.50	Pass
Middle	Band I (100kHz)	30	1000	364.165	-46.96	0.020	0.25	Pass
	Band II (1MHz)	1000	2387	2358.5665	-41.91	0.064	2.50	Pass
	Band III (1MHz)	2387	2400	2388.716	-40.74	0.084	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2486.113	-41.13	0.077	25	Pass
	Band V (1MHz)	2496.5	12500	9764.04275	-36.78	0.210	2.50	Pass
High	Band I (100kHz)	30	1000	76.56	-47.08	0.020	0.25	Pass
	Band II (1MHz)	1000	2387	2357.873	-41.71	0.067	2.50	Pass
	Band III (1MHz)	2387	2400	2388.5275	-41.09	0.078	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2487.7445	-40.65	0.086	25	Pass
	Band V (1MHz)	2496.5	12500	9924.09875	-36.82	0.208	2.50	Pass

Test Condition: HV, 8DPSK

Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm/RBW)	Result (μW/RBW)	Limit (μW/RBW)	Verdict
		Start(MHz)	Stop(MHz)					
Low	Band I (100kHz)	30	1000	585.325	-46.65	0.022	0.25	Pass
	Band II (1MHz)	1000	2387	2196.981	-40.49	0.089	2.50	Pass
	Band III (1MHz)	2387	2400	2399.9805	-21.72	6.730	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2494.1145	-41.22	0.076	25	Pass
	Band V (1MHz)	2496.5	12500	9608.9885	-38.15	0.153	2.50	Pass
Middle	Band I (100kHz)	30	1000	557.68	-46.17	0.024	0.25	Pass
	Band II (1MHz)	1000	2387	2248.9935	-41.36	0.073	2.50	Pass
	Band III (1MHz)	2387	2400	2395.502	-40.98	0.080	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2493.2955	-39.65	0.108	25	Pass
	Band V (1MHz)	2496.5	12500	9764.04275	-36.95	0.202	2.50	Pass
High	Band I (100kHz)	30	1000	145.43	-46.77	0.021	0.25	Pass
	Band II (1MHz)	1000	2387	2288.523	-40.69	0.085	2.50	Pass
	Band III (1MHz)	2387	2400	2392.7655	-41.31	0.074	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2495.8565	-40.95	0.080	25	Pass
	Band V (1MHz)	2496.5	12500	9919.097	-36.99	0.200	2.50	Pass

Test Condition: LV, GFSK

Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm/RBW)	Result (μW/RBW)	Limit (μW/RBW)	Verdict
		Start(MHz)	Stop(MHz)					
Low	Band I (100kHz)	30	1000	461.65	-46.37	0.023	0.25	Pass
	Band II (1MHz)	1000	2387	2213.625	-41.64	0.069	2.50	Pass
	Band III (1MHz)	2387	2400	2400	-23.71	4.256	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2483.916	-40.64	0.086	25	Pass
	Band V (1MHz)	2496.5	12500	9608.9885	-38.12	0.154	2.50	Pass
Middle	Band I (100kHz)	30	1000	636.735	-46.39	0.023	0.25	Pass
	Band II (1MHz)	1000	2387	2304.4735	-40.98	0.080	2.50	Pass
	Band III (1MHz)	2387	2400	2397.049	-40.90	0.081	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2492.2555	-40.47	0.090	25	Pass
	Band V (1MHz)	2496.5	12500	9764.04275	-38.14	0.153	2.50	Pass
High	Band I (100kHz)	30	1000	839.95	-45.37	0.029	0.25	Pass
	Band II (1MHz)	1000	2387	2288.523	-40.55	0.088	2.50	Pass
	Band III (1MHz)	2387	2400	2397.2115	-41.09	0.078	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2484.306	-41.04	0.079	25	Pass
	Band V (1MHz)	2496.5	12500	9924.09875	-37.41	0.182	2.50	Pass

Test Condition: LV, $\pi/4$ -DQPSK

Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm/RBW)	Result (μ W/RBW)	Limit (μ W/RBW)	Verdict
		Start(MHz)	Stop(MHz)					
Low	Band I (100kHz)	30	1000	114.39	-46.67	0.022	0.25	Pass
	Band II (1MHz)	1000	2387	2365.5015	-42.12	0.061	2.50	Pass
	Band III (1MHz)	2387	2400	2400	-21.54	7.015	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2489.0705	-41.16	0.077	25	Pass
	Band V (1MHz)	2496.5	12500	9608.9885	-38.80	0.132	2.50	Pass
Middle	Band I (100kHz)	30	1000	434.49	-46.61	0.022	0.25	Pass
	Band II (1MHz)	1000	2387	2241.365	-41.26	0.075	2.50	Pass
	Band III (1MHz)	2387	2400	2388.677	-40.84	0.082	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2494.4135	-40.68	0.086	25	Pass
	Band V (1MHz)	2496.5	12500	9764.04275	-38.10	0.155	2.50	Pass
High	Band I (100kHz)	30	1000	419.455	-46.07	0.025	0.25	Pass
	Band II (1MHz)	1000	2387	2288.523	-40.71	0.085	2.50	Pass
	Band III (1MHz)	2387	2400	2396.4705	-40.91	0.081	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2484.1045	-41.32	0.074	25	Pass
	Band V (1MHz)	2496.5	12500	9919.097	-37.23	0.189	2.50	Pass

Test Condition: LV, 8DPSK

Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm/RBW)	Result (μW/RBW)	Limit (μW/RBW)	Verdict
		Start(MHz)	Stop(MHz)					
Low	Band I (100kHz)	30	1000	573.2	-46.66	0.022	0.25	Pass
	Band II (1MHz)	1000	2387	2306.554	-41.69	0.068	2.50	Pass
	Band III (1MHz)	2387	2400	2399.9805	-21.58	6.950	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2492.808	-40.65	0.086	25	Pass
	Band V (1MHz)	2496.5	12500	9608.9885	-39.09	0.123	2.50	Pass
Middle	Band I (100kHz)	30	1000	483.475	-46.66	0.022	0.25	Pass
	Band II (1MHz)	1000	2387	2249.687	-41.80	0.066	2.50	Pass
	Band III (1MHz)	2387	2400	2394.54	-41.18	0.076	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2493.302	-40.99	0.080	25	Pass
	Band V (1MHz)	2496.5	12500	9764.04275	-37.05	0.197	2.50	Pass
High	Band I (100kHz)	30	1000	369.5	-46.86	0.021	0.25	Pass
	Band II (1MHz)	1000	2387	2340.5355	-41.99	0.063	2.50	Pass
	Band III (1MHz)	2387	2400	2395.879	-41.24	0.075	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2489.1355	-40.65	0.086	25	Pass
	Band V (1MHz)	2496.5	12500	9924.09875	-37.38	0.183	2.50	Pass

Test Condition: NV, GFSK

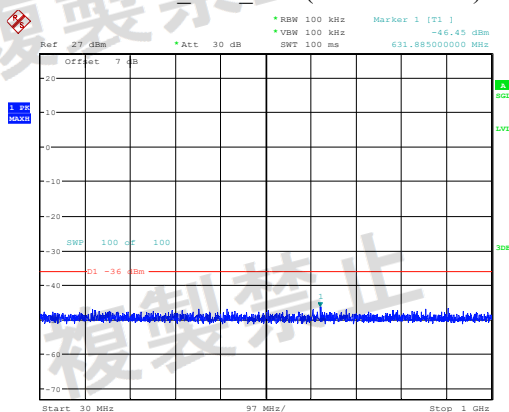
Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm/RBW)	Result (μW/RBW)	Limit (μW/RBW)	Verdict
		Start(MHz)	Stop(MHz)					
Low	Band I (100kHz)	30	1000	288.505	-46.43	0.023	0.25	Pass
	Band II (1MHz)	1000	2387	2226.108	-41.27	0.075	2.50	Pass
	Band III (1MHz)	2387	2400	2400	-24.11	3.882	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2490.6305	-41.29	0.074	25	Pass
	Band V (1MHz)	2496.5	12500	9608.9885	-38.03	0.157	2.50	Pass
Middle	Band I (100kHz)	30	1000	932.1	-46.60	0.022	0.25	Pass
	Band II (1MHz)	1000	2387	2294.071	-41.20	0.076	2.50	Pass
	Band III (1MHz)	2387	2400	2397.738	-41.10	0.078	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2485.359	-40.94	0.081	25	Pass
	Band V (1MHz)	2496.5	12500	9764.04275	-37.60	0.174	2.50	Pass
High	Band I (100kHz)	30	1000	988.845	-46.69	0.021	0.25	Pass
	Band II (1MHz)	1000	2387	2288.523	-42.10	0.062	2.50	Pass
	Band III (1MHz)	2387	2400	2392.161	-41.10	0.078	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2483.747	-41.21	0.076	25	Pass
	Band V (1MHz)	2496.5	12500	9924.09875	-36.79	0.209	2.50	Pass

Test Condition: NV, $\pi/4$ -DQPSK

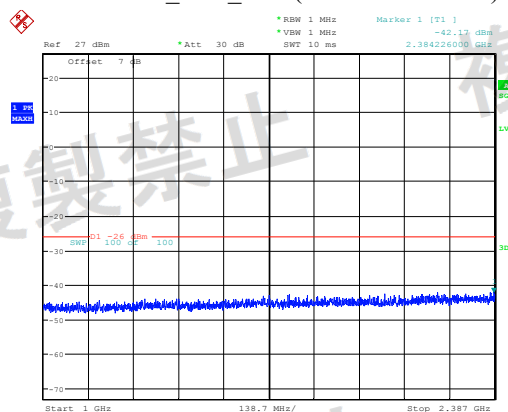
Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm/RBW)	Result (μ W/RBW)	Limit (μ W/RBW)	Verdict
		Start(MHz)	Stop(MHz)					
Low	Band I (100kHz)	30	1000	219.15	-46.97	0.020	0.25	Pass
	Band II (1MHz)	1000	2387	2143.5815	-41.92	0.064	2.50	Pass
	Band III (1MHz)	2387	2400	2399.9935	-22.04	6.252	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2491.248	-40.30	0.093	25	Pass
	Band V (1MHz)	2496.5	12500	9608.9885	-38.19	0.152	2.50	Pass
Middle	Band I (100kHz)	30	1000	789.51	-46.91	0.020	0.25	Pass
	Band II (1MHz)	1000	2387	2355.099	-41.95	0.064	2.50	Pass
	Band III (1MHz)	2387	2400	2395.2225	-40.70	0.085	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2484.306	-41.25	0.075	25	Pass
	Band V (1MHz)	2496.5	12500	9764.04275	-37.39	0.182	2.50	Pass
High	Band I (100kHz)	30	1000	57.16	-47.10	0.019	0.25	Pass
	Band II (1MHz)	1000	2387	2288.523	-39.77	0.105	2.50	Pass
	Band III (1MHz)	2387	2400	2389.236	-41.00	0.079	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2483.7925	-40.88	0.082	25	Pass
	Band V (1MHz)	2496.5	12500	9919.097	-36.36	0.231	2.50	Pass

Test Condition: NV, 8DPSK

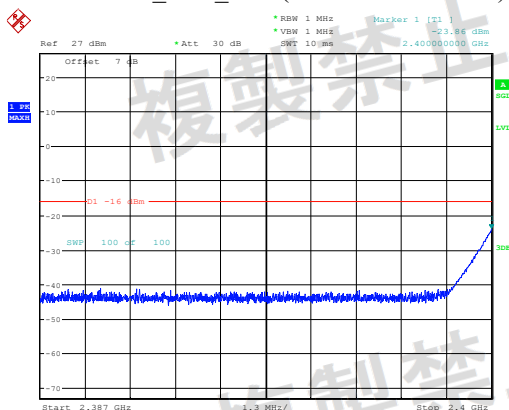
Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm/RBW)	Result (μW/RBW)	Limit (μW/RBW)	Verdict
		Start(MHz)	Stop(MHz)					
Low	Band I (100kHz)	30	1000	987.875	-46.85	0.021	0.25	Pass
	Band II (1MHz)	1000	2387	2346.777	-41.21	0.076	2.50	Pass
	Band III (1MHz)	2387	2400	2400	-21.88	6.486	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2494.966	-40.61	0.087	25	Pass
	Band V (1MHz)	2496.5	12500	9608.9885	-37.83	0.165	2.50	Pass
Middle	Band I (100kHz)	30	1000	412.665	-46.45	0.023	0.25	Pass
	Band II (1MHz)	1000	2387	2248.9935	-42.04	0.063	2.50	Pass
	Band III (1MHz)	2387	2400	2390.64	-40.77	0.084	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2488.9275	-40.70	0.085	25	Pass
	Band V (1MHz)	2496.5	12500	9764.04275	-37.02	0.199	2.50	Pass
High	Band I (100kHz)	30	1000	615.88	-45.74	0.027	0.25	Pass
	Band II (1MHz)	1000	2387	2288.523	-41.52	0.070	2.50	Pass
	Band III (1MHz)	2387	2400	2397.179	-41.02	0.079	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2495.85	-40.75	0.084	25	Pass
	Band V (1MHz)	2496.5	12500	9924.09875	-37.07	0.196	2.50	Pass

Test Condition: HV**GFSK_Low_DH1(30MHz~1GHz)**

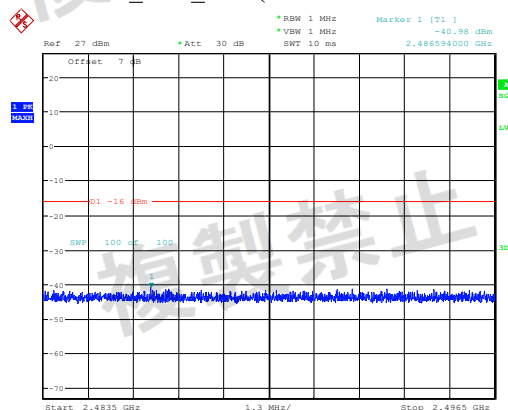
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 06:51:20

GFSK_Low_DH1(1GHz~2.387GHz)

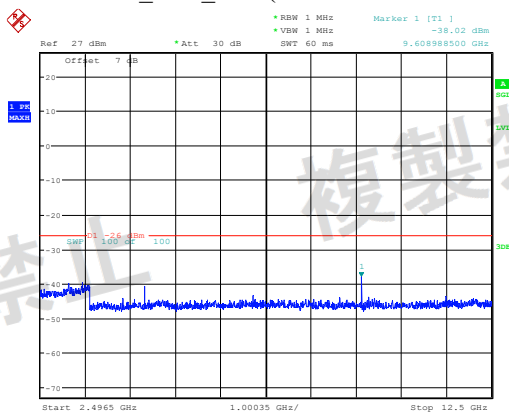
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 06:51:36

GFSK_Low_DH1(2.387GHz~2.4GHz)

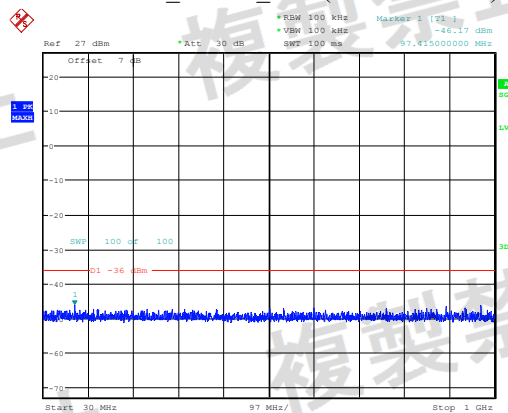
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 06:51:50

GFSK_Low_DH1(2.4835GHz~2.4965GHz)

ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 06:52:03

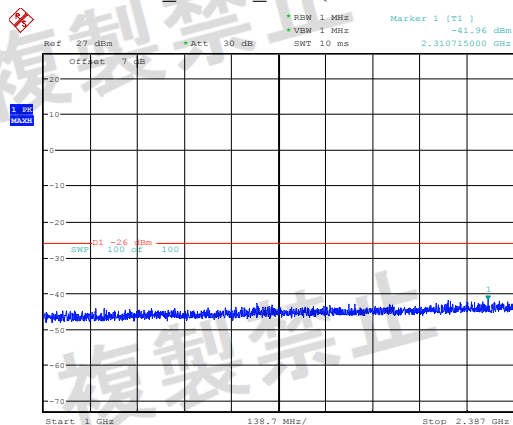
GFSK_Low_DH1(2.4965GHz~12.5GHz)

ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 06:52:34

GFSK_Middle_DH1(30MHz~1GHz)

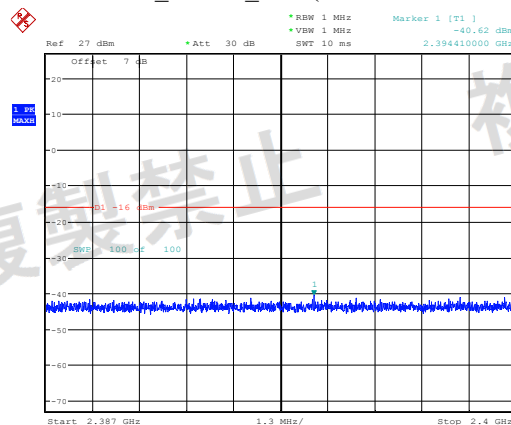
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 06:53:27

GFSK_Middle_DH1(1GHz~2.387GHz)



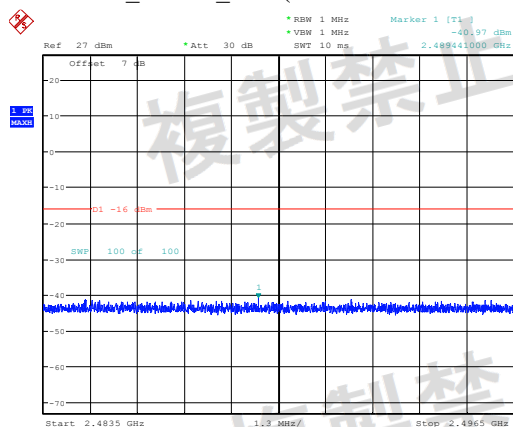
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 06:53:43

GFSK_Middle_DH1(2.387GHz~2.4GHz)



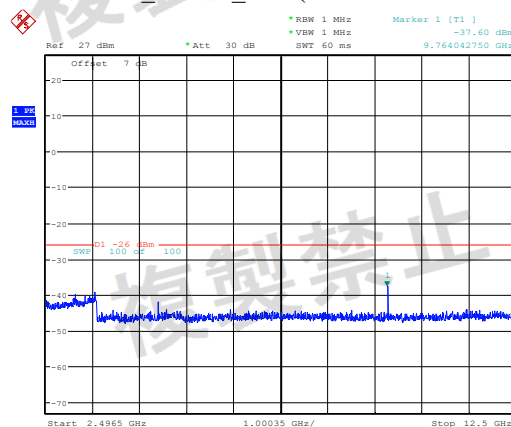
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 06:53:56

GFSK_Middle_DH1(2.4835GHz~2.4965GHz)



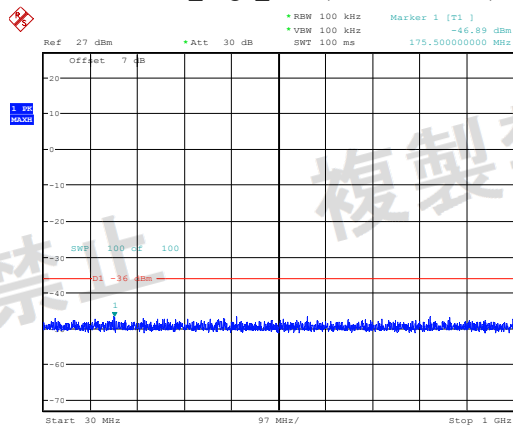
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 06:54:11

GFSK_Middle_DH1(2.4965GHz~12.5GHz)



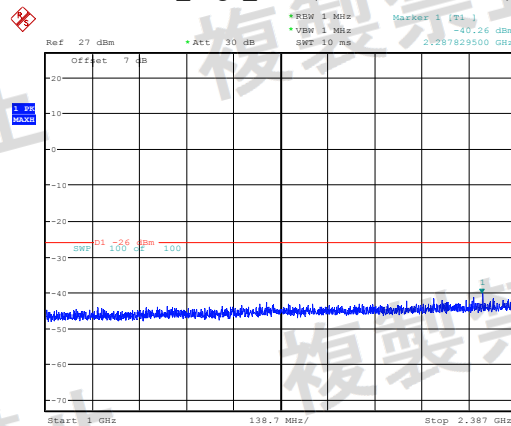
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 06:54:44

GFSK_High_DH1(30MHz~1GHz)



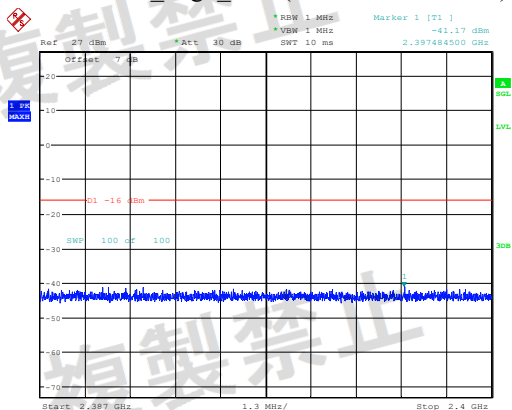
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 06:55:27

GFSK_High_DH1(1GHz~2.387GHz)



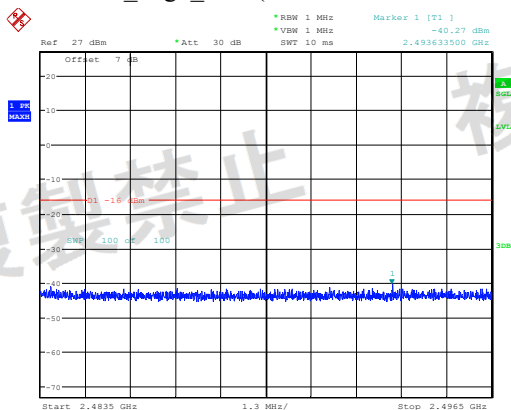
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 06:55:42

GFSK_High_DH1(2.387GHz~2.4GHz)



ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 06:55:55

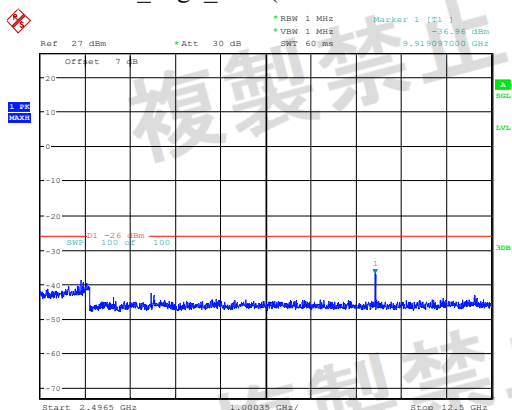
GFSK_High_DH1(2.4835GHz~2.4965GHz)



ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 06:56:08

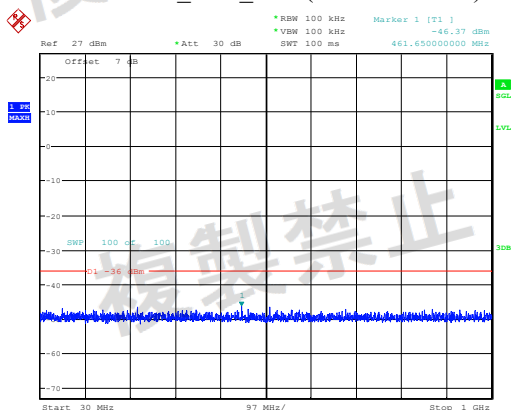
Test Condition: LV

GFSK_High_DH1(2.4965GHz~12.5GHz)



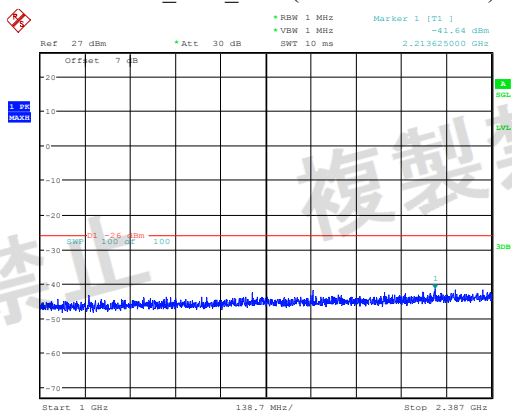
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 06:56:38

GFSK_Low_DH1(30MHz~1GHz)



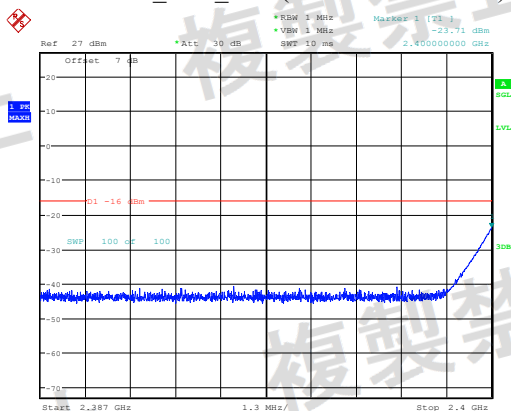
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:17:31

GFSK_Low_DH1(1GHz~2.387GHz)



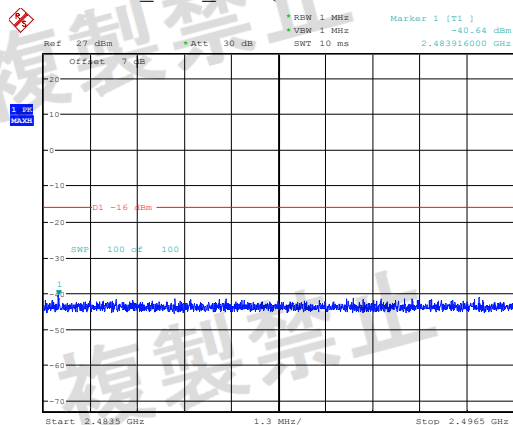
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:17:46

GFSK_Low_DH1(2.387GHz~2.4GHz)



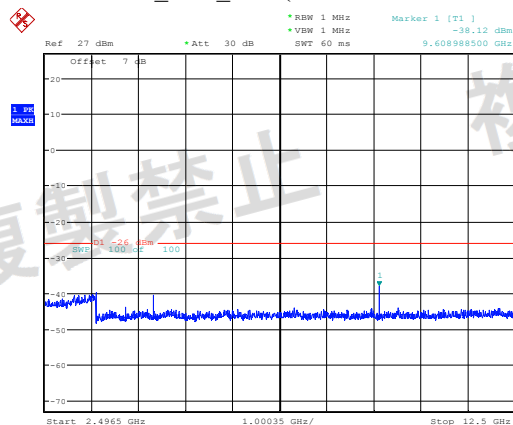
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:17:59

GFSK_Low_DH1(2.4835GHz~2.4965GHz)



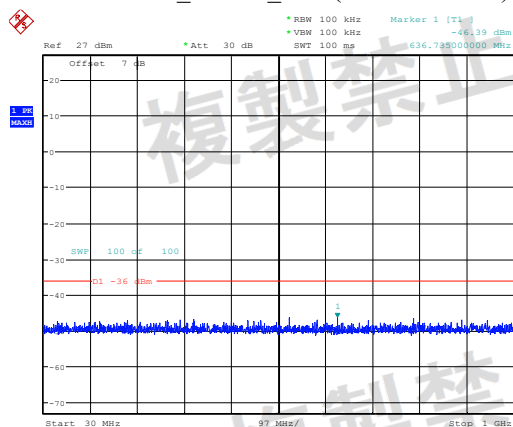
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:18:12

GFSK_Low_DH1(2.4965GHz~12.5GHz)



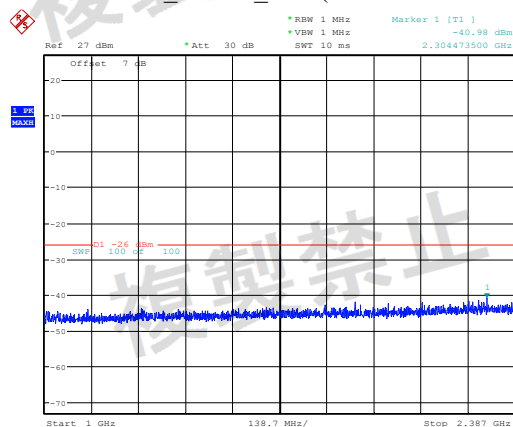
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:18:43

GFSK_Middle_DH1(30MHz~1GHz)



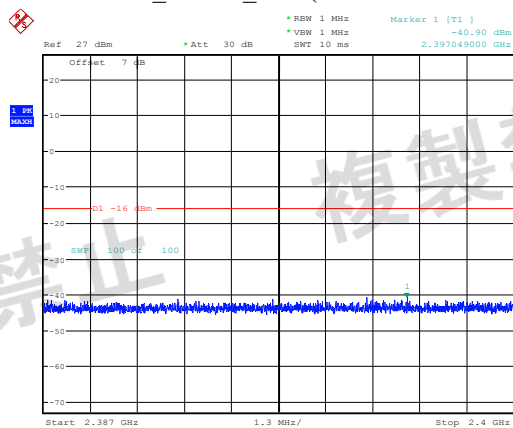
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:19:41

GFSK_Middle_DH1(1GHz~2.387GHz)



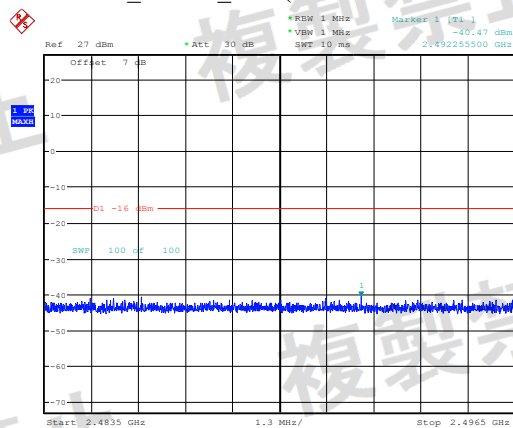
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:19:58

GFSK_Middle_DH1(2.387GHz~2.4GHz)



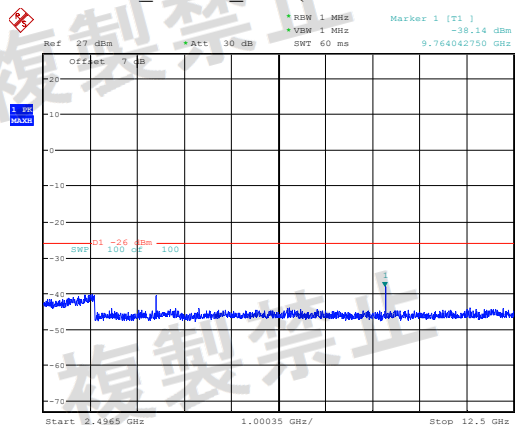
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:20:11

GFSK_Middle_DH1(2.4835GHz~2.4965GHz)



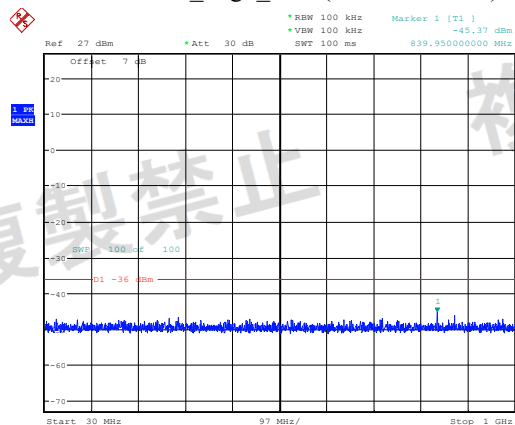
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:20:24

GFSK_Middle_DH1(2.4965GHz~12.5GHz)



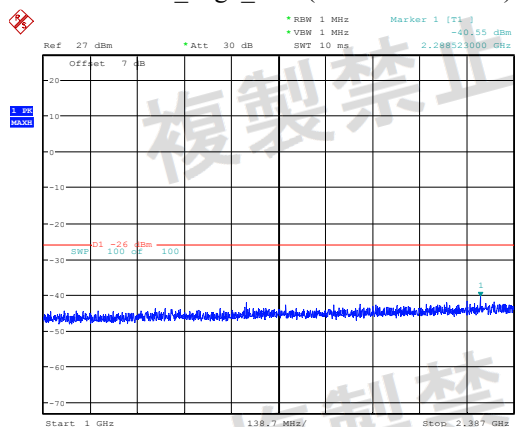
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:20:54

GFSK_High_DH1(30MHz~1GHz)



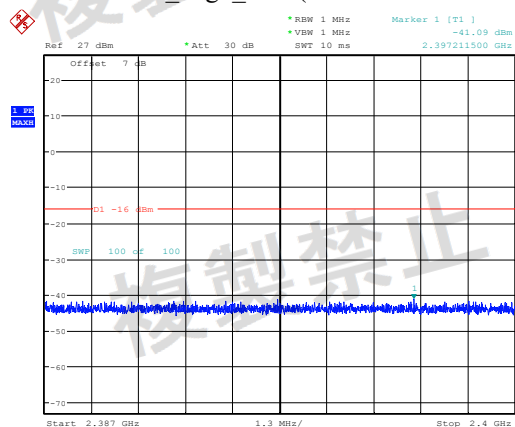
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:21:33

GFSK_High_DH1(1GHz~2.387GHz)



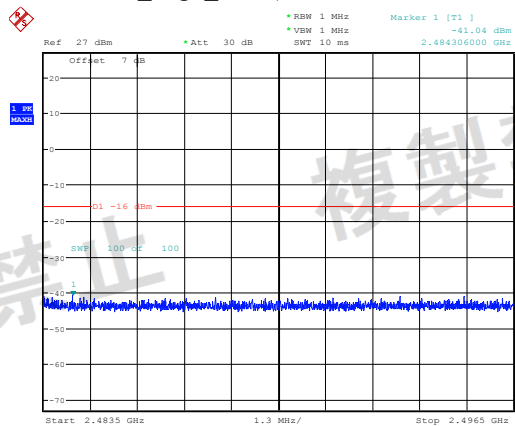
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:21:48

GFSK_High_DH1(2.387GHz~2.4GHz)



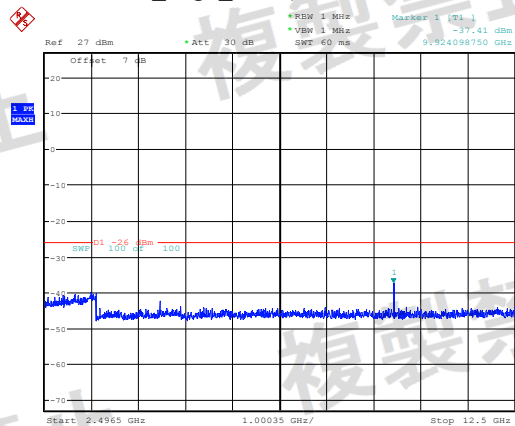
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:22:01

GFSK_High_DH1(2.4835GHz~2.4965GHz)



ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:22:14

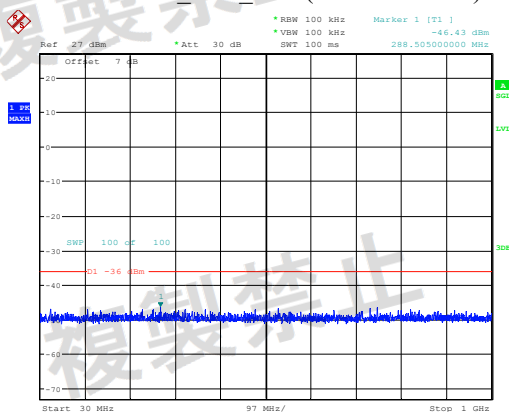
GFSK_High_DH1(2.4965GHz~12.5GHz)



ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:22:44

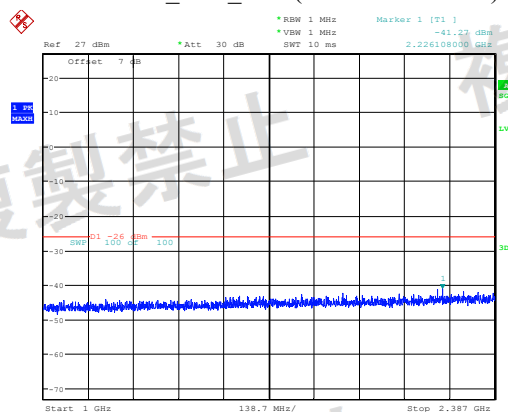
Test Condition: NV

GFSK_Low_DH1(30MHz~1GHz)



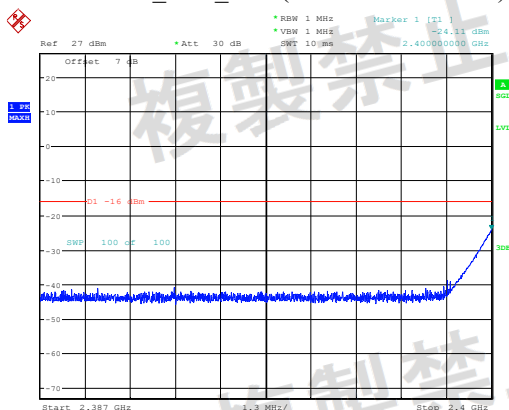
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 03:42:57

GFSK_Low_DH1(1GHz~2.387GHz)



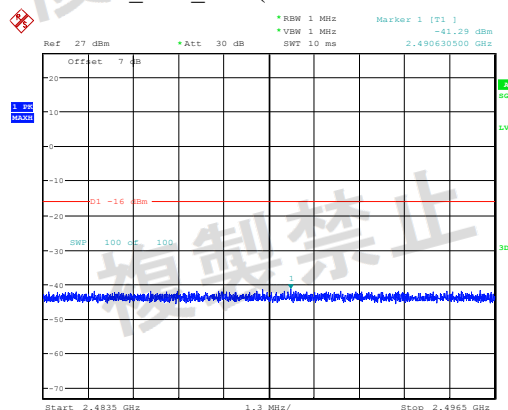
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 03:43:13

GFSK_Low_DH1(2.387GHz~2.4GHz)



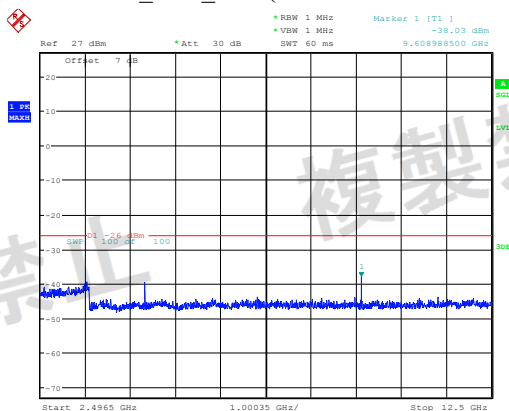
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 03:43:26

GFSK_Low_DH1(2.4835GHz~2.4965GHz)



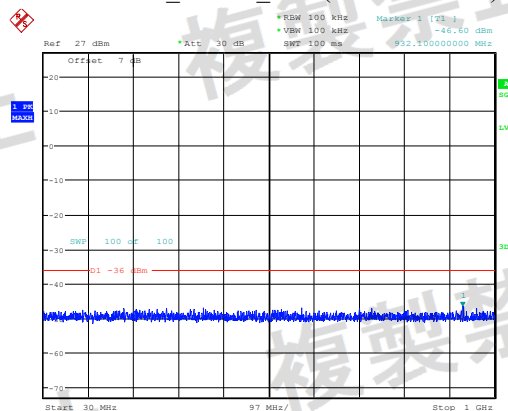
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 03:43:39

GFSK_Low_DH1(2.4965GHz~12.5GHz)



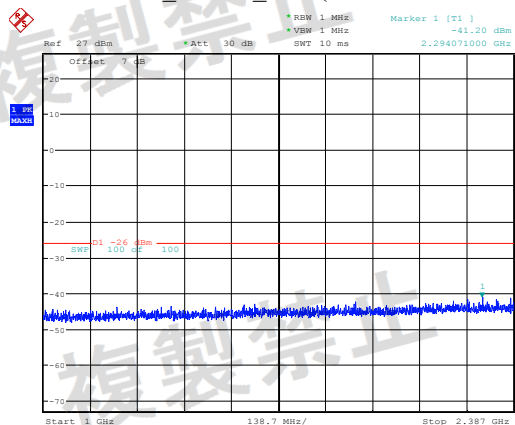
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 03:44:10

GFSK_Middle_DH1(30MHz~1GHz)



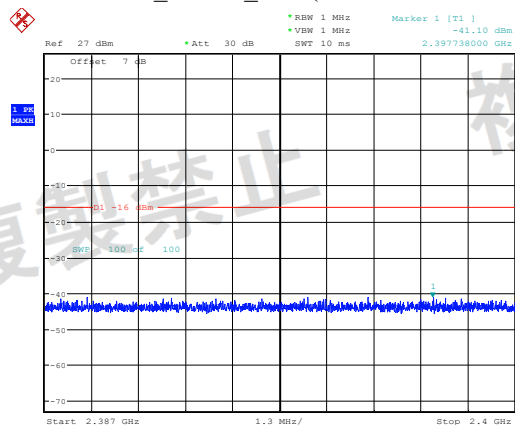
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 03:45:19

GFSK_Middle_DH1(1GHz~2.387GHz)



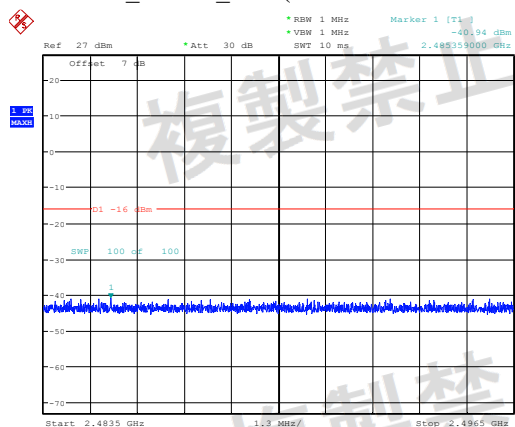
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 03:45:34

GFSK_Middle_DH1(2.387GHz~2.4GHz)



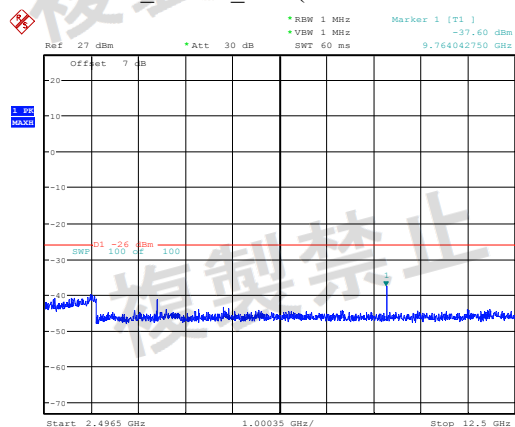
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 03:45:48

GFSK_Middle_DH1(2.4835GHz~2.4965GHz)



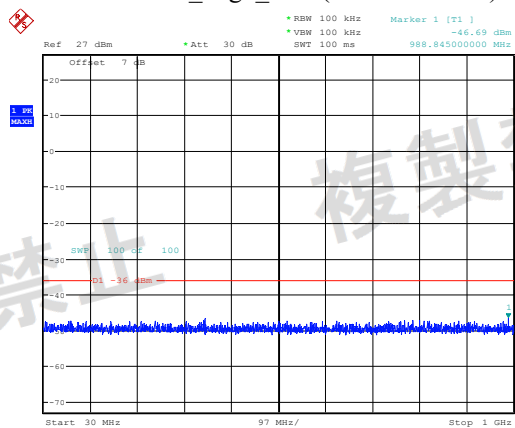
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 03:46:00

GFSK_Middle_DH1(2.4965GHz~12.5GHz)



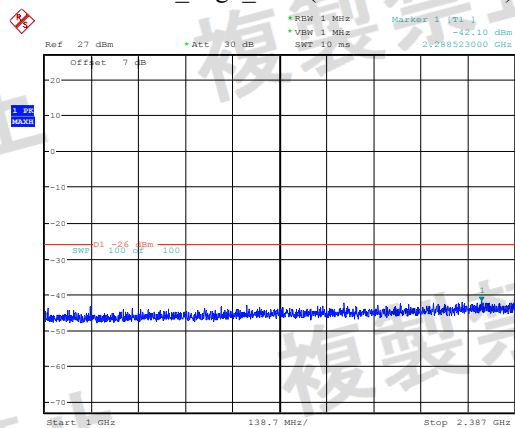
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 03:46:31

GFSK_High_DH1(30MHz~1GHz)



ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 03:47:18

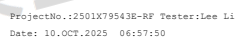
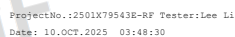
GFSK_High_DH1(1GHz~2.387GHz)



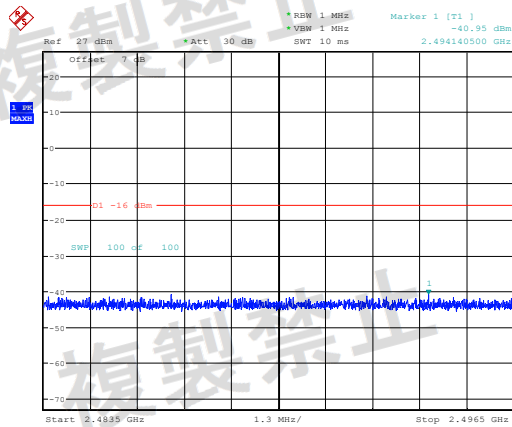
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 03:47:33



$\pi/4$ -DQPSK Low 2DH1(30MHz~1GHz)

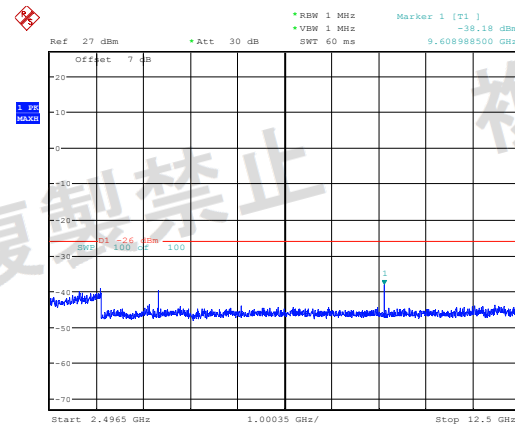


$\pi/4$ -DQPSK_Low_2DH1(2.4835GHz~2.4965GHz)



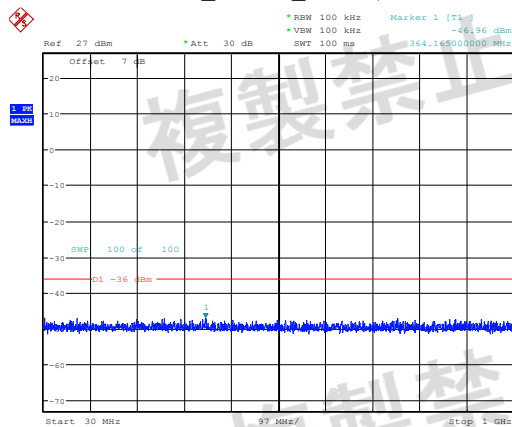
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 06:58:04

$\pi/4$ -DQPSK_Low_2DH1(2.4965GHz~12.5GHz)



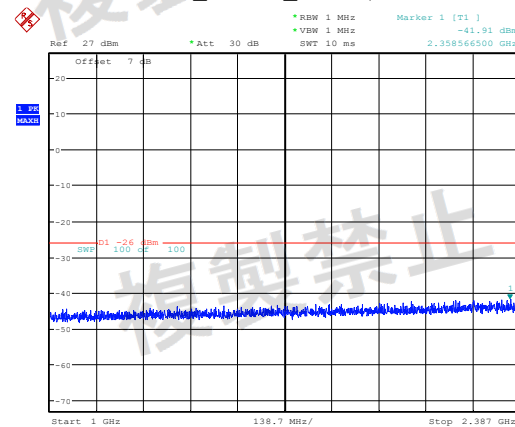
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 06:58:35

$\pi/4$ -DQPSK_Middle_2DH1(30MHz~1GHz)



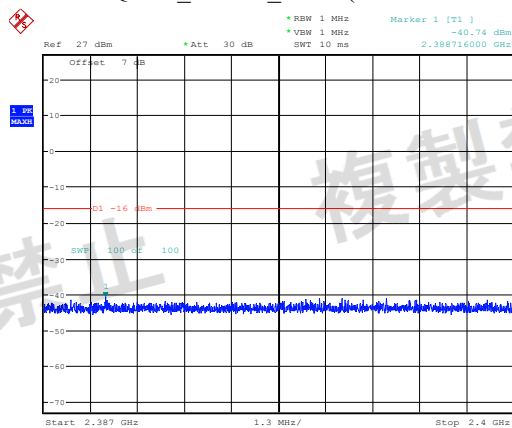
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 06:59:07

$\pi/4$ -DQPSK_Middle_2DH1(1GHz~2.387GHz)



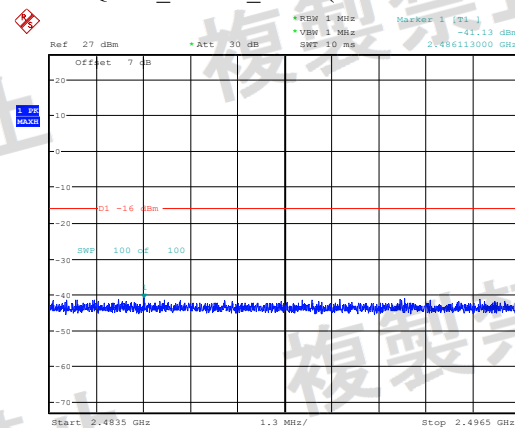
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 06:59:22

$\pi/4$ -DQPSK_Middle_2DH1(2.387GHz~2.4GHz)



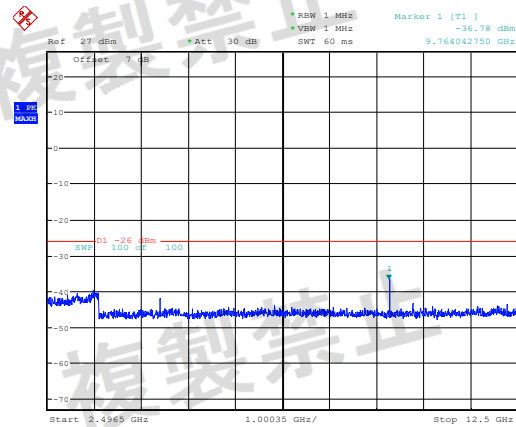
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 06:59:34

$\pi/4$ -DQPSK Middle 2DH1(2.4835GHz~2.4965GHz)



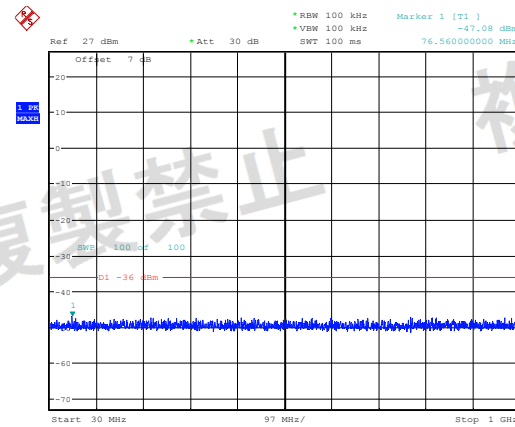
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 06:59:47

$\pi/4$ -DQPSK_Middle_2DH1(2.4965GHz~12.5GHz)



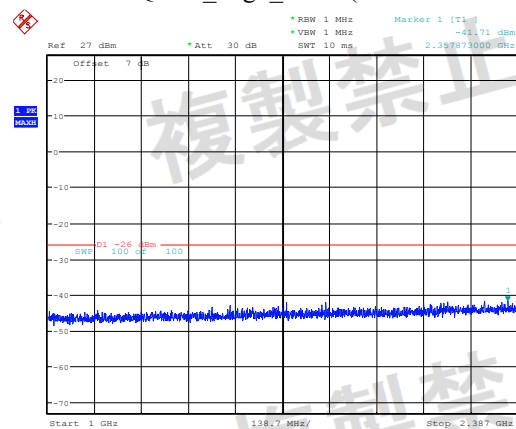
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 07:00:17

$\pi/4$ -DQPSK_High_2DH1(30MHz~1GHz)



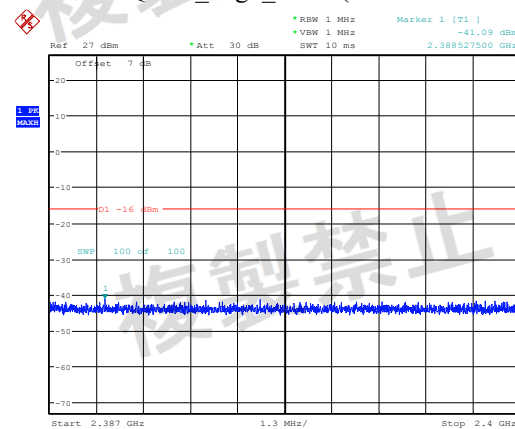
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 07:00:54

$\pi/4$ -DQPSK_High_2DH1(1GHz~2.387GHz)



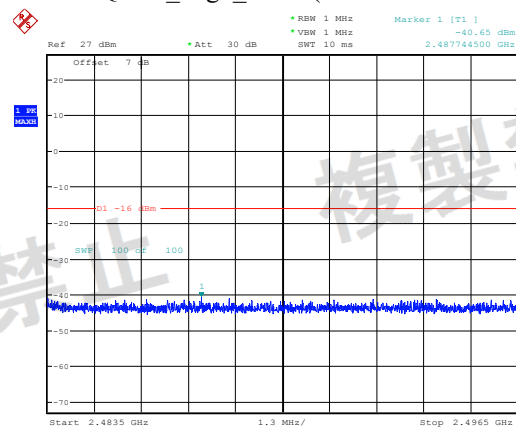
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 07:01:09

$\pi/4$ -DQPSK_High_2DH1(2.387GHz~2.4GHz)



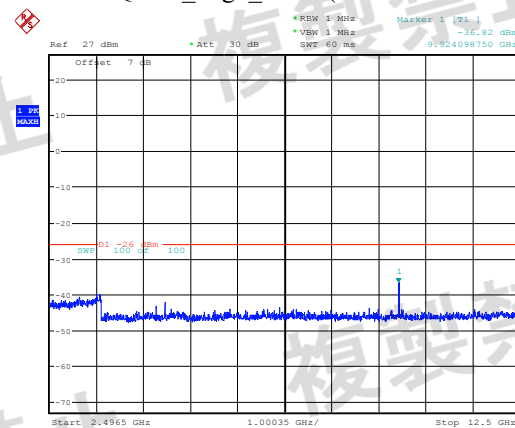
ProjectNo.:2501X79543E-RF Tester:Lee LS
Date: 10.OCT.2025 07:01:21

$\pi/4$ -DQPSK_High_2DH1(2.4835GHz~2.4965GHz)



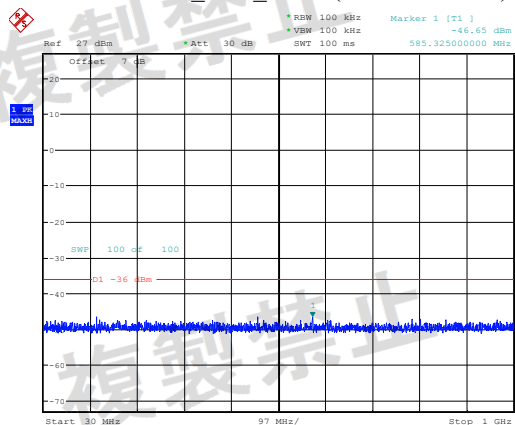
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 07:01:33

$\pi/4$ -DQPSK_High_2DH1(2.4965GHz~12.5GHz)



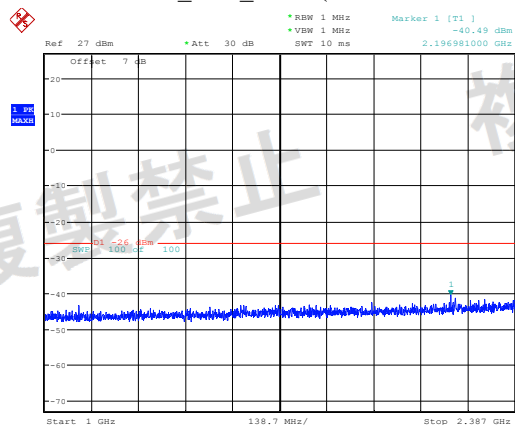
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 07:02:03

8DPSK_Low_3DH1(30MHz~1GHz)



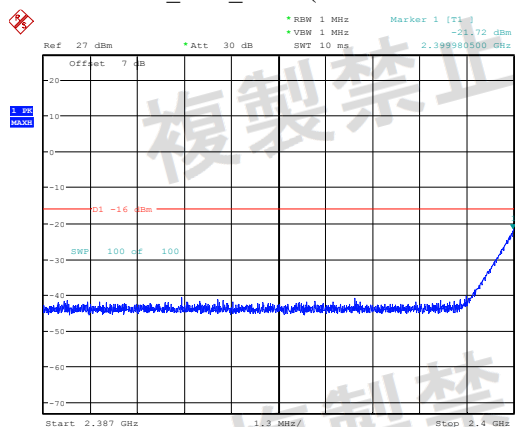
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 07:02:45

8DPSK_Low_3DH1(1GHz~2.387GHz)



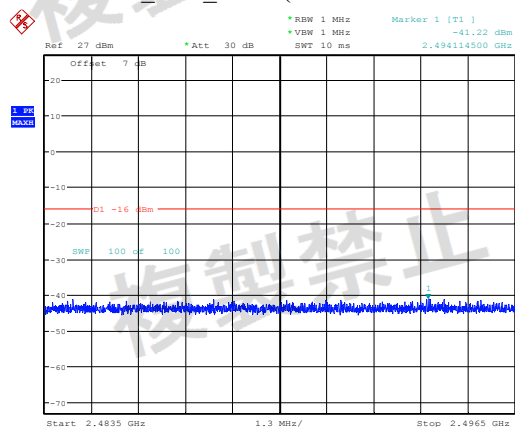
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 07:03:01

8DPSK_Low_3DH1(2.387GHz~2.4GHz)



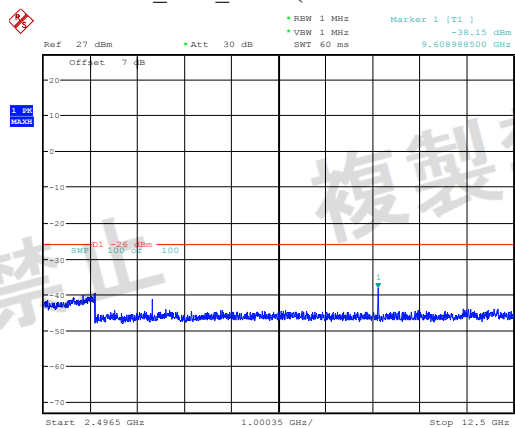
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 07:03:13

8DPSK_Low_3DH1(2.4835GHz~2.4965GHz)



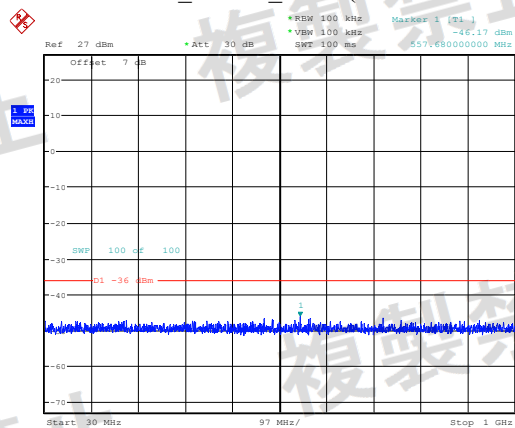
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 07:03:26

8DPSK_Low_3DH1(2.4965GHz~12.5GHz)



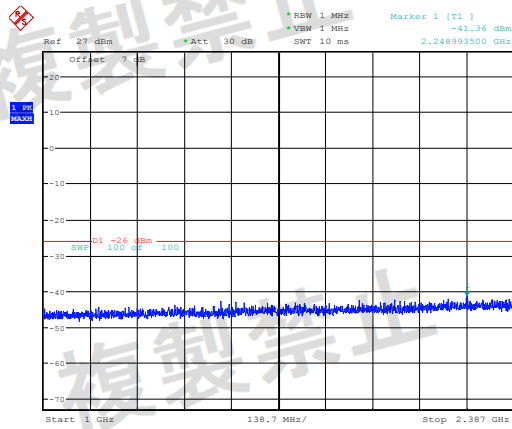
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 07:03:55

8DPSK_Middle_3DH1(30MHz~1GHz)



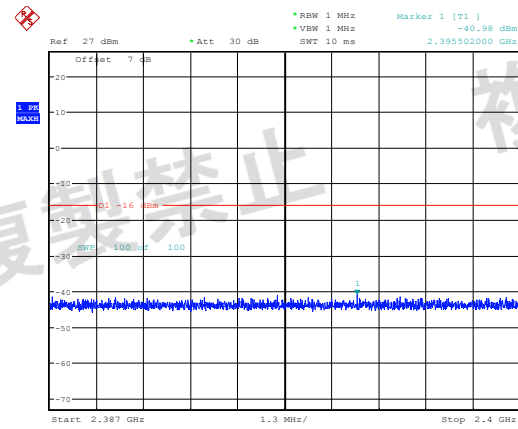
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 07:04:29

8DPSK_Middle_3DH1(1GHz~2.387GHz)



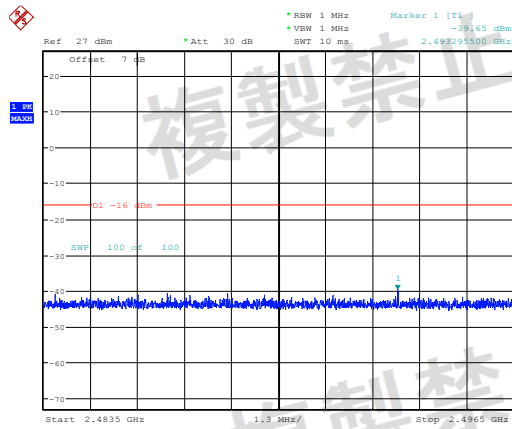
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 07:04:44

8DPSK_Middle_3DH1(2.387GHz~2.4GHz)



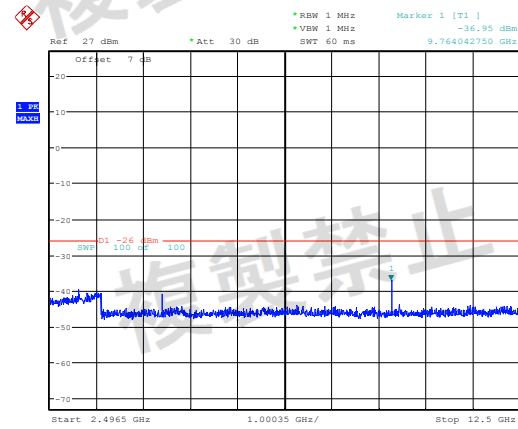
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 07:04:57

8DPSK_Middle_3DH1(2.4835GHz~2.4965GHz)



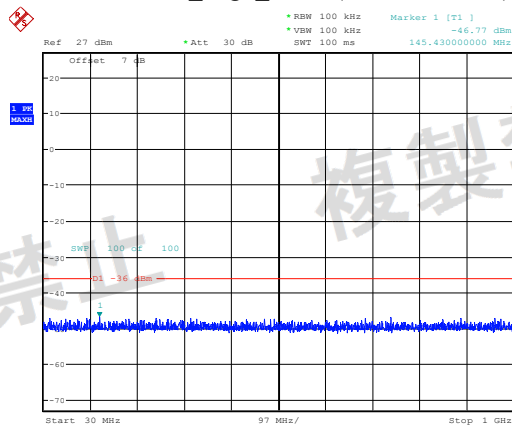
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 07:05:10

8DPSK_Middle_3DH1(2.4965GHz~12.5GHz)



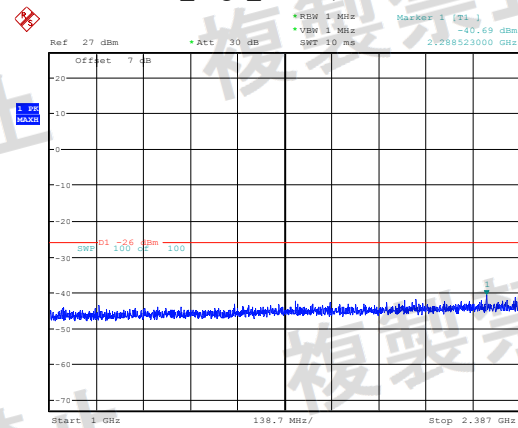
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 07:05:40

8DPSK_High_3DH1(30MHz~1GHz)



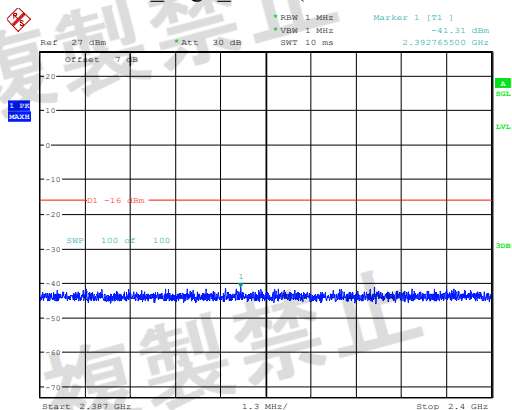
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 07:06:17

8DPSK_High_3DH1(1GHz~2.387GHz)



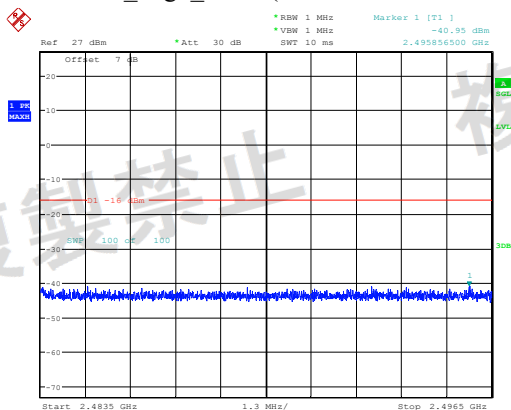
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 07:06:33

8DPSK_High_3DH1(2.387GHz~2.4GHz)



ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 07:06:46

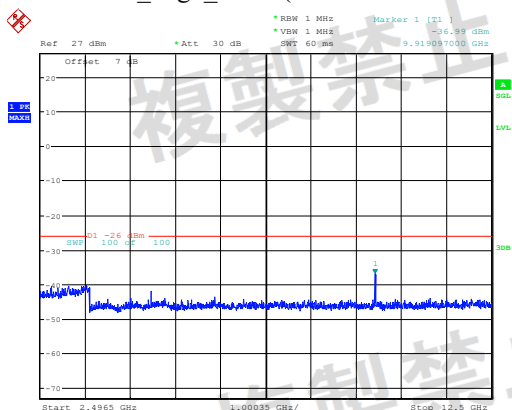
8DPSK_High_3DH1(2.4835GHz~2.4965GHz)



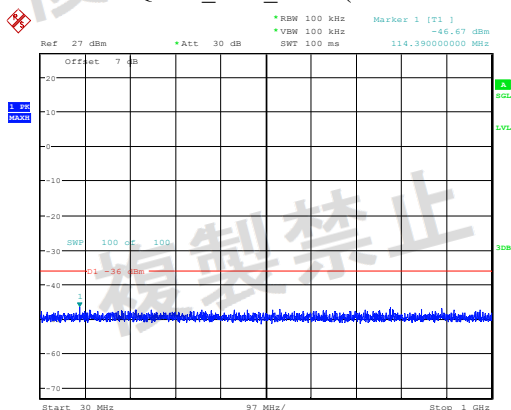
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 07:06:59

Test Condition: LV

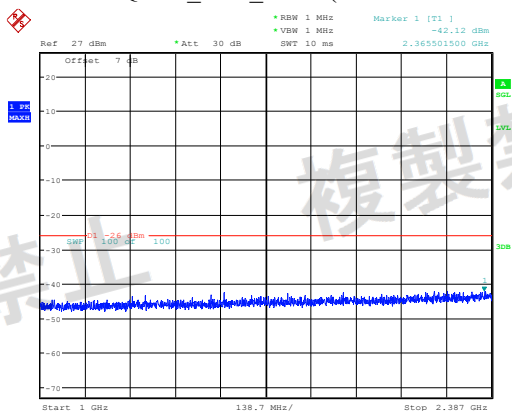
8DPSK_High_3DH1(2.4965GHz~12.5GHz)



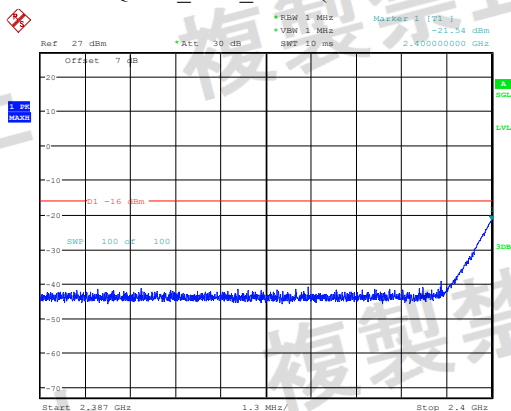
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 07:07:29

 $\pi/4$ -DQPSK_Low_2DH1(30MHz~1GHz)

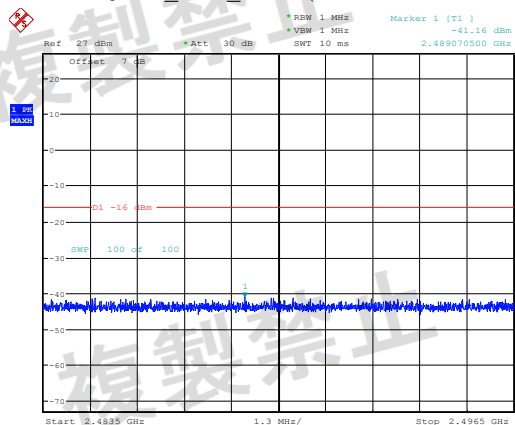
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:23:46

 $\pi/4$ -DQPSK_Low_2DH1(1GHz~2.387GHz)

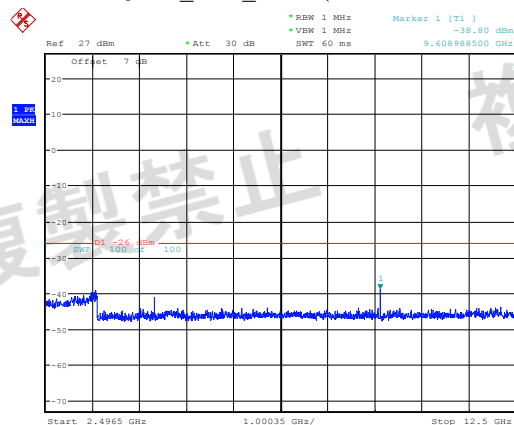
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:24:01

 $\pi/4$ -DQPSK_Low_2DH1(2.387GHz~2.4GHz)

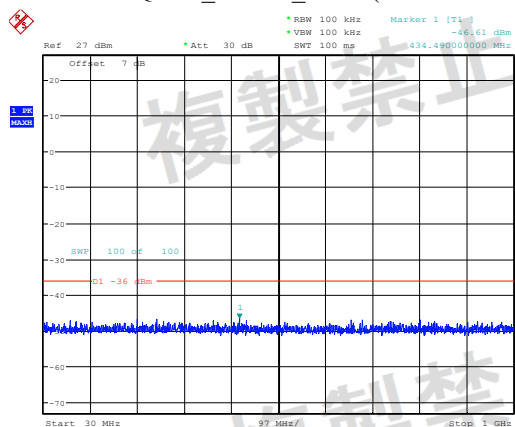
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:24:13

$\pi/4$ -DQPSK_Low_2DH1(2.4835GHz~2.4965GHz)

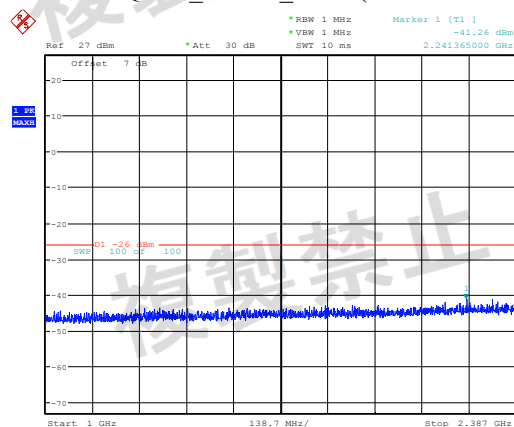
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:24:27

 $\pi/4$ -DQPSK_Low_2DH1(2.4965GHz~12.5GHz)

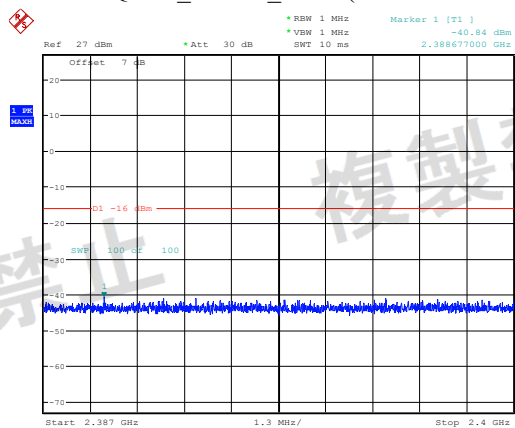
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:24:57

 $\pi/4$ -DQPSK_Middle_2DH1(30MHz~1GHz)

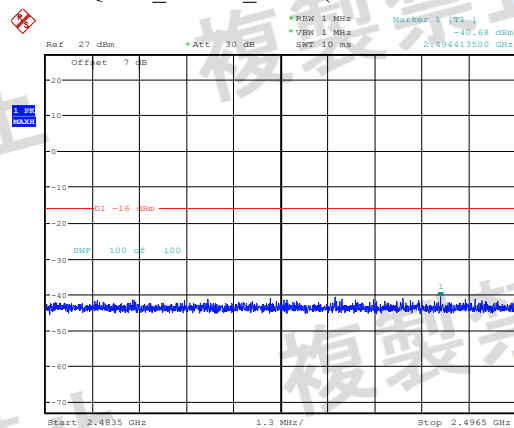
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:26:04

 $\pi/4$ -DQPSK_Middle_2DH1(1GHz~2.387GHz)

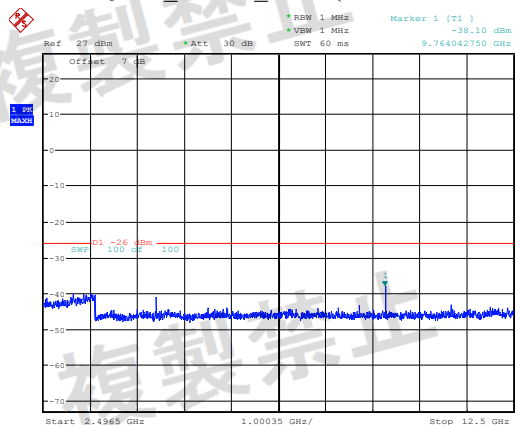
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:26:19

 $\pi/4$ -DQPSK_Middle_2DH1(2.387GHz~2.4GHz)

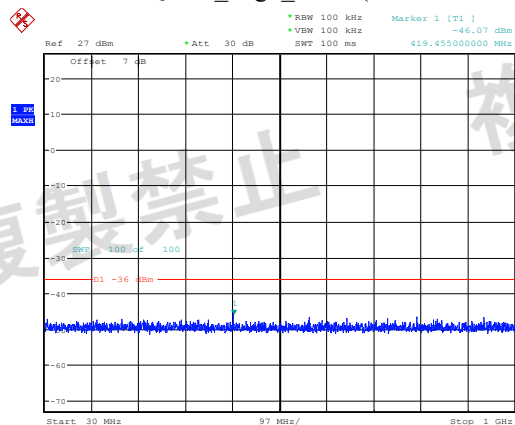
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:26:33

 $\pi/4$ -DQPSK_Middle_2DH1(2.4835GHz~2.4965GHz)

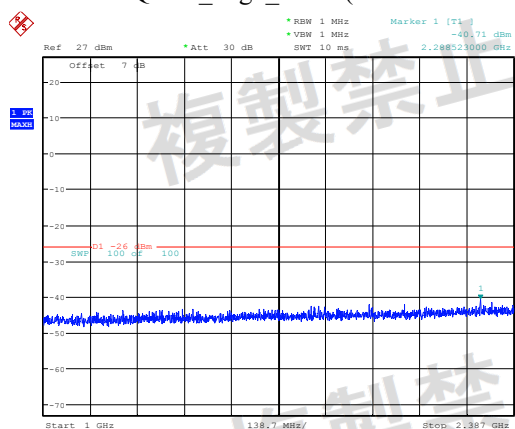
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:26:47

$\pi/4$ -DQPSK_Middle_2DH1(2.4965GHz~12.5GHz)

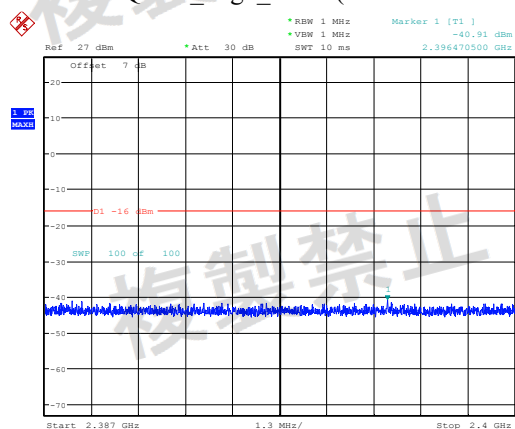
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:27:17

 $\pi/4$ -DQPSK_High_2DH1(30MHz~1GHz)

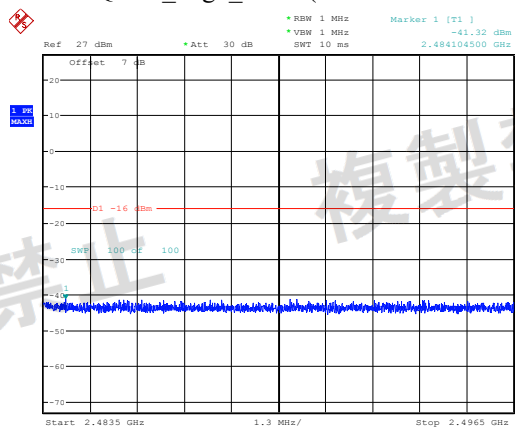
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:28:26

 $\pi/4$ -DQPSK_High_2DH1(1GHz~2.387GHz)

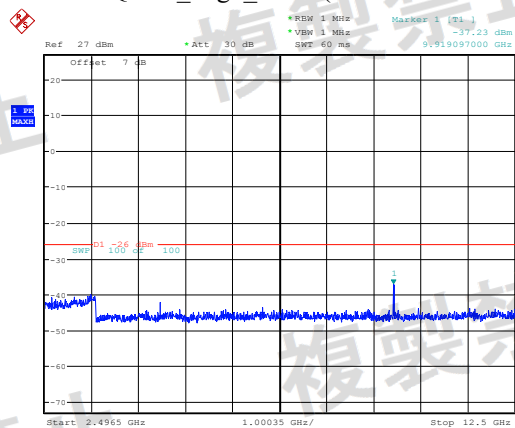
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:28:41

 $\pi/4$ -DQPSK_High_2DH1(2.387GHz~2.4GHz)

ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:28:55

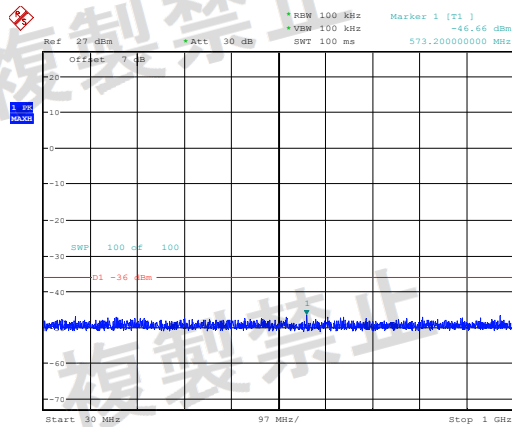
 $\pi/4$ -DQPSK_High_2DH1(2.4835GHz~2.4965GHz)

ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:29:08

 $\pi/4$ -DQPSK_High_2DH1(2.4965GHz~12.5GHz)

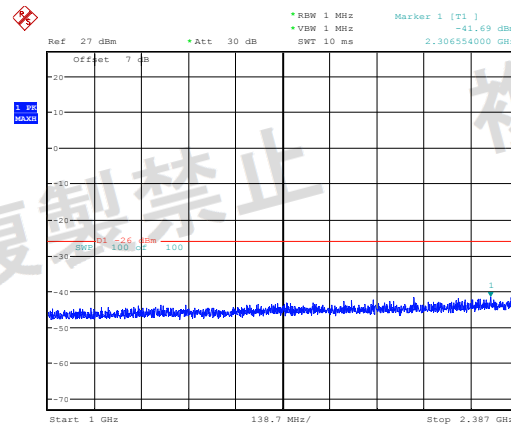
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:29:39

8DPSK_Low_3DH1(30MHz~1GHz)



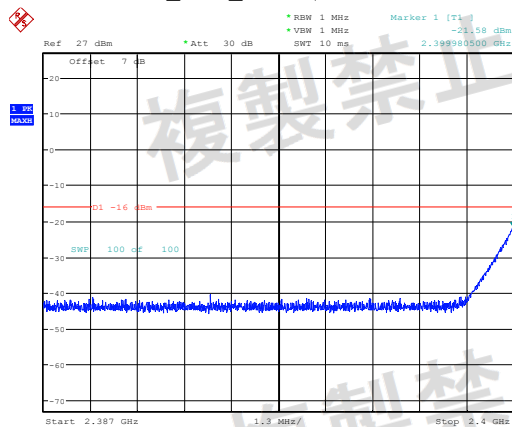
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:30:31

8DPSK_Low_3DH1(1GHz~2.387GHz)



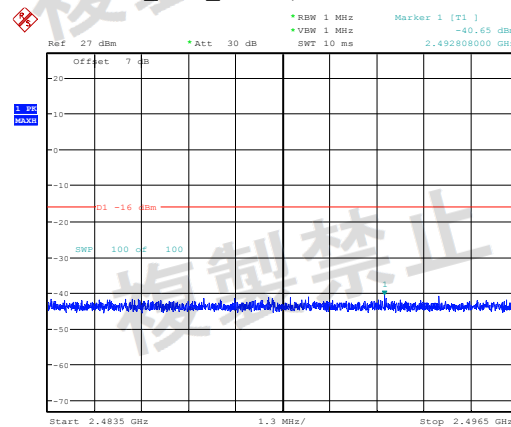
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:30:46

8DPSK_Low_3DH1(2.387GHz~2.4GHz)



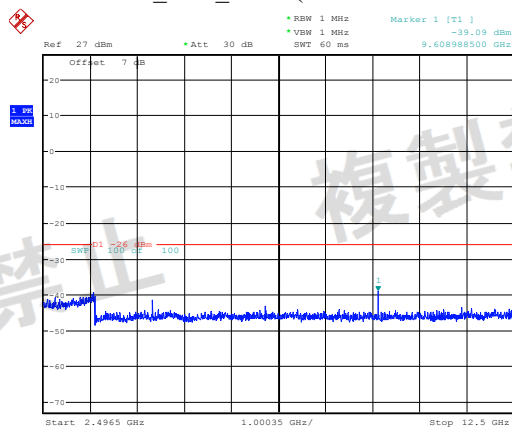
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:30:59

8DPSK_Low_3DH1(2.4835GHz~2.4965GHz)



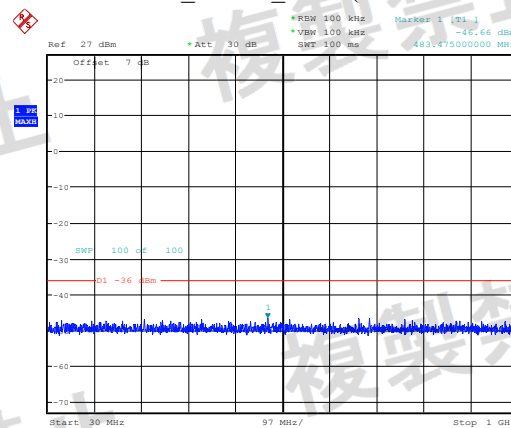
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:31:11

8DPSK_Low_3DH1(2.4965GHz~12.5GHz)



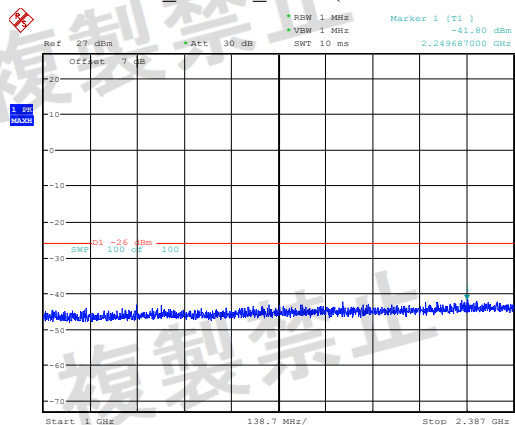
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:31:41

8DPSK_Middle_3DH1(30MHz~1GHz)



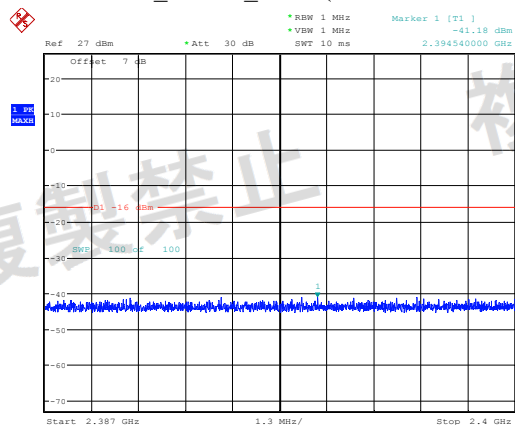
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:32:51

8DPSK_Middle_3DH1(1GHz~2.387GHz)



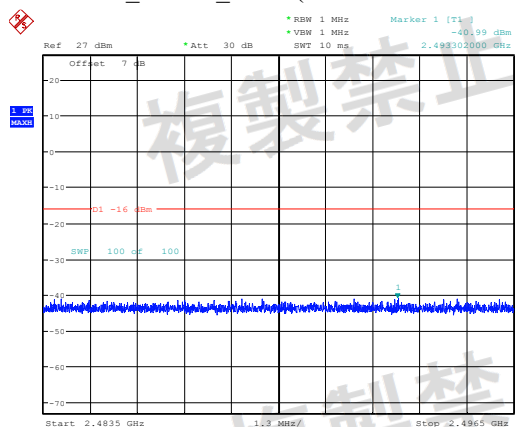
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:33:06

8DPSK_Middle_3DH1(2.387GHz~2.4GHz)



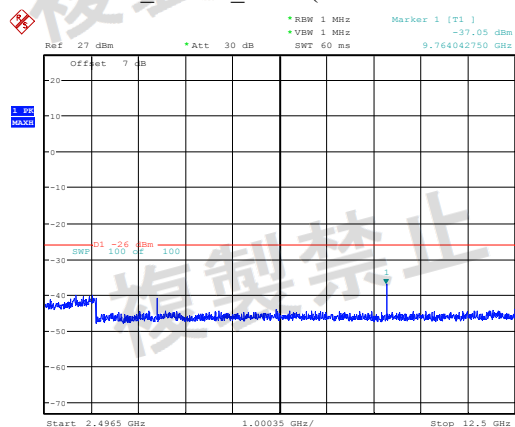
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:33:19

8DPSK_Middle_3DH1(2.4835GHz~2.4965GHz)



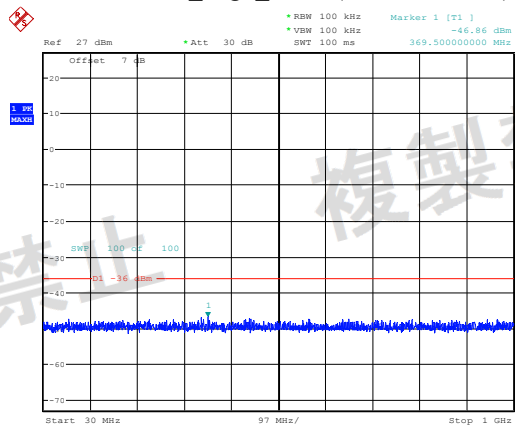
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:33:31

8DPSK_Middle_3DH1(2.4965GHz~12.5GHz)



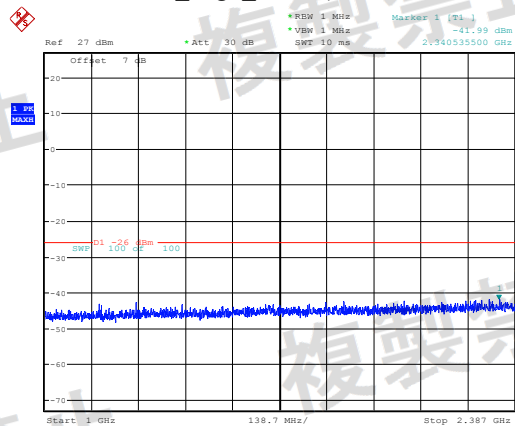
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:34:01

8DPSK_High_3DH1(30MHz~1GHz)



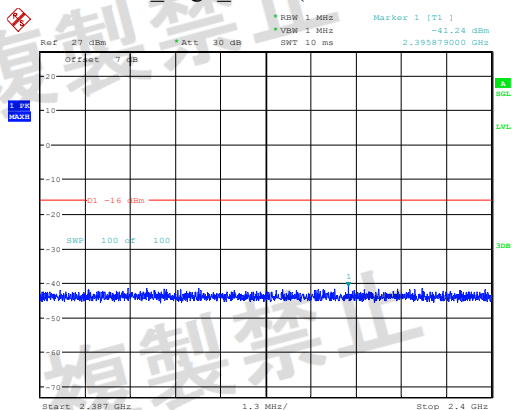
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:34:34

8DPSK_High_3DH1(1GHz~2.387GHz)



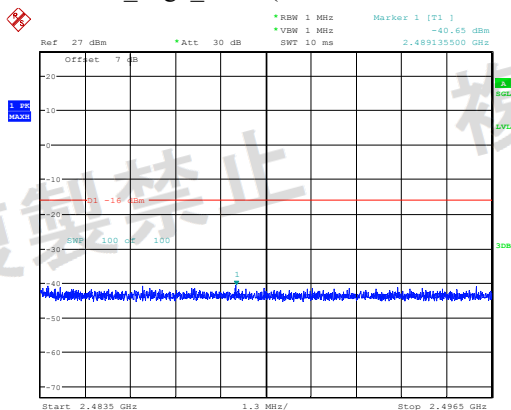
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:34:50

8DPSK_High_3DH1(2.387GHz~2.4GHz)



ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:35:02

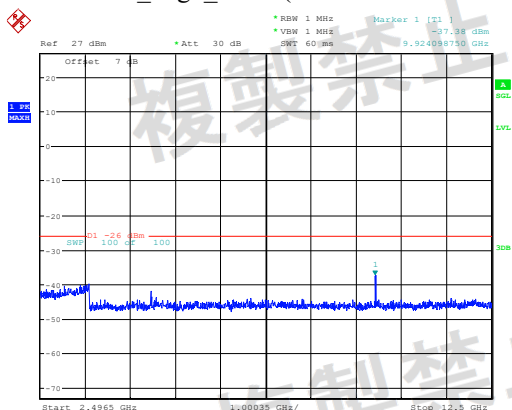
8DPSK_High_3DH1(2.4835GHz~2.4965GHz)



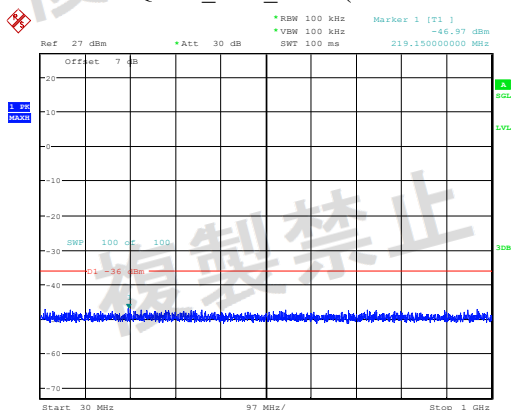
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:35:15

Test Condition: NV

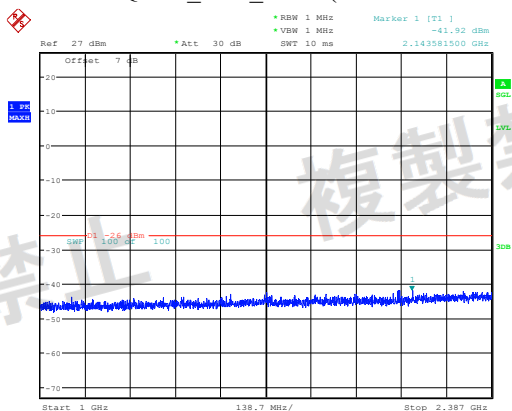
8DPSK_High_3DH1(2.4965GHz~12.5GHz)



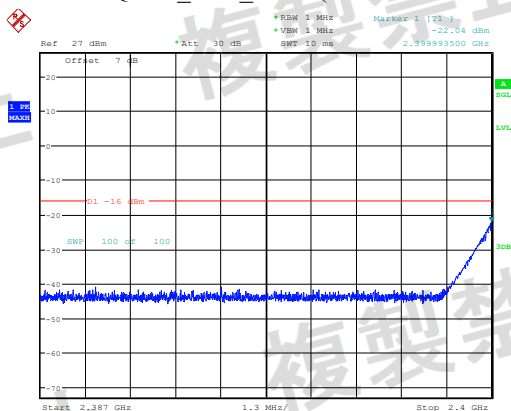
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:35:44

 $\pi/4$ -DQPSK_Low_2DH1(30MHz~1GHz)

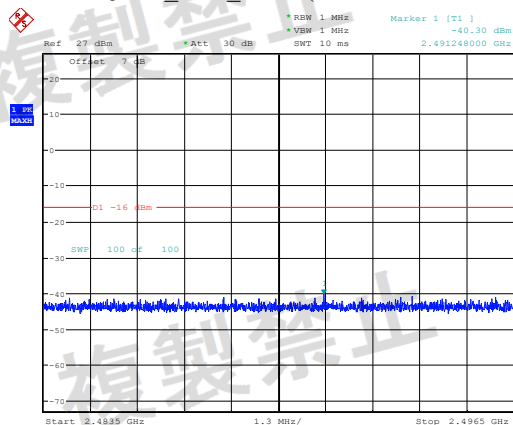
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 03:49:39

 $\pi/4$ -DQPSK_Low_2DH1(1GHz~2.387GHz)

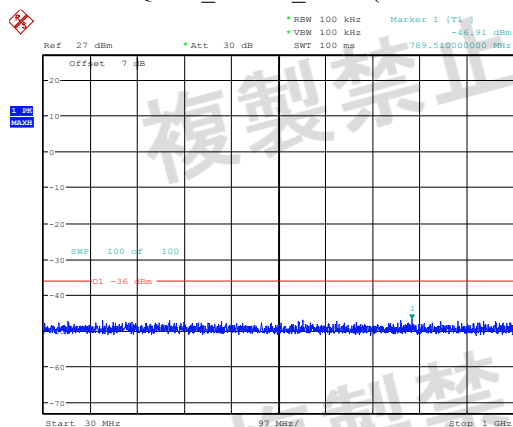
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 03:49:54

 $\pi/4$ -DQPSK_Low_2DH1(2.387GHz~2.4GHz)

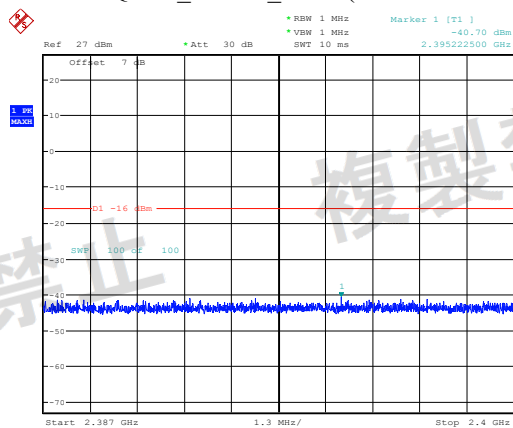
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 03:50:07

$\pi/4$ -DQPSK_Low_2DH1(2.4835GHz~2.4965GHz)

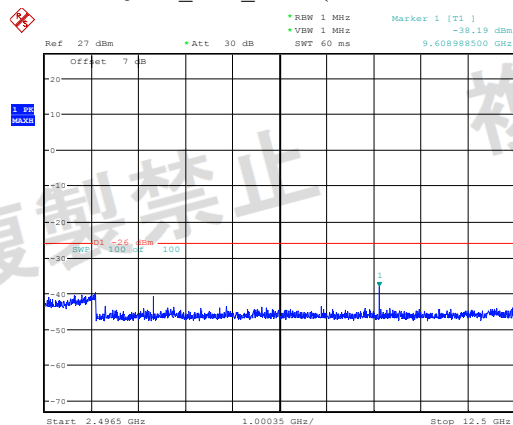
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 03:50:19

 $\pi/4$ -DQPSK_Middle_2DH1(30MHz~1GHz)

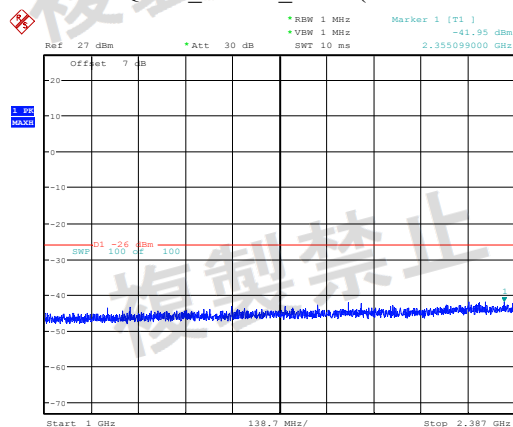
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 03:51:50

 $\pi/4$ -DQPSK_Middle_2DH1(2.387GHz~2.4GHz)

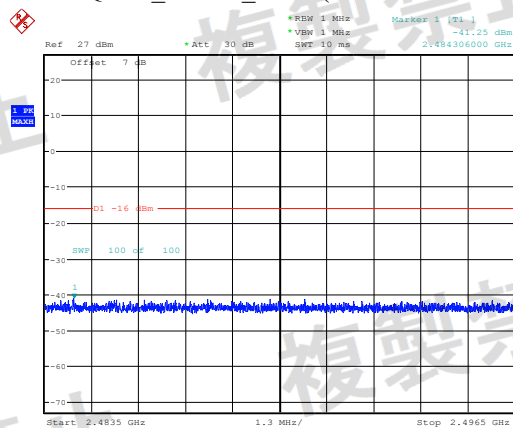
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 03:52:17

 $\pi/4$ -DQPSK_Low_2DH1(2.4965GHz~12.5GHz)

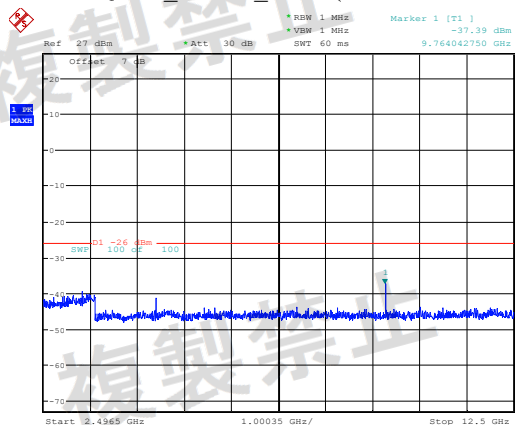
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 03:50:50

 $\pi/4$ -DQPSK_Middle_2DH1(1GHz~2.387GHz)

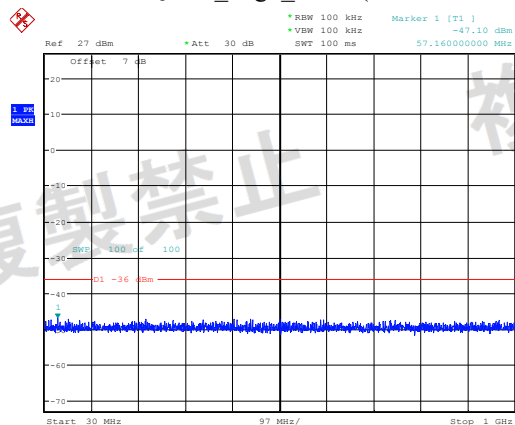
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 03:52:05

 $\pi/4$ -DQPSK_Middle_2DH1(2.4835GHz~2.4965GHz)

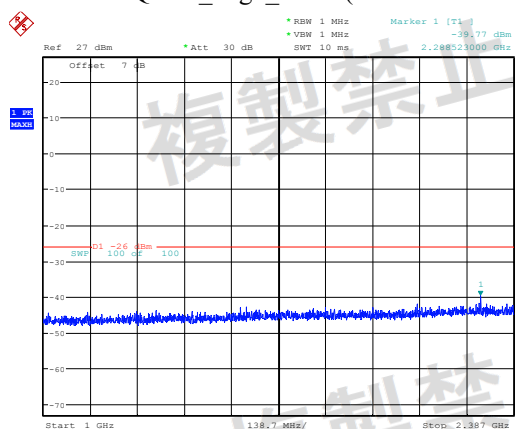
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 03:52:29

$\pi/4$ -DQPSK_Middle_2DH1(2.4965GHz~12.5GHz)

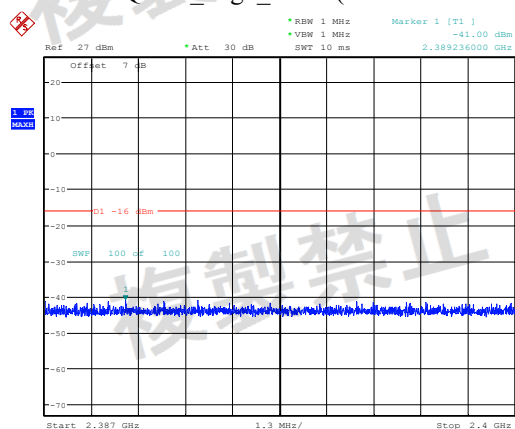
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 03:52:59

 $\pi/4$ -DQPSK_High_2DH1(30MHz~1GHz)

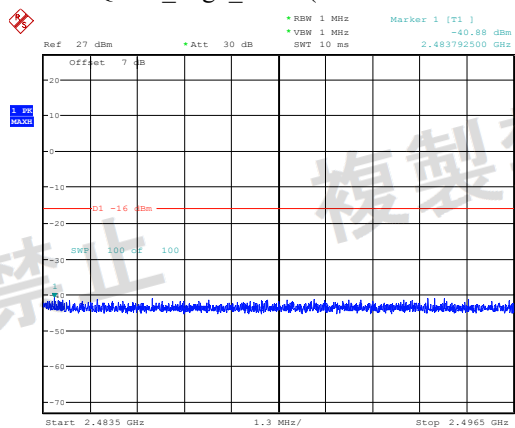
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 03:53:33

 $\pi/4$ -DQPSK_High_2DH1(1GHz~2.387GHz)

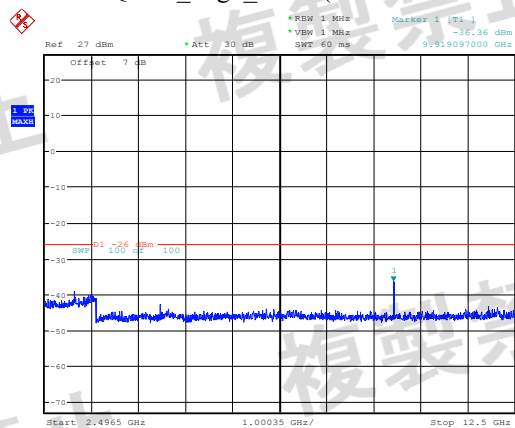
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 03:53:48

 $\pi/4$ -DQPSK_High_2DH1(2.387GHz~2.4GHz)

ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 03:54:01

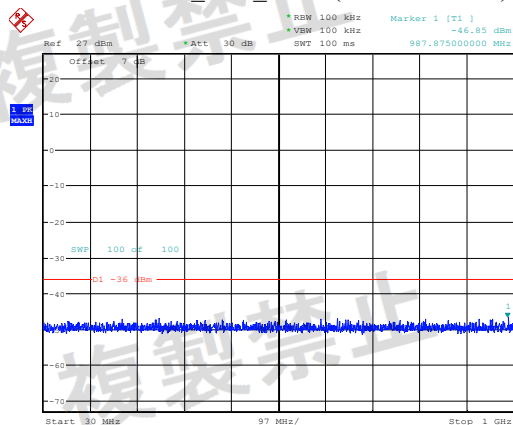
 $\pi/4$ -DQPSK_High_2DH1(2.4835GHz~2.4965GHz)

ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 03:54:14

 $\pi/4$ -DQPSK_High_2DH1(2.4965GHz~12.5GHz)

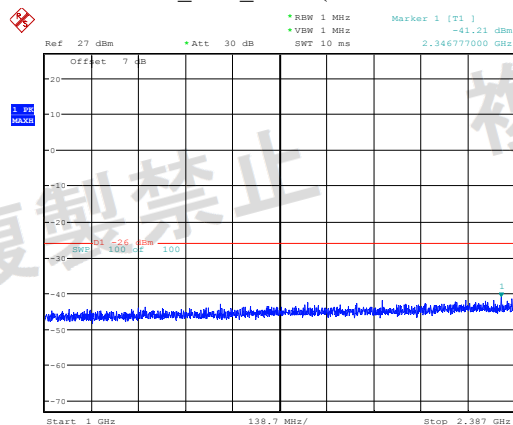
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 03:54:45

8DPSK_Low_3DH1(30MHz~1GHz)



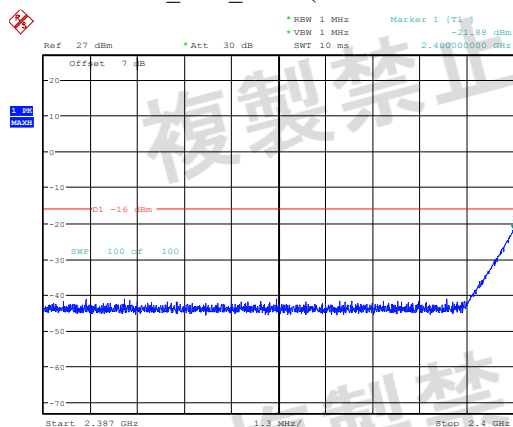
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 03:55:26

8DPSK_Low_3DH1(1GHz~2.387GHz)



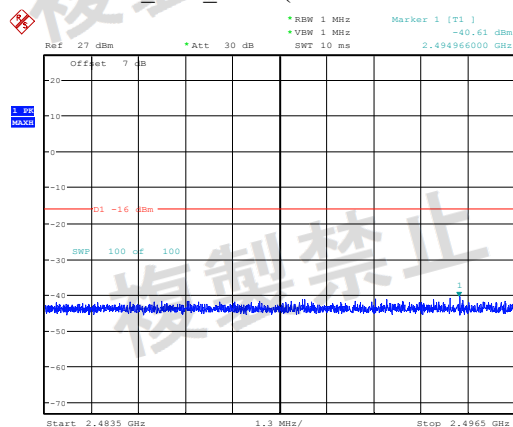
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 03:55:41

8DPSK_Low_3DH1(2.387GHz~2.4GHz)



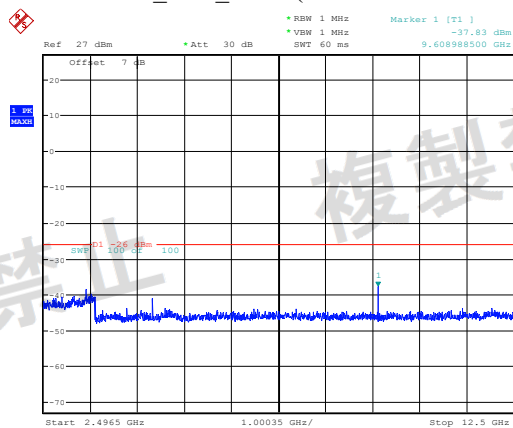
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 03:55:54

8DPSK_Low_3DH1(2.4835GHz~2.4965GHz)



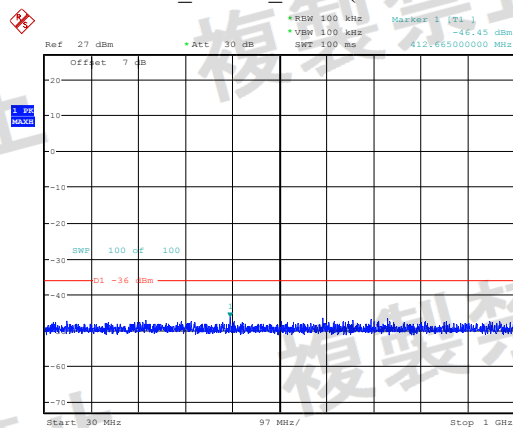
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 03:56:07

8DPSK_Low_3DH1(2.4965GHz~12.5GHz)



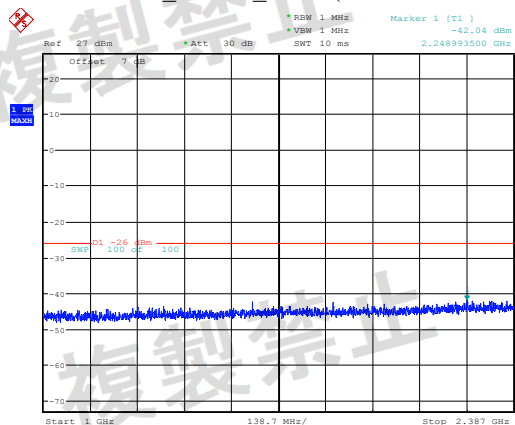
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 03:56:38

8DPSK_Middle_3DH1(30MHz~1GHz)



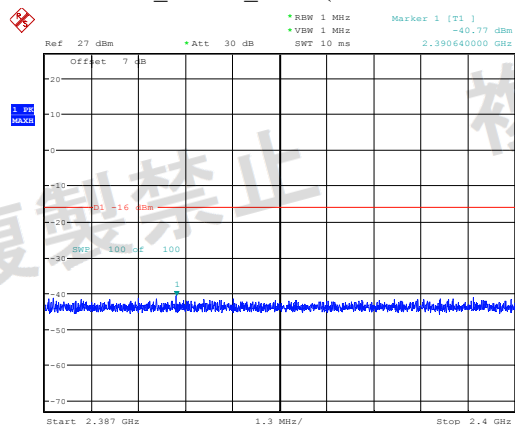
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 03:57:16

8DPSK_Middle_3DH1(1GHz~2.387GHz)



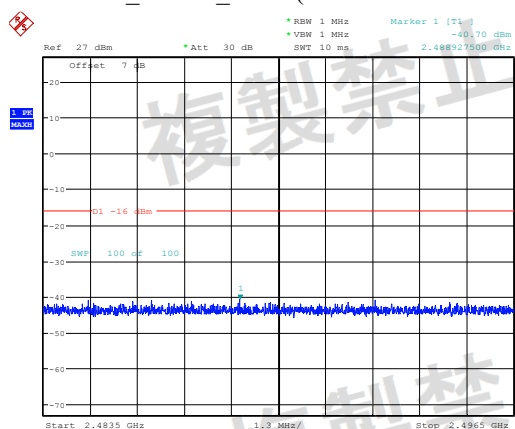
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 03:57:31

8DPSK_Middle_3DH1(2.387GHz~2.4GHz)



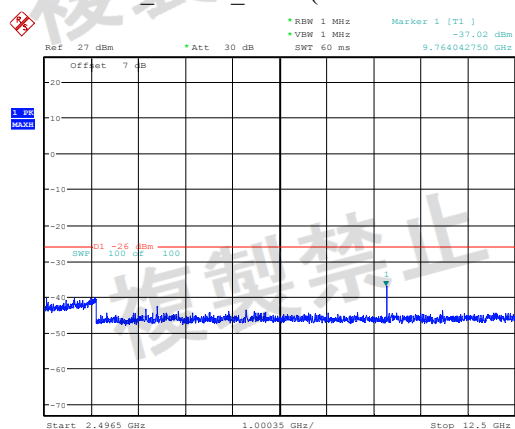
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 03:57:43

8DPSK_Middle_3DH1(2.4835GHz~2.4965GHz)



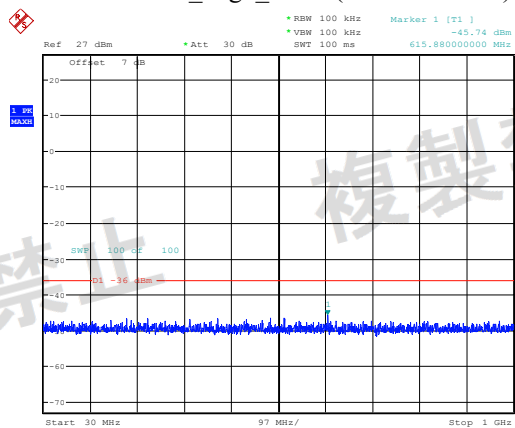
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 03:57:56

8DPSK_Middle_3DH1(2.4965GHz~12.5GHz)



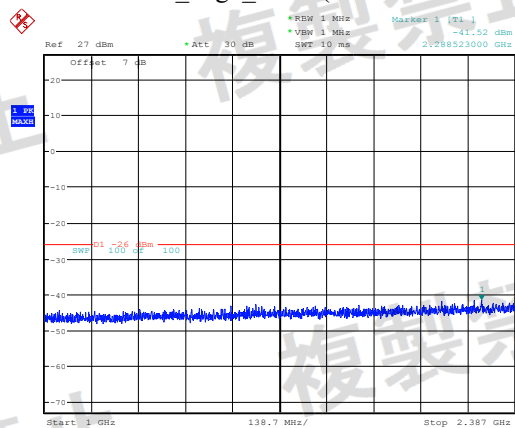
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 03:58:26

8DPSK_High_3DH1(30MHz~1GHz)



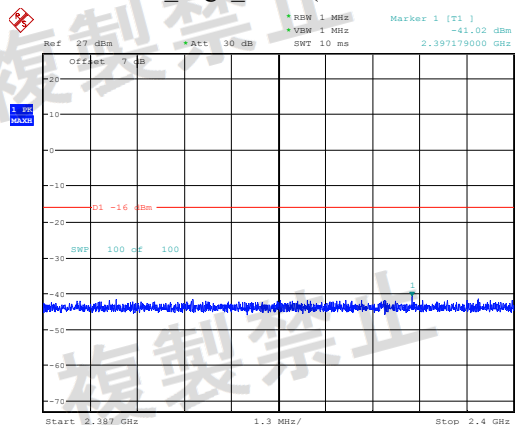
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 04:00:10

8DPSK_High_3DH1(1GHz~2.387GHz)



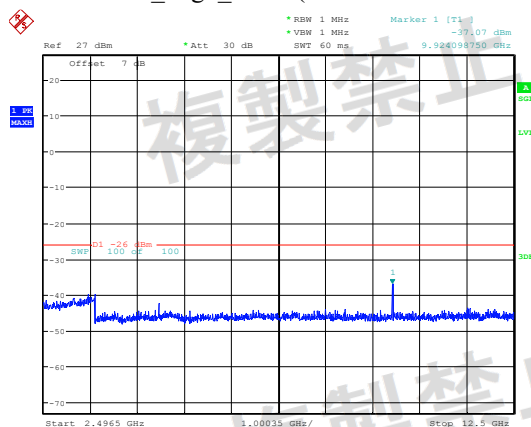
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 04:00:24

8DPSK_High_3DH1(2.387GHz~2.4GHz)



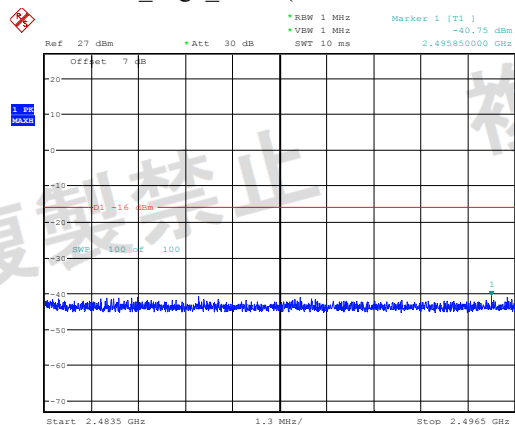
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 04:00:38

8DPSK_High_3DH1(2.4965GHz~12.5GHz)



ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 04:01:21

8DPSK_High_3DH1(2.4835GHz~2.4965GHz)



ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 04:00:51

Receiver Spurious Emission and Unwanted Emission Intensity

Test Condition: HV

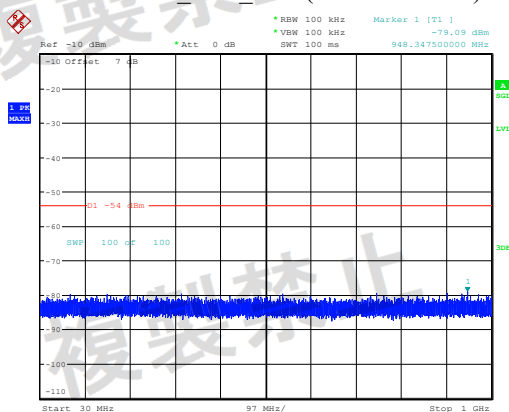
Mode	Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm)	Result (nW)	Limit (nW)	Verdict
			Start(MHz)	Stop(MHz)					
GFSK	Low	Band I (100kHz)	30	1000	948.3475	-79.09	0.012	4	Pass
		Band II (1MHz)	1000	12500	2462.8	-50.25	9.441	20	Pass
	Middle	Band I (100kHz)	30	1000	266.389	-79.27	0.012	4	Pass
		Band II (1MHz)	1000	12500	2459.35	-56.71	2.133	20	Pass
	High	Band I (100kHz)	30	1000	470.9135	-78.71	0.013	4	Pass
		Band II (1MHz)	1000	12500	2461.075	-61.91	0.644	20	Pass
$\pi/4$ -DQPSK	Low	Band I (100kHz)	30	1000	302.376	-79.12	0.012	4	Pass
		Band II (1MHz)	1000	12500	2560.55	-61.55	0.700	20	Pass
	Middle	Band I (100kHz)	30	1000	948.1535	-78.21	0.015	4	Pass
		Band II (1MHz)	1000	12500	5508	-65.17	0.304	20	Pass
	High	Band I (100kHz)	30	1000	534.109	-79.27	0.012	4	Pass
		Band II (1MHz)	1000	12500	2458.2	-64.47	0.357	20	Pass
8DPSK	Low	Band I (100kHz)	30	1000	201.302	-79.54	0.011	4	Pass
		Band II (1MHz)	1000	12500	2580.675	-64.48	0.356	20	Pass
	Middle	Band I (100kHz)	30	1000	948.1535	-79.05	0.012	4	Pass
		Band II (1MHz)	1000	12500	2460.5	-65.56	0.278	20	Pass
	High	Band I (100kHz)	30	1000	290.3965	-79.00	0.013	4	Pass
		Band II (1MHz)	1000	12500	2462.8	-64.01	0.397	20	Pass

Test Condition: LV

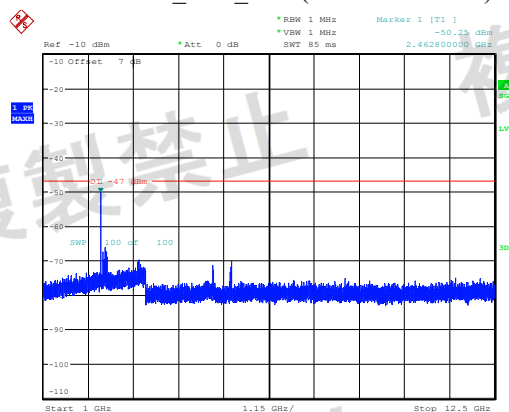
Mode	Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm)	Result (nW)	Limit (nW)	Verdict
			Start(MHz)	Stop(MHz)					
GFSK	Low	Band I (100kHz)	30	1000	167.934	-73.06	0.049	4	Pass
		Band II (1MHz)	1000	12500	2627.25	-61.65	0.684	20	Pass
	Middle	Band I (100kHz)	30	1000	948.3475	-78.33	0.015	4	Pass
		Band II (1MHz)	1000	12500	3516.2	-63.92	0.406	20	Pass
	High	Band I (100kHz)	30	1000	445.9845	-76.02	0.025	4	Pass
		Band II (1MHz)	1000	12500	2461.65	-63.22	0.476	20	Pass
$\pi/4$ -DQPSK	Low	Band I (100kHz)	30	1000	58.227	-79.12	0.012	4	Pass
		Band II (1MHz)	1000	12500	2627.825	-64.69	0.340	20	Pass
	Middle	Band I (100kHz)	30	1000	533.2845	-79.04	0.012	4	Pass
		Band II (1MHz)	1000	12500	3516.2	-61.78	0.664	20	Pass
	High	Band I (100kHz)	30	1000	707.351	-79.16	0.012	4	Pass
		Band II (1MHz)	1000	12500	2461.65	-61.80	0.661	20	Pass
8DPSK	Low	Band I (100kHz)	30	1000	948.396	-78.56	0.014	4	Pass
		Band II (1MHz)	1000	12500	2463.375	-61.59	0.693	20	Pass
	Middle	Band I (100kHz)	30	1000	274.149	-78.99	0.013	4	Pass
		Band II (1MHz)	1000	12500	2460.5	-63.50	0.447	20	Pass
	High	Band I (100kHz)	30	1000	948.3475	-79.05	0.012	4	Pass
		Band II (1MHz)	1000	12500	1736.575	-59.73	1.064	20	Pass

Test Condition: NV

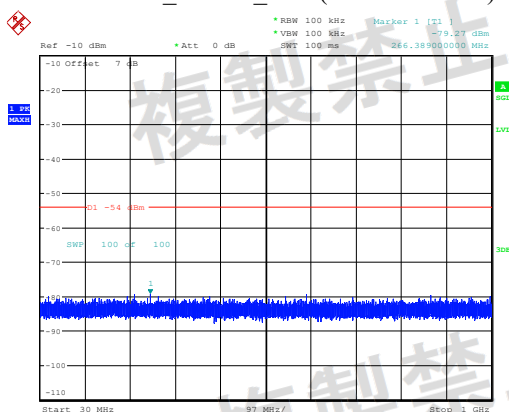
Mode	Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm)	Result (nW)	Limit (nW)	Verdict
			Start(MHz)	Stop(MHz)					
GFSK	Low	Band I (100kHz)	30	1000	464.269	-79.03	0.013	4	Pass
		Band II (1MHz)	1000	12500	1736	-57.83	1.648	20	Pass
	Middle	Band I (100kHz)	30	1000	192.2325	-79.32	0.012	4	Pass
		Band II (1MHz)	1000	12500	5174.5	-63.93	0.405	20	Pass
	High	Band I (100kHz)	30	1000	134.3235	-79.34	0.012	4	Pass
		Band II (1MHz)	1000	12500	2521.45	-63.03	0.498	20	Pass
$\pi/4$ -DQPSK	Low	Band I (100kHz)	30	1000	597.547	-78.72	0.013	4	Pass
		Band II (1MHz)	1000	12500	2623.225	-66.43	0.228	20	Pass
	Middle	Band I (100kHz)	30	1000	446.0815	-62.49	0.564	4	Pass
		Band II (1MHz)	1000	12500	1746.35	-58.74	1.337	20	Pass
	High	Band I (100kHz)	30	1000	942.479	-79.40	0.011	4	Pass
		Band II (1MHz)	1000	12500	2627.825	-66.59	0.219	20	Pass
8DPSK	Low	Band I (100kHz)	30	1000	196.1125	-79.76	0.011	4	Pass
		Band II (1MHz)	1000	12500	2532.375	-66.90	0.204	20	Pass
	Middle	Band I (100kHz)	30	1000	935.0585	-79.06	0.012	4	Pass
		Band II (1MHz)	1000	12500	5759.275	-65.45	0.285	20	Pass
	High	Band I (100kHz)	30	1000	445.9845	-70.82	0.083	4	Pass
		Band II (1MHz)	1000	12500	2461.075	-60.79	0.834	20	Pass

Test Condition: HV**GFSK_Low_DH1(30MHz~1GHz)**

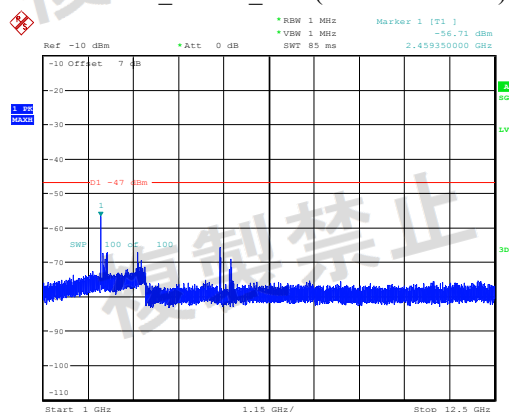
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:51:04

GFSK_Low_DH1(1GHz~12.5GHz)

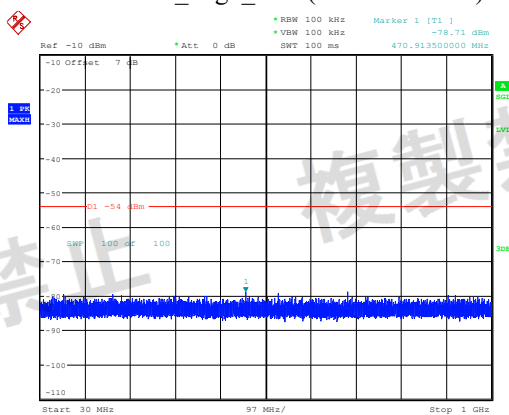
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:51:40

GFSK_Middle_DH1(30MHz~1GHz)

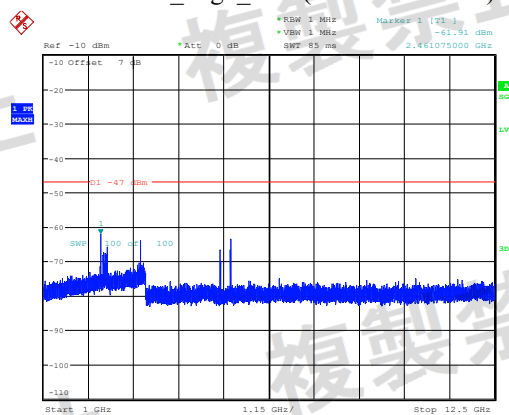
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:52:28

GFSK_Middle_DH1(1GHz~12.5GHz)

ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:53:03

GFSK_High_DH1(30MHz~1GHz)

ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:53:34

GFSK_High_DH1(1GHz~12.5GHz)

ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:54:10

GFSK Low DH1(30MHz~1GHz)



ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:41:39

ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:42:43

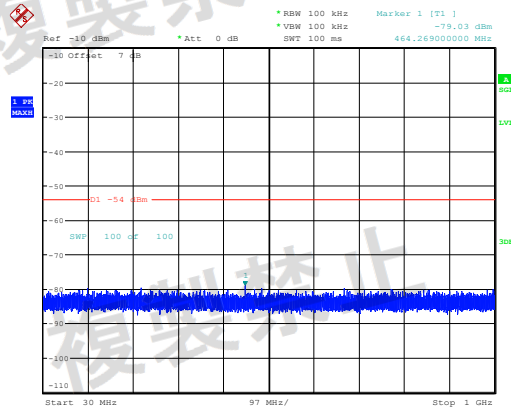
ProjectNo.:2501X79543E-RF Tester:Lee L
Date: 10-OCT-2025 05:41:10

ProjectNo.:2501X79543E-RF Tester:Lee L.
Date: 10.OCT.2025 05:42:14

ProjectNo.:2501X79543E-RF Tester:Lee L.
Date: 10.OCT.2025 05:43:21

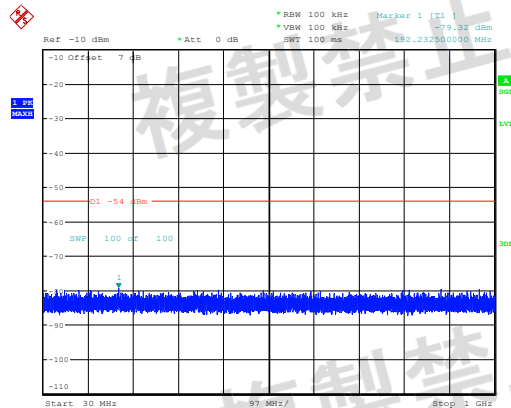
Test Condition: NV

GFSK_Low_DH1(30MHz~1GHz)



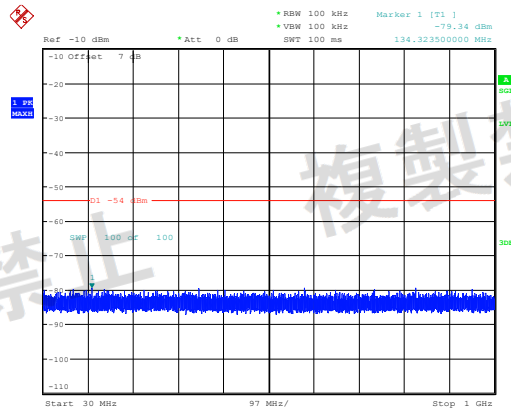
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 04:17:01

GFSK_Middle_DH1(30MHz~1GHz)



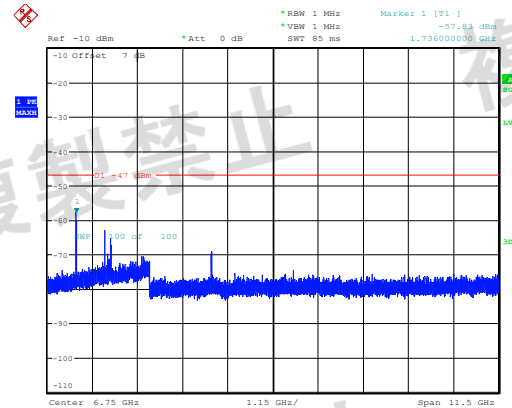
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 04:23:28

GFSK_High_DH1(30MHz~1GHz)



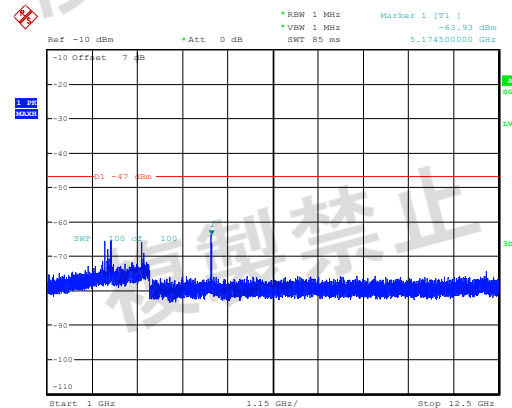
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 04:24:35

GFSK_Low_DH1(1GHz~12.5GHz)



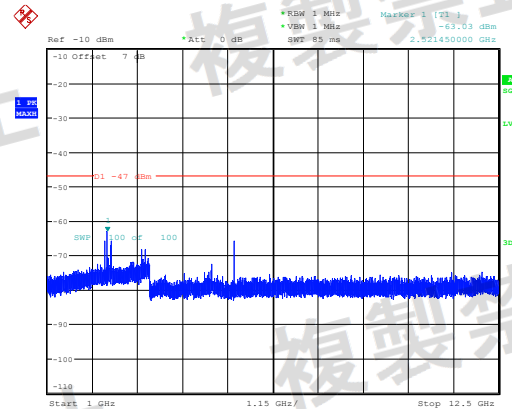
ProjectNo.:2501X79543E-RF Tester:Lee L
Date: 10.OCT.2025 04:22:54

GFSK_Middle_DH1(1GHz~12.5GHz)

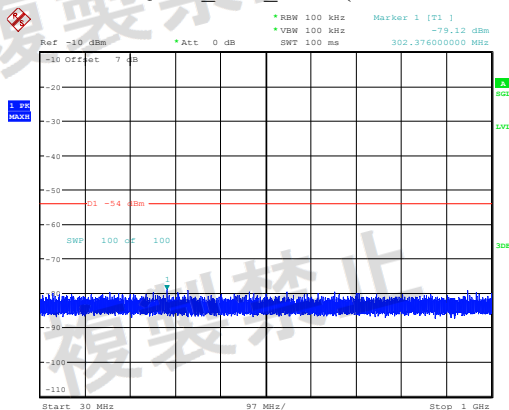


ProjectNo.:2501X79543E-RF Tester:Lee L.
Date: 10.OCT.2025 04:24:04

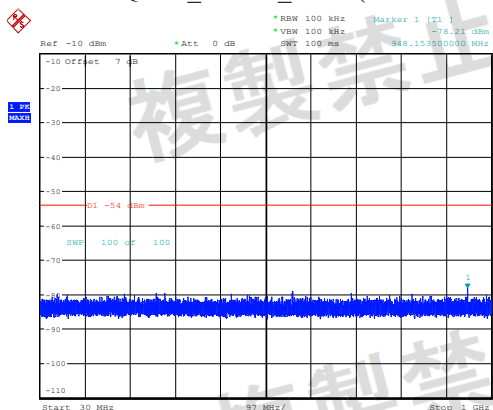
GFSK_High_DH1(1GHz~12.5GHz)



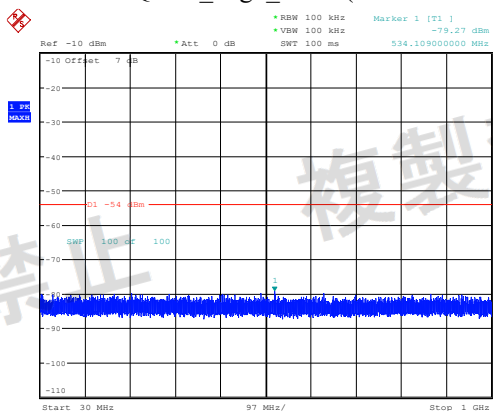
ProjectNo.:2501X79543E-RF Tester:Lee L
Date: 10.OCT.2025 04:25:11

Test Condition: HV $\pi/4$ -DQPSK_Low_2DH1(30MHz~1GHz)

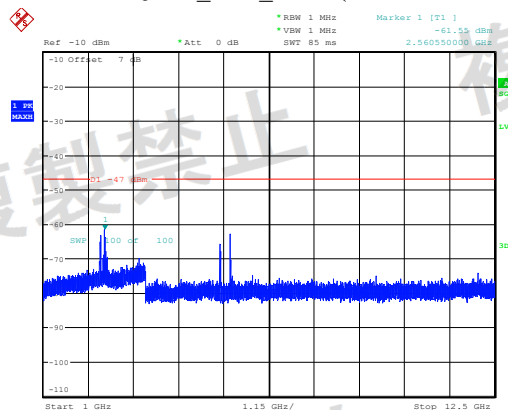
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:54:43

 $\pi/4$ -DQPSK_Middle_2DH1(30MHz~1GHz)

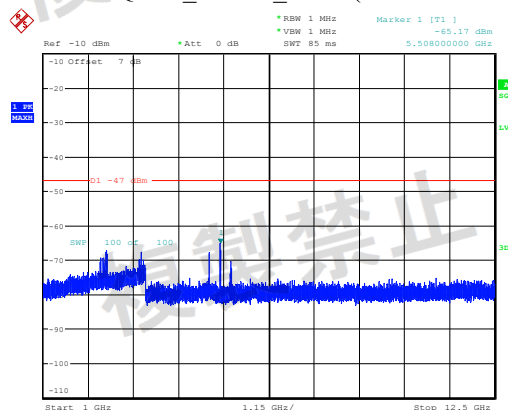
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:55:48

 $\pi/4$ -DQPSK_High_2DH1(30MHz~1GHz)

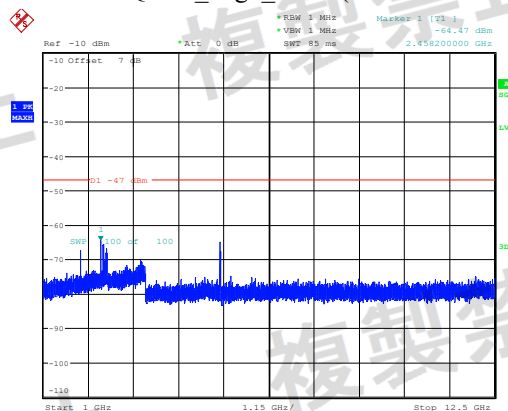
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:56:53

 $\pi/4$ -DQPSK_Low_2DH1(1GHz~12.5GHz)

ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:55:19

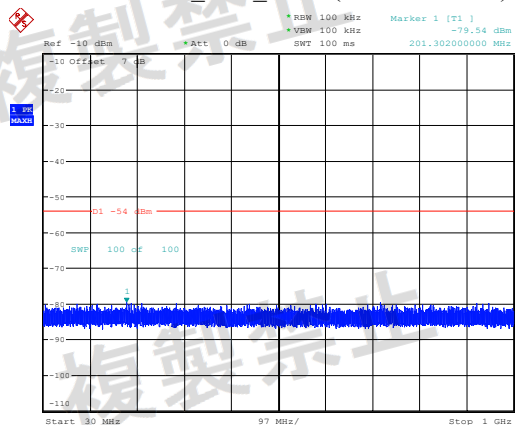
 $\pi/4$ -DQPSK_Middle_2DH1(1GHz~12.5GHz)

ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:56:24

 $\pi/4$ -DQPSK_High_2DH1(1GHz~12.5GHz)

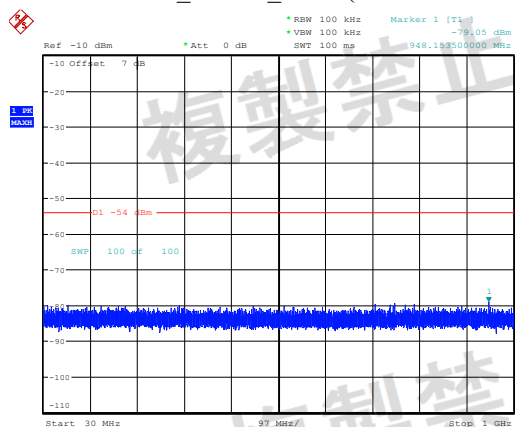
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:57:29

8DPSK_Low_3DH1(30MHz~1GHz)



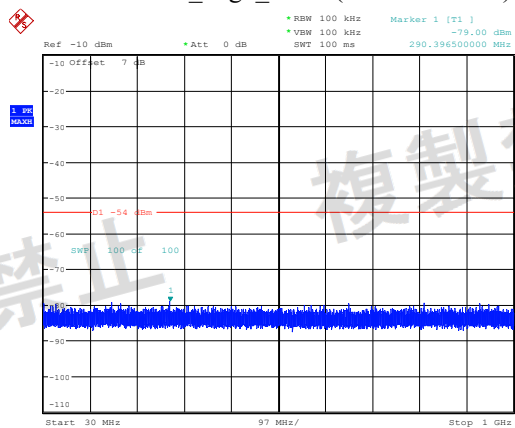
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:57:57

8DPSK_Middle_3DH1(30MHz~1GHz)



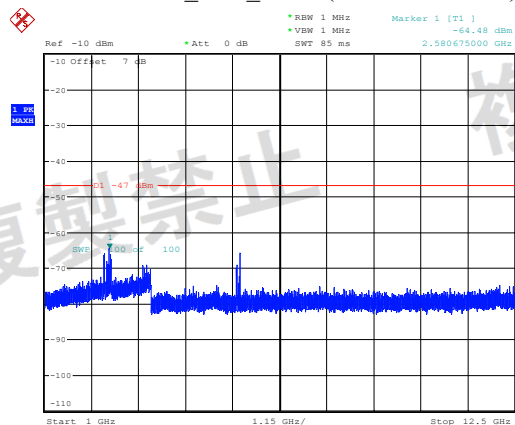
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:59:04

8DPSK_High_3DH1(30MHz~1GHz)



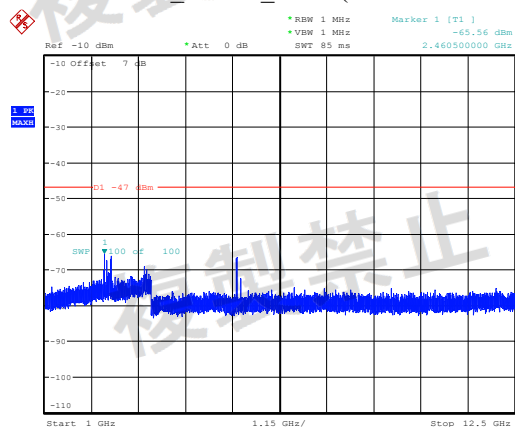
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 06:00:09

8DPSK_Low_3DH1(1GHz~12.5GHz)



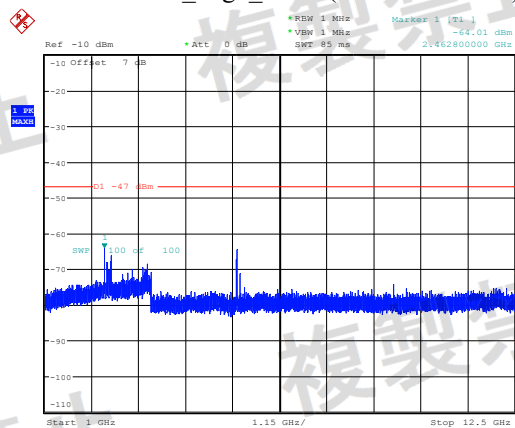
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:58:33

8DPSK_Middle_3DH1(1GHz~12.5GHz)

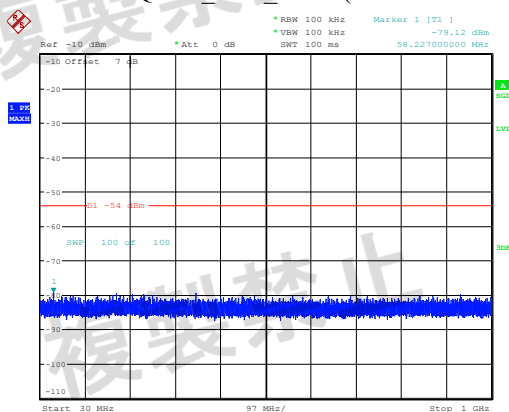


ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:59:40

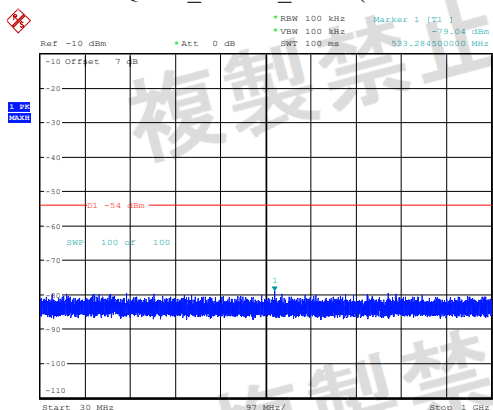
8DPSK_High_3DH1(1GHz~12.5GHz)



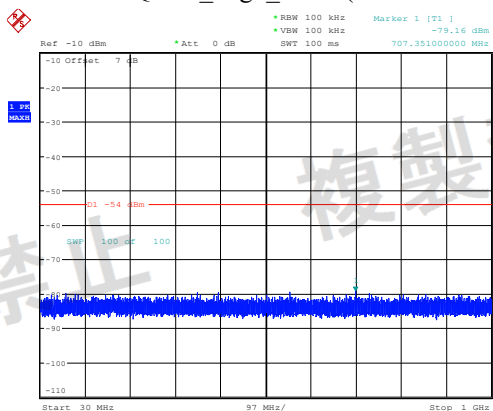
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 06:00:46

Test Condition: LV $\pi/4$ -DQPSK_Low_2DH1(30MHz~1GHz)

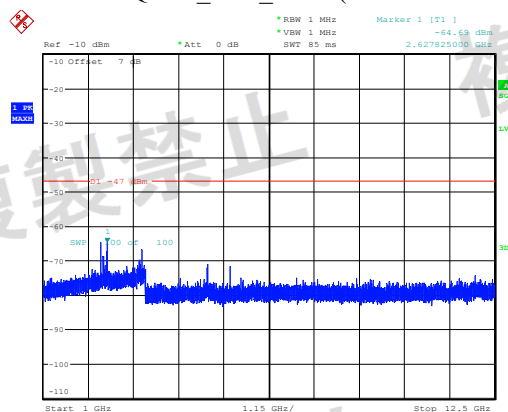
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:43:52

 $\pi/4$ -DQPSK_Middle_2DH1(30MHz~1GHz)

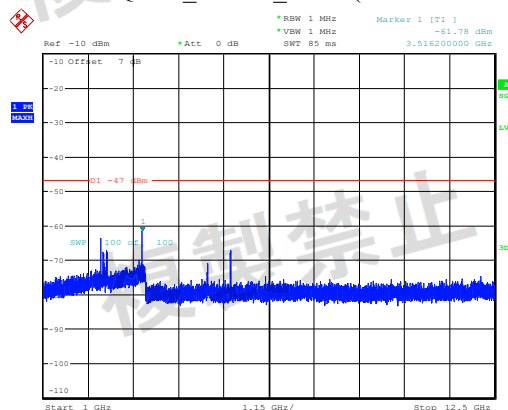
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:44:57

 $\pi/4$ -DQPSK_High_2DH1(30MHz~1GHz)

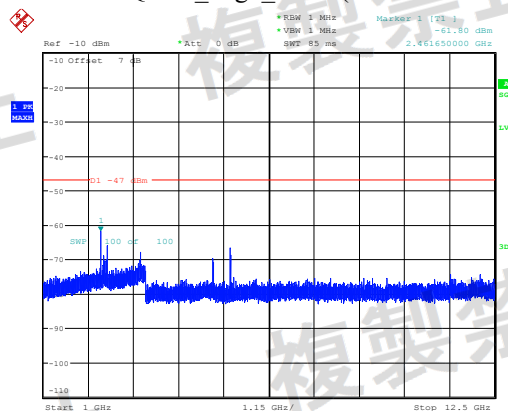
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:46:01

 $\pi/4$ -DQPSK_Low_2DH1(1GHz~12.5GHz)

ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:44:28

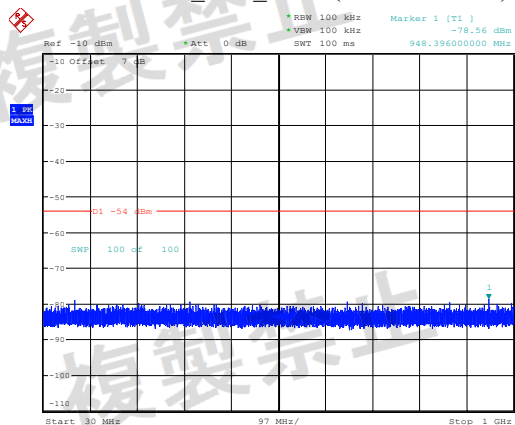
 $\pi/4$ -DQPSK_Middle_2DH1(1GHz~12.5GHz)

ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:45:33

 $\pi/4$ -DQPSK_High_2DH1(1GHz~12.5GHz)

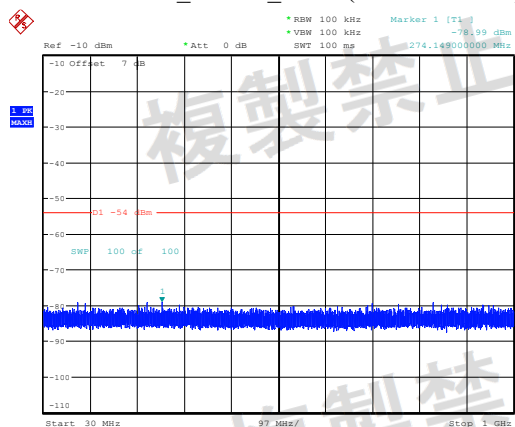
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:46:38

8DPSK_Low_3DH1(30MHz~1GHz)



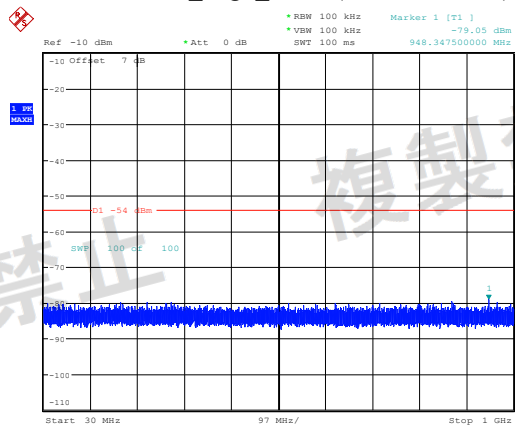
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:47:10

8DPSK_Middle_3DH1(30MHz~1GHz)



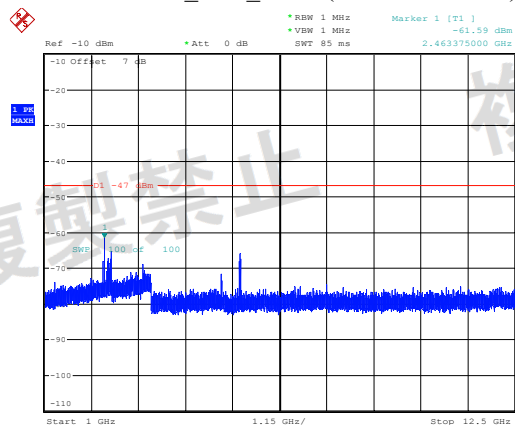
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:48:17

8DPSK_High_3DH1(30MHz~1GHz)



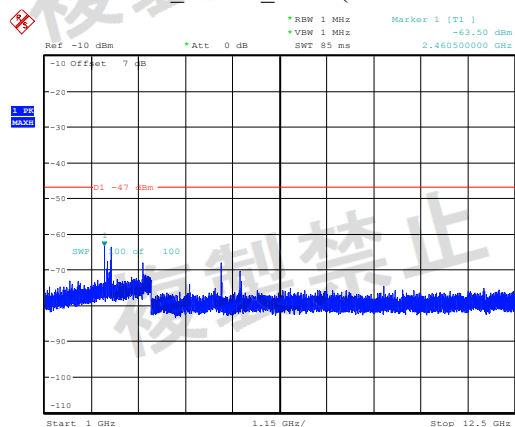
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:49:29

8DPSK_Low_3DH1(1GHz~12.5GHz)



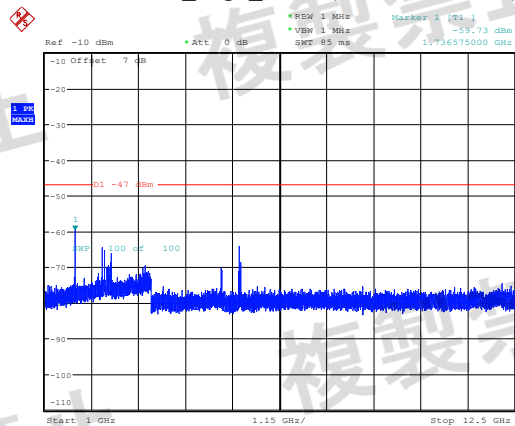
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:47:47

8DPSK_Middle_3DH1(1GHz~12.5GHz)



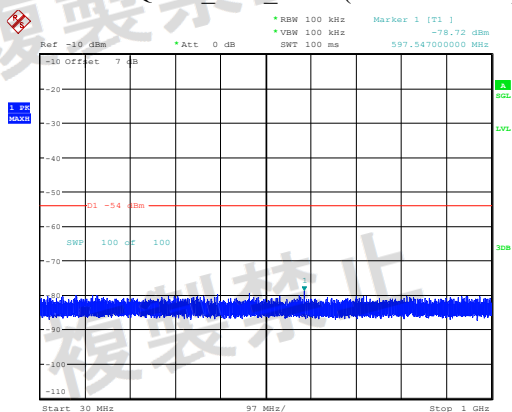
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:48:54

8DPSK_High_3DH1(1GHz~12.5GHz)

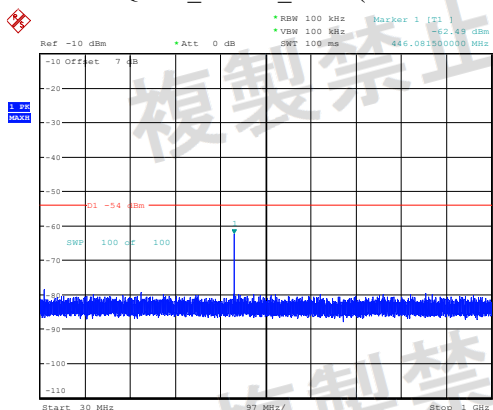


ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 05:50:05

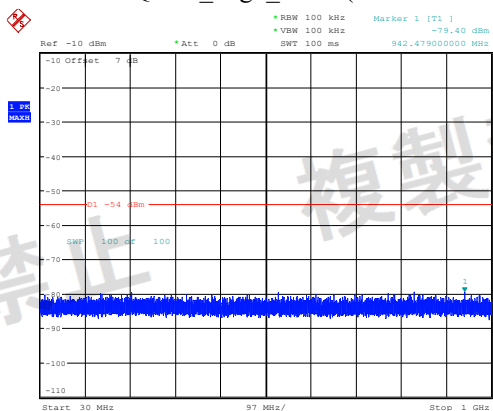
Test Condition: NV

 $\pi/4$ -DQPSK_Low_2DH1(30MHz~1GHz)

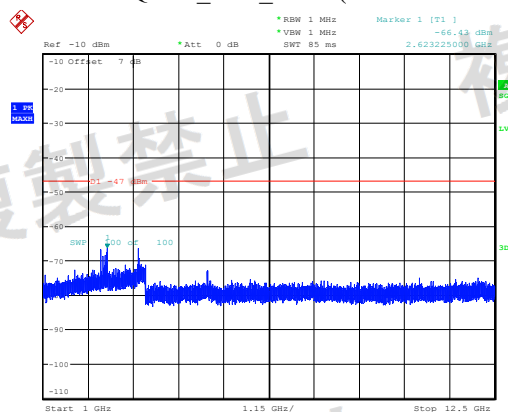
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 04:25:42

 $\pi/4$ -DQPSK_Middle_2DH1(30MHz~1GHz)

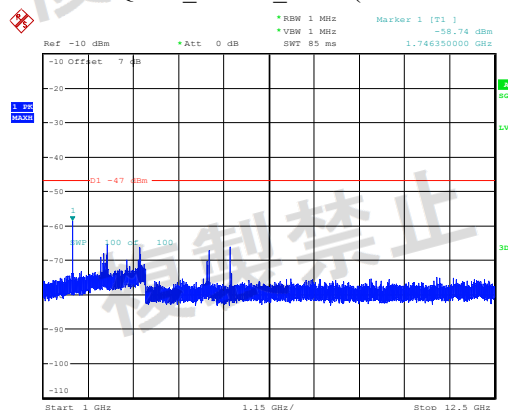
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 04:26:51

 $\pi/4$ -DQPSK_High_2DH1(30MHz~1GHz)

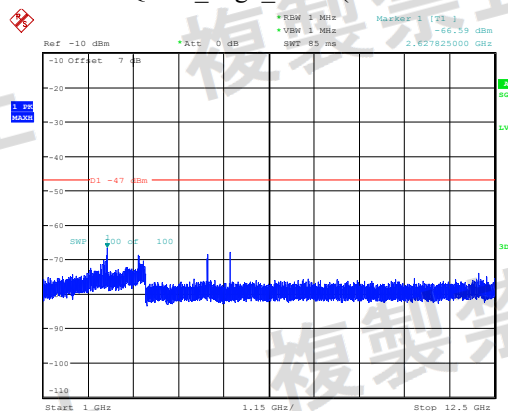
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 04:28:14

 $\pi/4$ -DQPSK_Low_2DH1(1GHz~12.5GHz)

ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 04:26:19

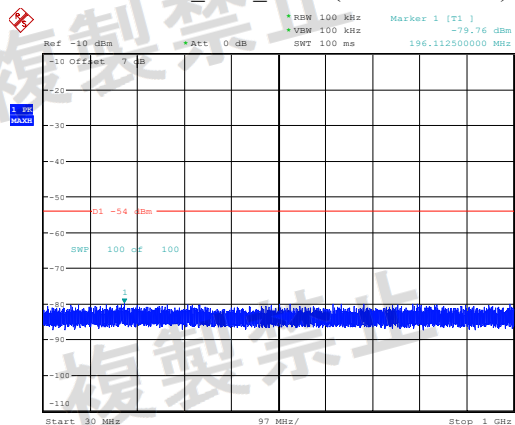
 $\pi/4$ -DQPSK_Middle_2DH1(1GHz~12.5GHz)

ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 04:27:27

 $\pi/4$ -DQPSK_High_2DH1(1GHz~12.5GHz)

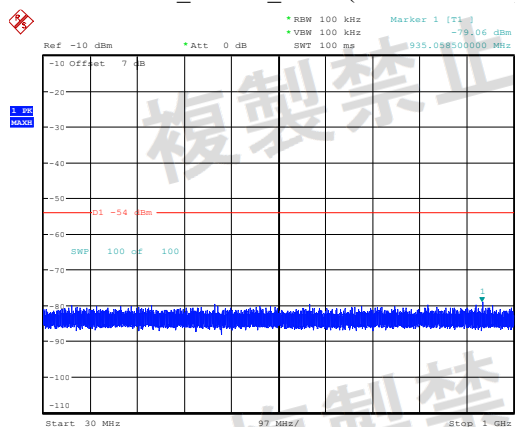
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 04:28:51

8DPSK_Low_3DH1(30MHz~1GHz)



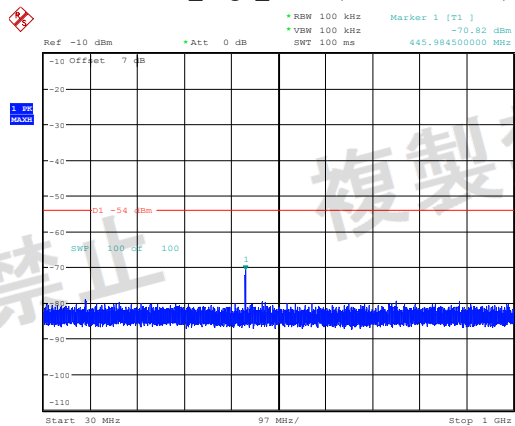
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 04:29:19

8DPSK_Middle_3DH1(30MHz~1GHz)



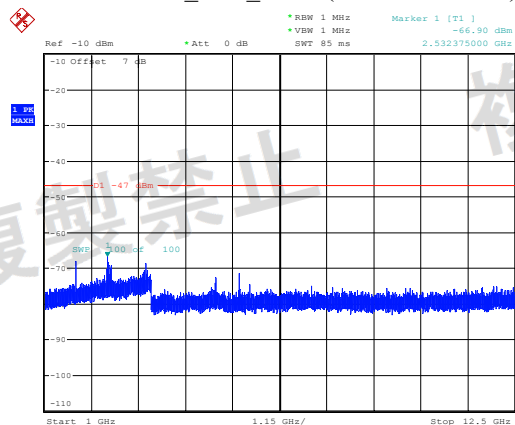
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 04:30:24

8DPSK_High_3DH1(30MHz~1GHz)



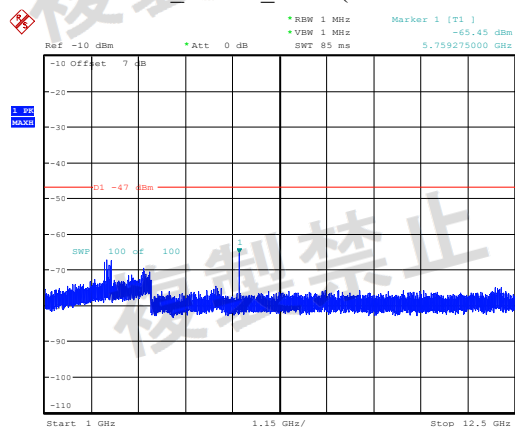
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 04:32:13

8DPSK_Low_3DH1(1GHz~12.5GHz)



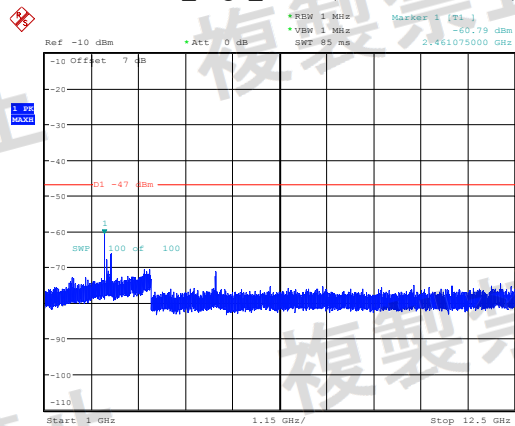
ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 04:29:55

8DPSK_Middle_3DH1(1GHz~12.5GHz)



ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 04:31:01

8DPSK_High_3DH1(1GHz~12.5GHz)



ProjectNo.:2501X79543E-RF Tester:Lee Li
Date: 10.OCT.2025 04:32:49

Frequency Hopping Dwell Time

Test Condition: HV

Mode	Packet Type	Spreading bandwidth	Ton (ms)	Observed Period(s)	Hopping Number In Observed Period	Result (s)	Limit(s)	Verdict
GFSK	DH1	70.60	0.392	28.24	191	0.075	≤ 0.4	Pass
	DH3	70.80	1.649	28.32	113	0.186		Pass
	DH5	70.80	2.908	28.32	83	0.241		Pass
$\pi/4$ -DQPSK	2DH1	71.00	0.402	28.40	182	0.073		Pass
	2DH3	71.00	1.658	28.40	115	0.191		Pass
	2DH5	70.80	2.913	28.32	89	0.259		Pass
8DPSK	3DH1	71.00	0.402	28.40	192	0.077		Pass
	3DH3	70.80	1.655	28.32	114	0.189		Pass
	3DH5	70.80	2.908	28.32	81	0.236		Pass

Test Condition: LV

Mode	Packet Type	Spreading bandwidth	Ton (ms)	Observed Period(s)	Hopping Number In Observed Period	Result (s)	Limit(s)	Verdict
GFSK	DH1	70.40	0.392	28.16	193	0.076	≤ 0.4	Pass
	DH3	70.80	1.649	28.32	110	0.181		Pass
	DH5	70.80	2.908	28.32	78	0.227		Pass
$\pi/4$ -DQPSK	2DH1	71.00	0.402	28.40	201	0.081		Pass
	2DH3	71.20	1.652	28.48	122	0.202		Pass
	2DH5	71.00	2.913	28.40	81	0.236		Pass
8DPSK	3DH1	71.20	0.402	28.48	185	0.074		Pass
	3DH3	70.60	1.655	28.24	118	0.195		Pass
	3DH5	71.40	2.913	28.56	89	0.259		Pass

Test Condition: NV

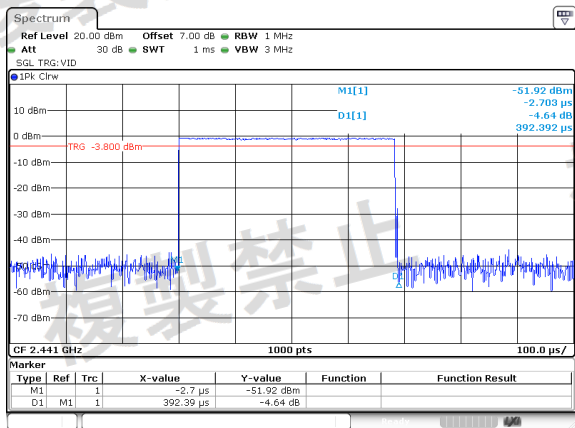
Mode	Packet Type	Spreading bandwidth	Ton (ms)	Observed Period(s)	Hopping Number In Observed Period	Result (s)	Limit(s)	Verdict
GFSK	DH1	70.40	0.392	28.16	210	0.082	≤ 0.4	Pass
	DH3	70.60	1.646	28.24	114	0.188		Pass
	DH5	70.60	2.903	28.24	84	0.244		Pass
$\pi/4$ -DQPSK	2DH1	70.80	0.402	28.32	212	0.085		Pass
	2DH3	71.00	1.658	28.40	116	0.192		Pass
	2DH5	70.80	2.913	28.32	94	0.274		Pass
8DPSK	3DH1	71.00	0.402	28.40	222	0.089		Pass
	3DH3	70.80	1.655	28.32	122	0.202		Pass
	3DH5	71.00	2.913	28.40	85	0.248		Pass

Note:

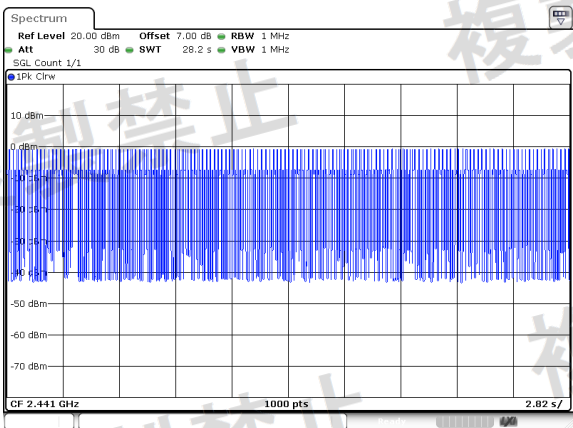
1. Dwell time = Time per one hopping (Ton) * hopping number (within the time obtained by multiplying the spread rate by 0.4s).
2. The Spread Bandwidth please refer to Occupied Bandwidth and Spreading Bandwidth.
3. Ton refer to the Duty Cycle.

Test Condition: HV

GFSK_Hopping_DH1

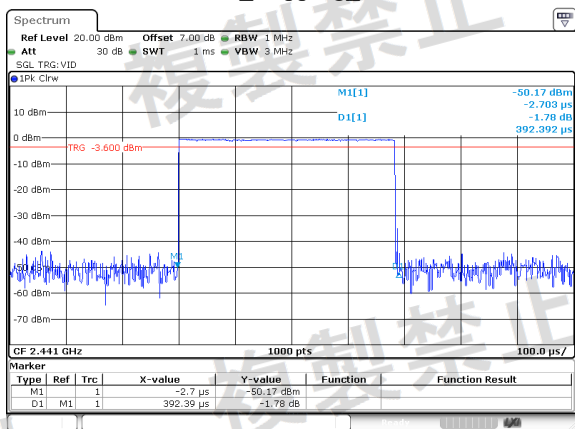


GFSK_Hopping_DH1

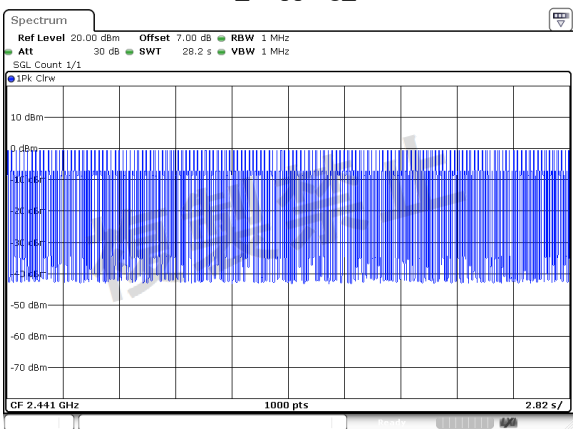


Test Condition: LV

GFSK_Hopping_DH1

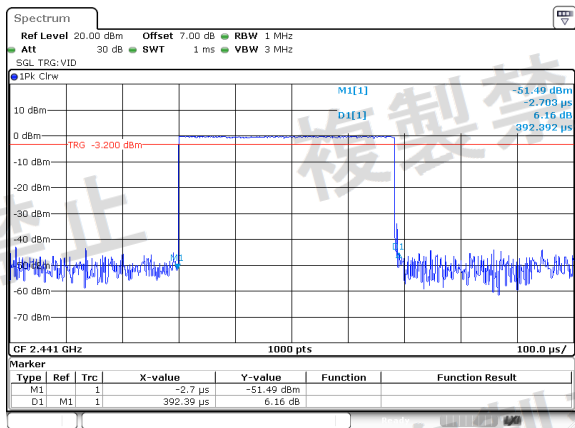


GFSK_Hopping_DH1

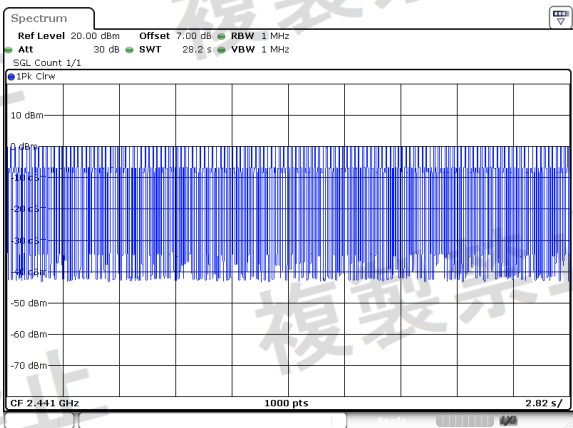


Test Condition: NV

GFSK_Hopping_DH1

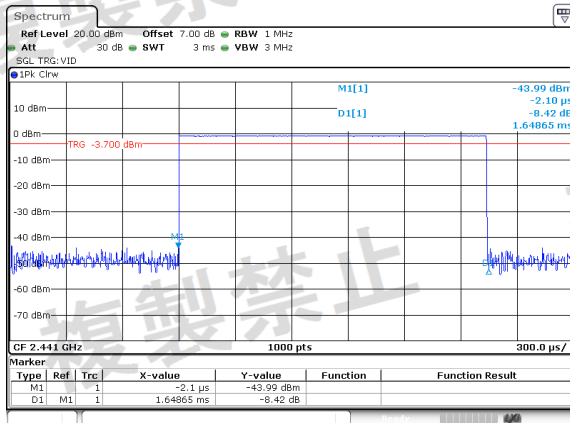


GFSK_Hopping_DH1



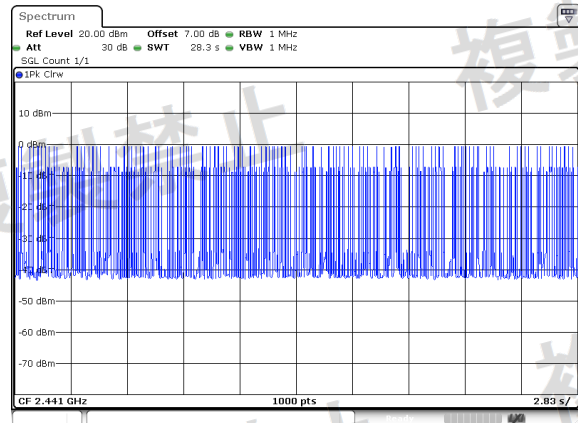
Test Condition: HV

GFSK_Hopping_DH3



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 18:34:11

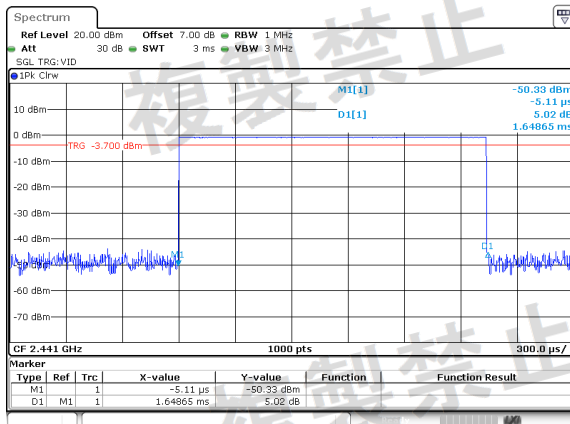
GFSK_Hopping_DH3



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 18:34:45

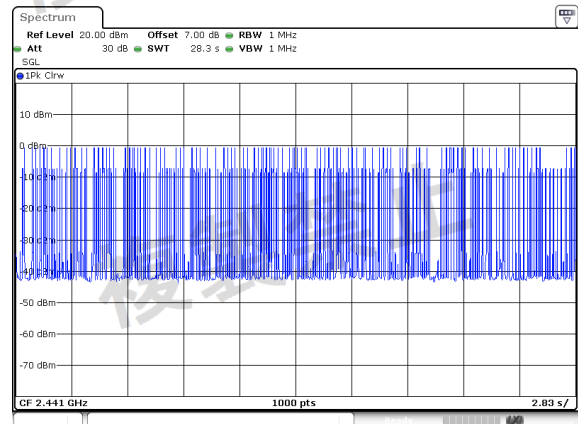
Test Condition: LV

GFSK_Hopping_DH3



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 17:44:21

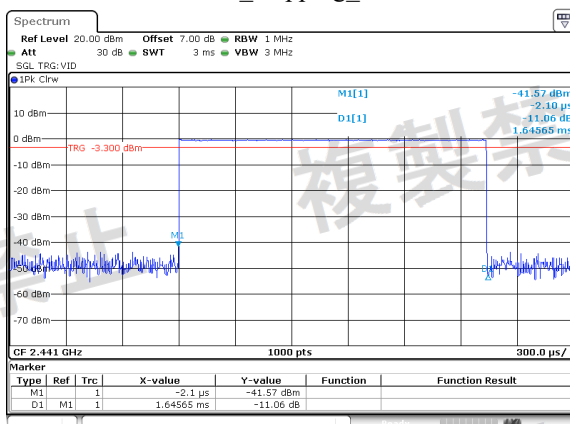
GFSK_Hopping_DH3



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 25.NOV.2025 16:27:54

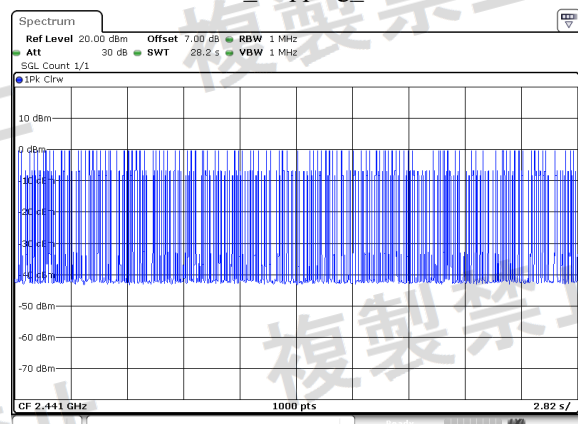
Test Condition: NV

GFSK_Hopping_DH3



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 5.NOV.2025 16:53:49

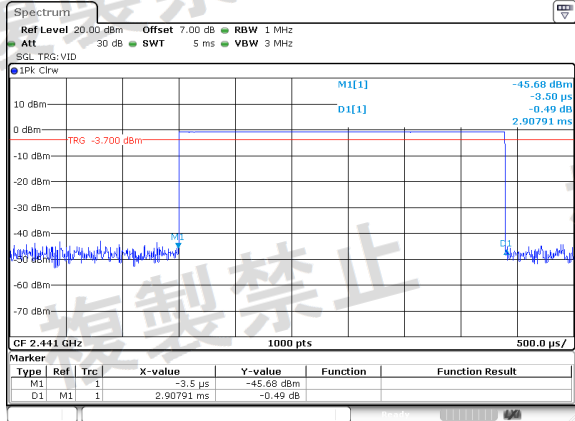
GFSK_Hopping_DH3



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 5.NOV.2025 16:54:23

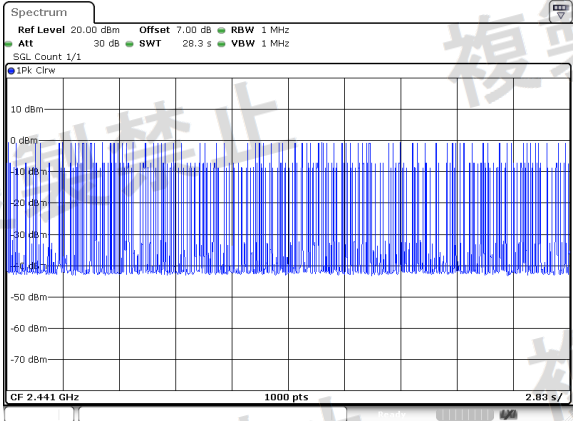
Test Condition: HV

GFSK_Hopping_DH5



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 18:35:31

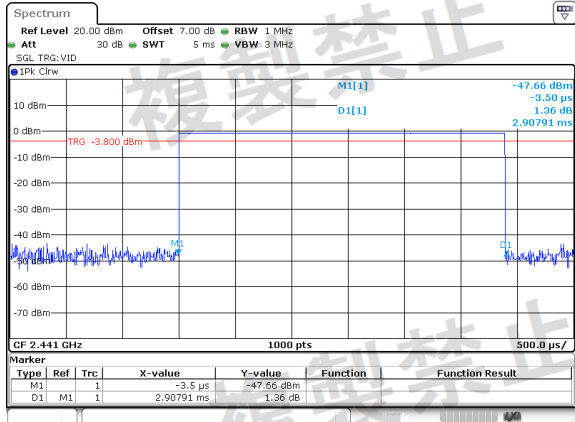
GFSK_Hopping_DH5



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 18:36:05

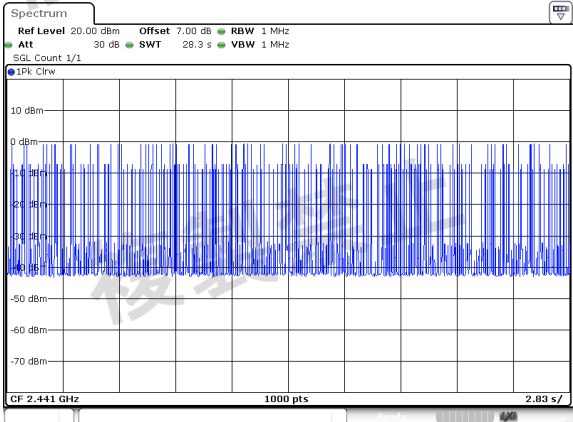
Test Condition: LV

GFSK_Hopping_DH5



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 17:45:50

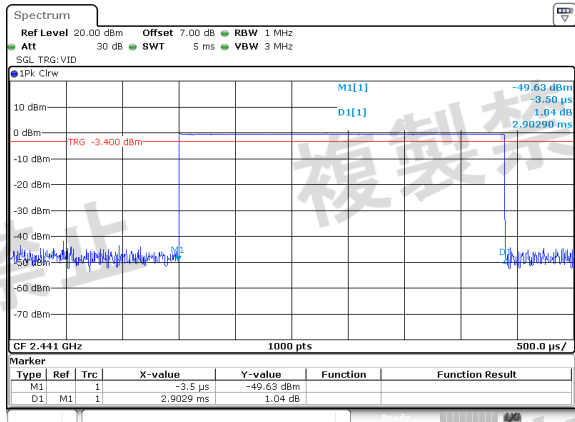
GFSK_Hopping_DH5



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 17:46:24

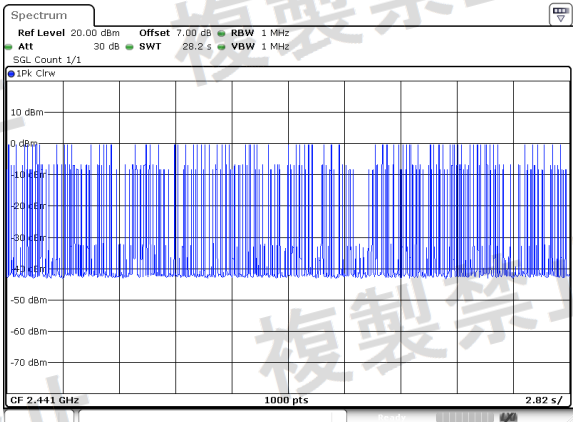
Test Condition: NV

GFSK_Hopping_DH5



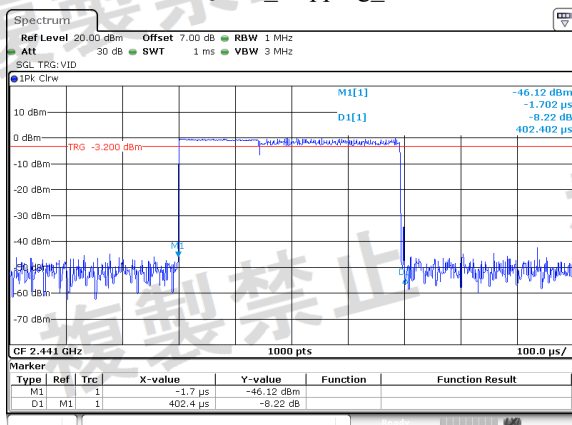
ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 5.NOV.2025 16:55:11

GFSK_Hopping_DH5

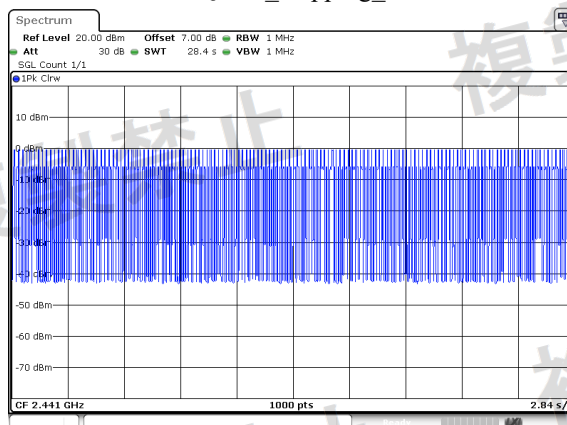


ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 5.NOV.2025 16:55:45

Test Condition: HV

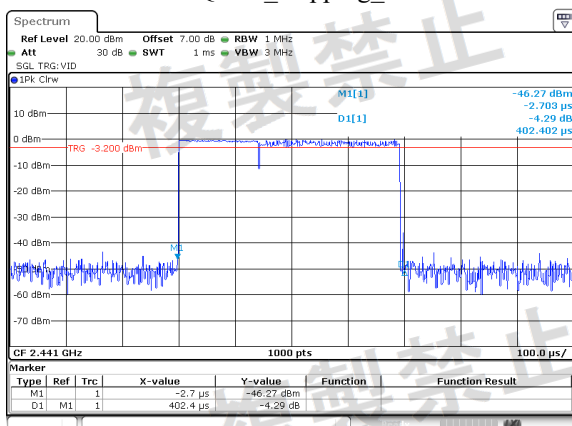
 $\pi/4$ -DQPSK_Hopping_2DH1

ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 18:47:39

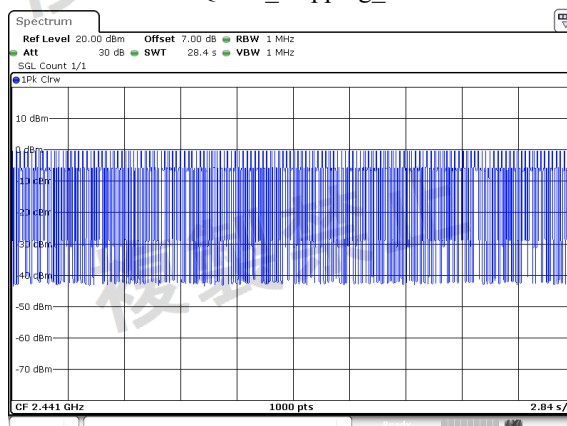
 $\pi/4$ -DQPSK_Hopping_2DH1

ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 18:48:13

Test Condition: LV

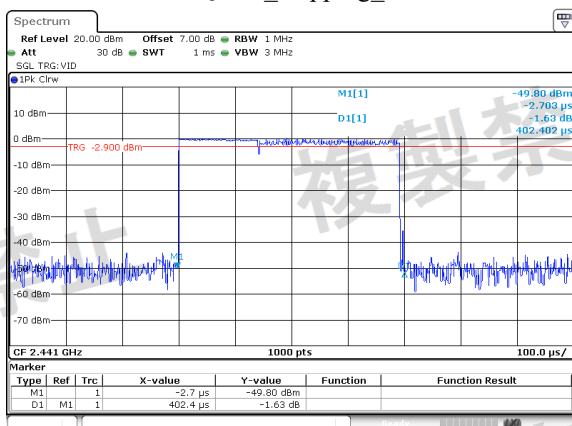
 $\pi/4$ -DQPSK_Hopping_2DH1

ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 17:48:18

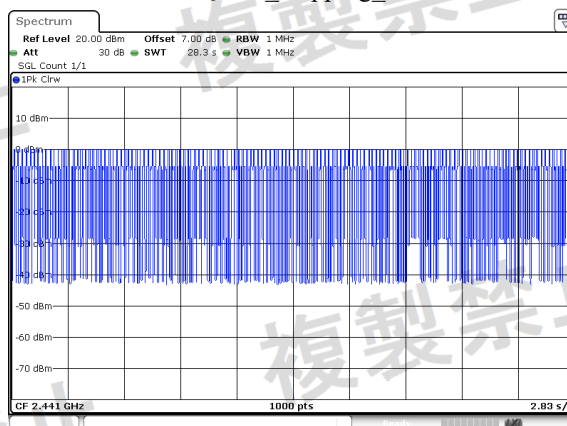
 $\pi/4$ -DQPSK_Hopping_2DH1

ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 17:48:52

Test Condition: NV

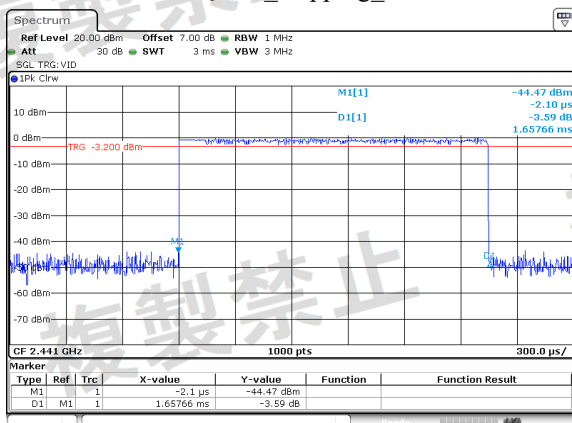
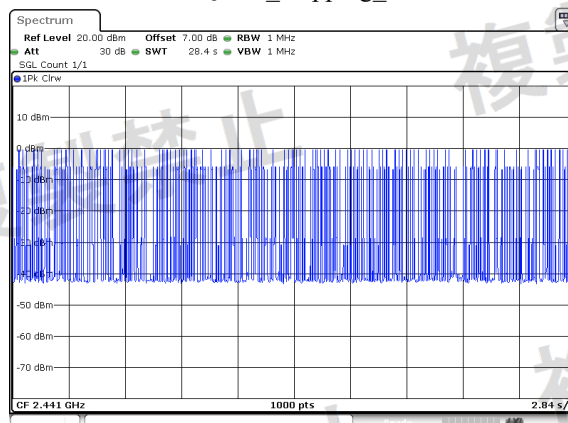
 $\pi/4$ -DQPSK_Hopping_2DH1

ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 5.NOV.2025 16:56:30

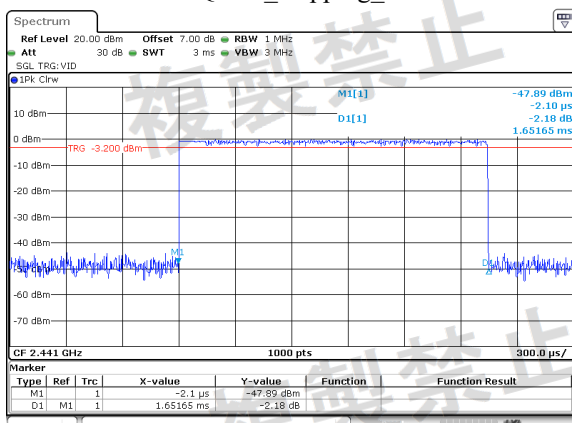
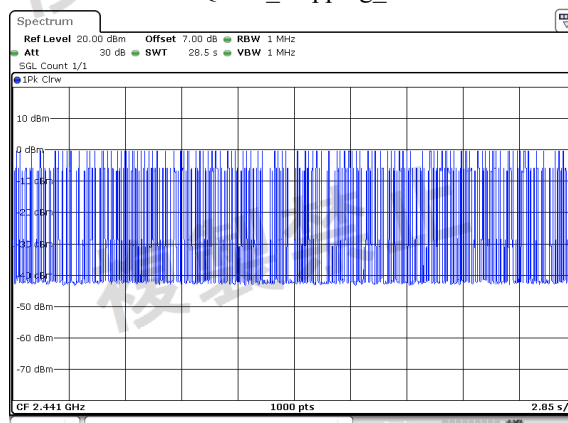
 $\pi/4$ -DQPSK_Hopping_2DH1

ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 5.NOV.2025 16:57:04

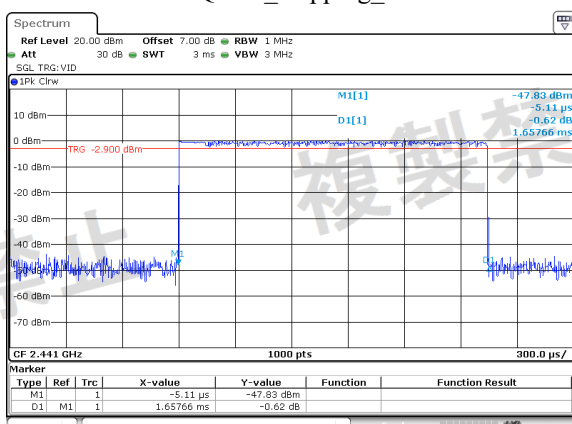
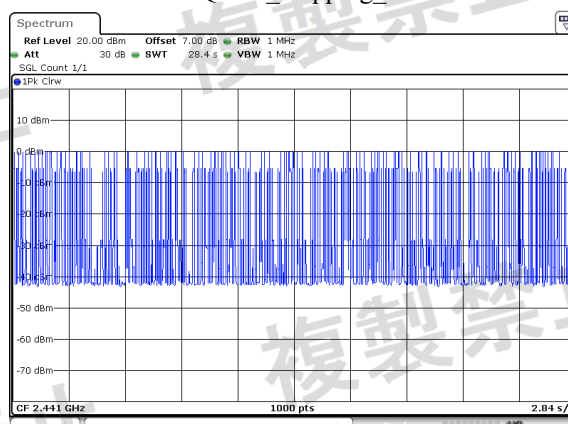
Test Condition: HV

 $\pi/4$ -DQPSK_Hopping_2DH3ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 18:40:24 $\pi/4$ -DQPSK_Hopping_2DH3ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 18:48:59

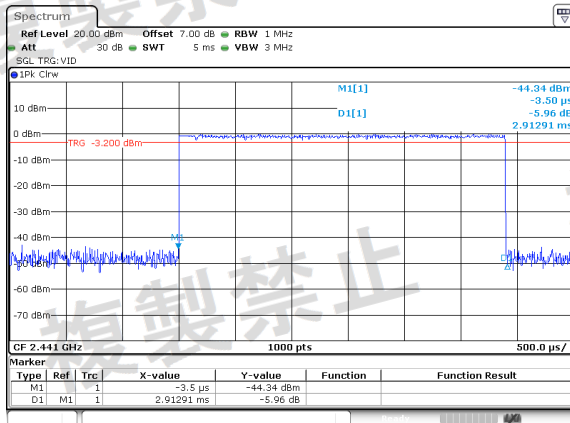
Test Condition: LV

 $\pi/4$ -DQPSK_Hopping_2DH3ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 17:49:33 $\pi/4$ -DQPSK_Hopping_2DH3ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 17:50:07

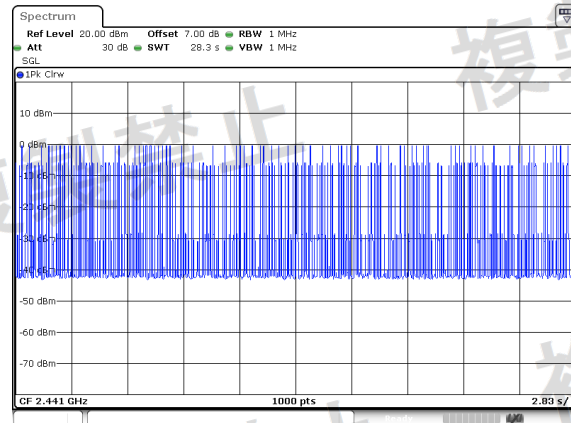
Test Condition: NV

 $\pi/4$ -DQPSK_Hopping_2DH3ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 5.NOV.2025 16:57:56 $\pi/4$ -DQPSK_Hopping_2DH3ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 5.NOV.2025 16:59:30

Test Condition: HV

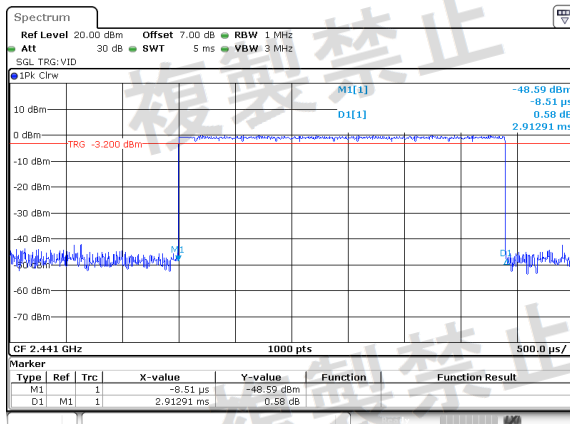
 $\pi/4$ -DQPSK_Hopping_2DH5

ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 18:41:47

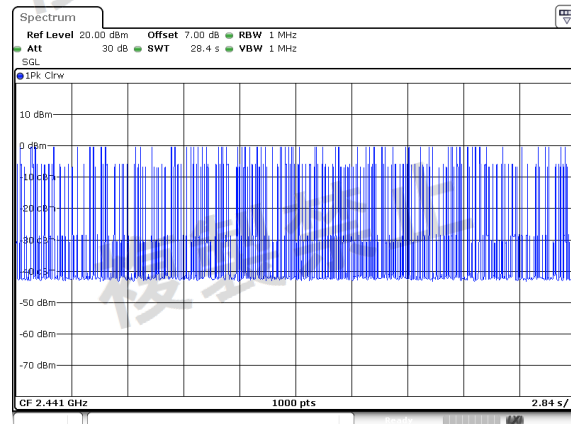
 $\pi/4$ -DQPSK_Hopping_2DH5

ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 25.NOV.2025 16:28:28

Test Condition: LV

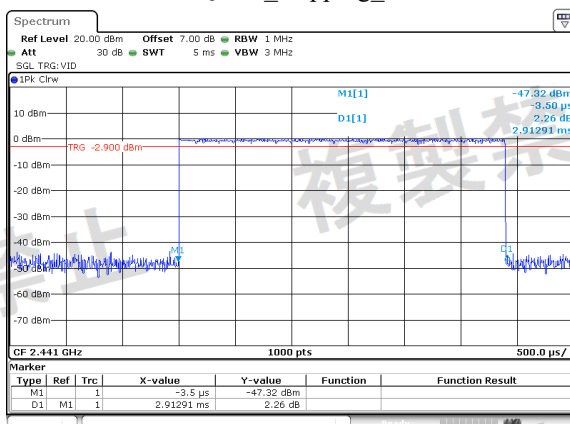
 $\pi/4$ -DQPSK_Hopping_2DH5

ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 17:50:52

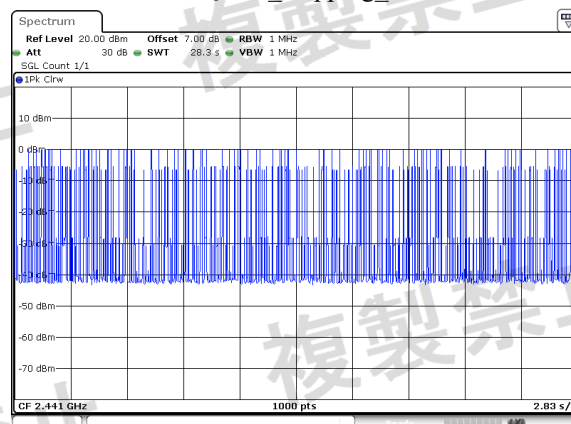
 $\pi/4$ -DQPSK_Hopping_2DH5

ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 25.NOV.2025 16:30:21

Test Condition: NV

 $\pi/4$ -DQPSK_Hopping_2DH5

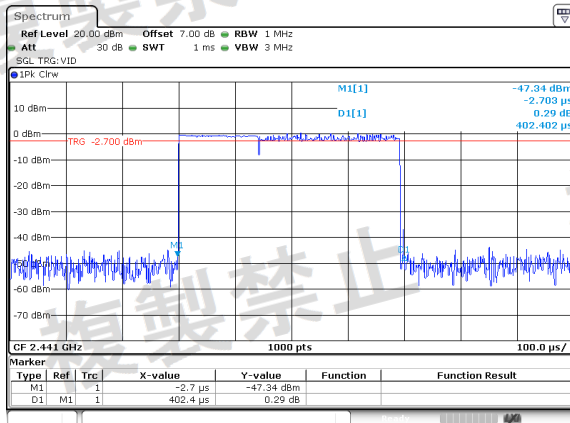
ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 5.NOV.2025 16:59:15

 $\pi/4$ -DQPSK_Hopping_2DH5

ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 5.NOV.2025 16:59:50

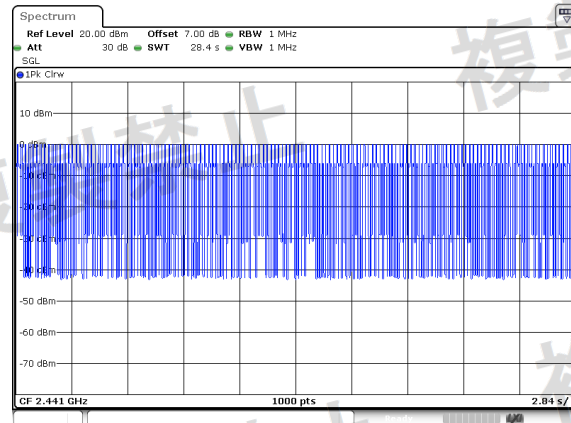
Test Condition: HV

8DPSK_Hopping_3DH1



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 18:42:56

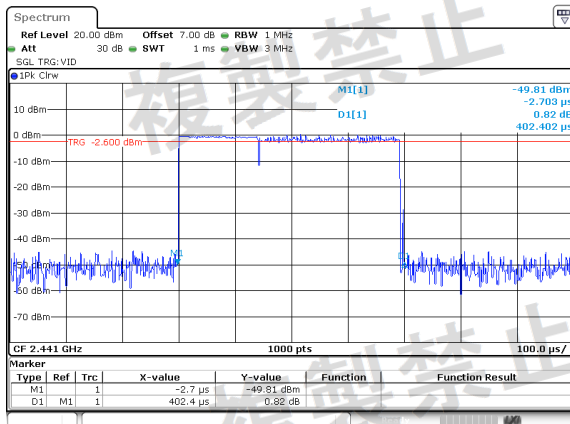
8DPSK_Hopping_3DH1



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 29.NOV.2025 16:38:15

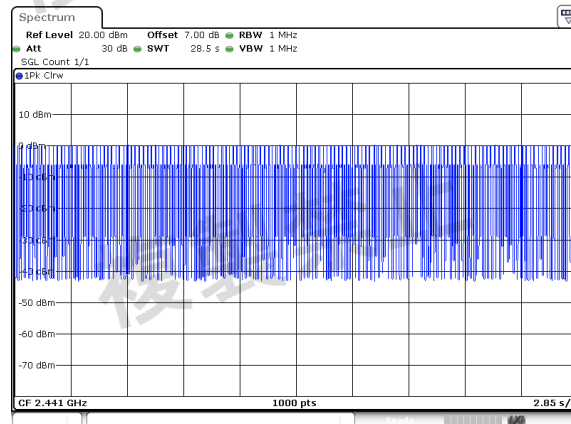
Test Condition: LV

8DPSK_Hopping_3DH1



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 17:52:05

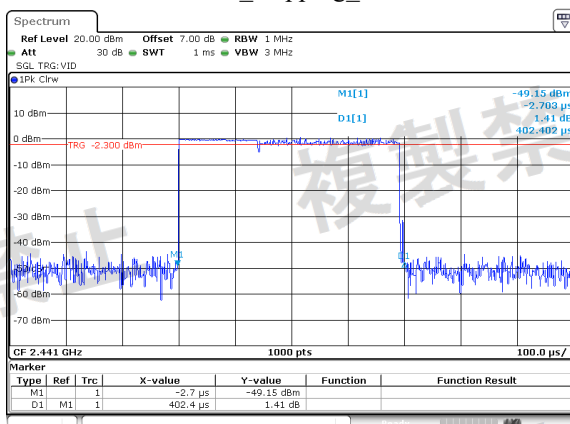
8DPSK_Hopping_3DH1



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 17:52:39

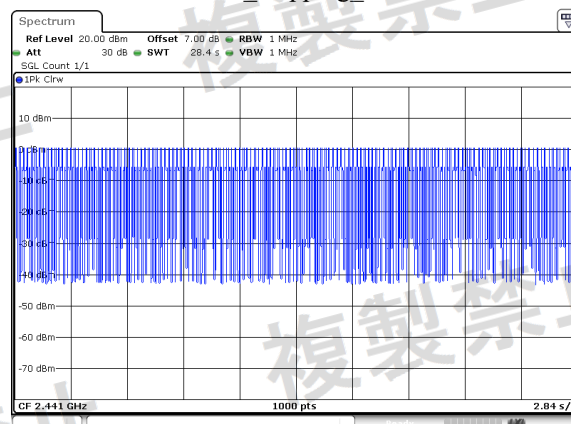
Test Condition: NV

8DPSK_Hopping_3DH1



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 5.NOV.2025 17:00:50

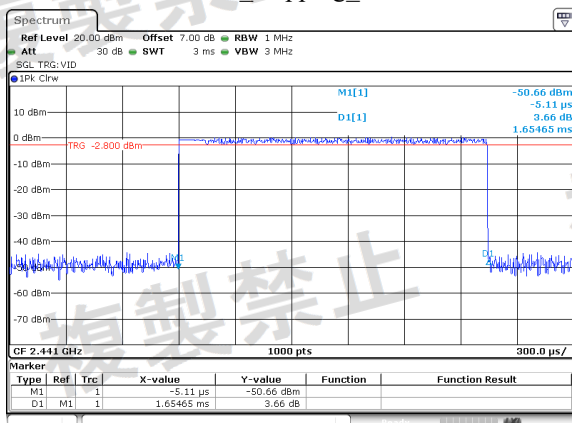
8DPSK_Hopping_3DH1



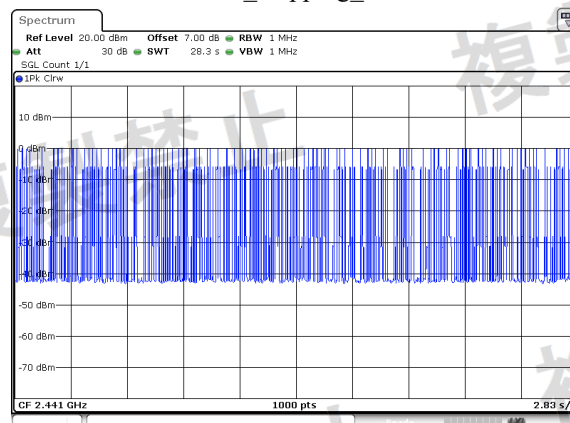
ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 5.NOV.2025 17:01:24

Test Condition: HV

8DPSK_Hopping_3DH3

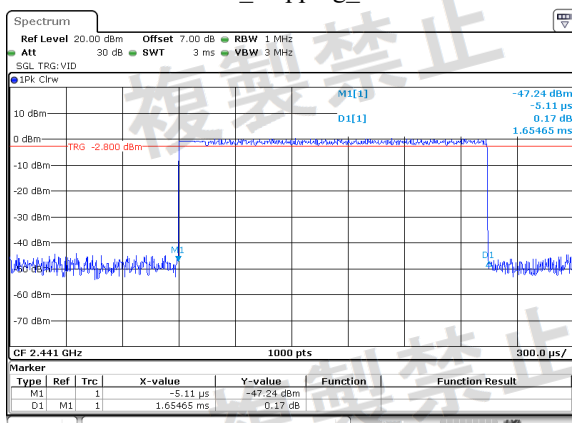
ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 18:44:14

8DPSK_Hopping_3DH3

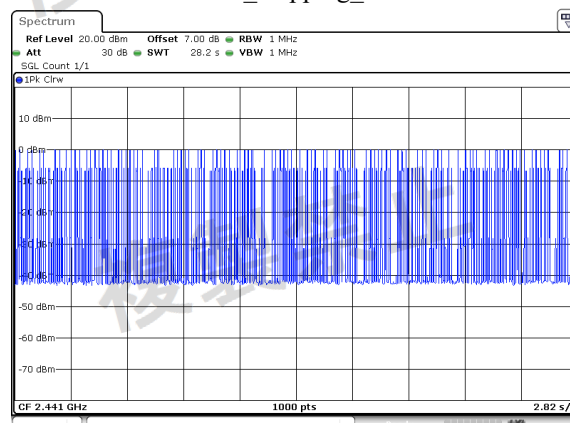
ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 18:44:48

Test Condition: LV

8DPSK_Hopping_3DH3

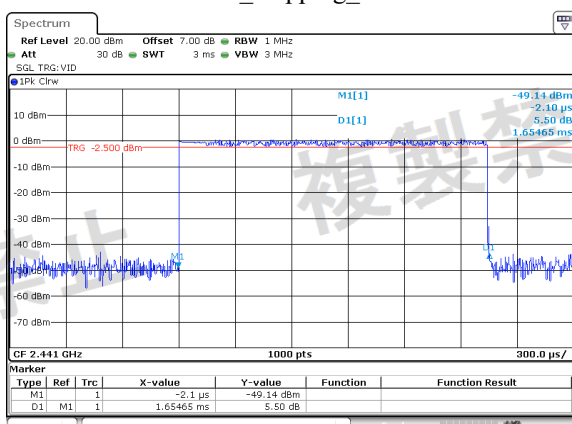
ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 17:53:33

8DPSK_Hopping_3DH3

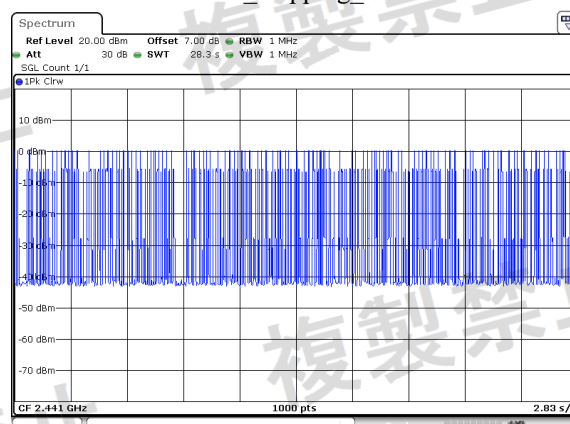
ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 10.NOV.2025 17:54:07

Test Condition: NV

8DPSK_Hopping_3DH3

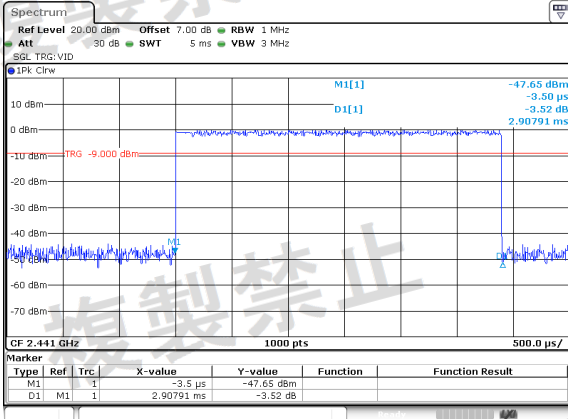
ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 5.NOV.2025 17:02:14

8DPSK_Hopping_3DH3

ProjectNo.:2501X79543E-RF Tester:Cheeb Huang
Date: 5.NOV.2025 17:02:48

Test Condition: HV

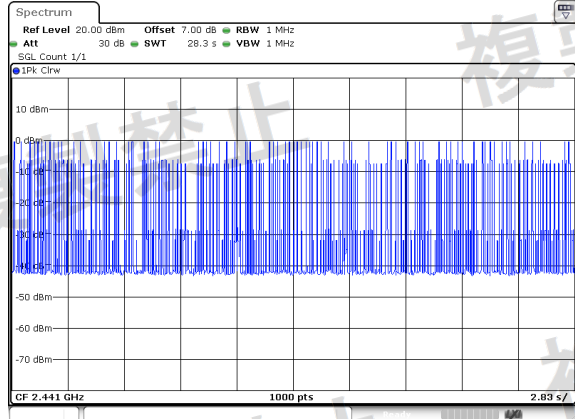
8DPSK_Hopping_3DH5



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang

Date: 10.NOV.2025 16:17:22

8DPSK_Hopping_3DH5

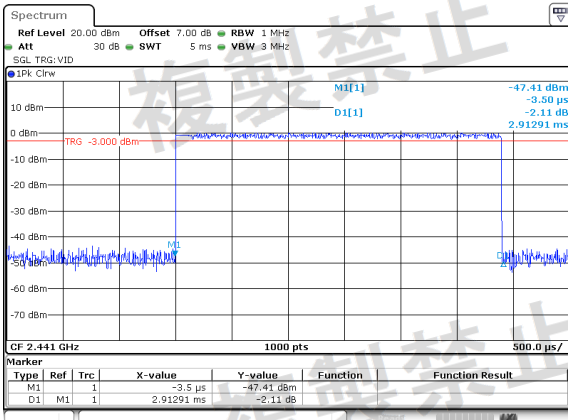


ProjectNo.:2501X79543E-RF Tester:Cheeb Huang

Date: 10.NOV.2025 16:17:26

Test Condition: LV

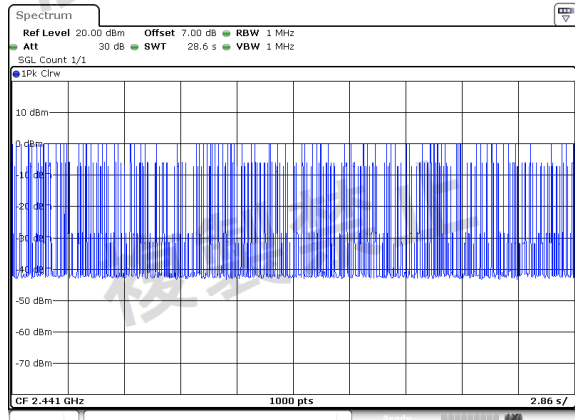
8DPSK_Hopping_3DH5



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang

Date: 10.NOV.2025 17:54:45

8DPSK_Hopping_3DH5

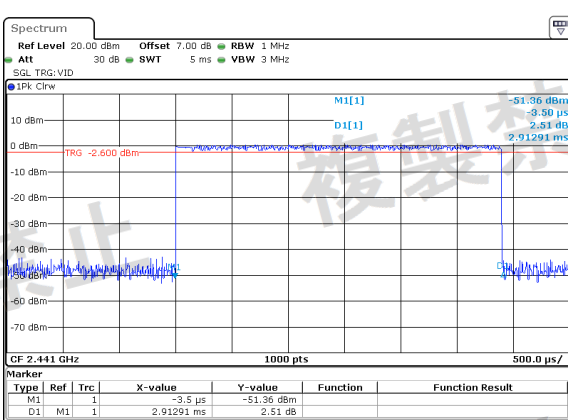


ProjectNo.:2501X79543E-RF Tester:Cheeb Huang

Date: 10.NOV.2025 17:55:19

Test Condition: NV

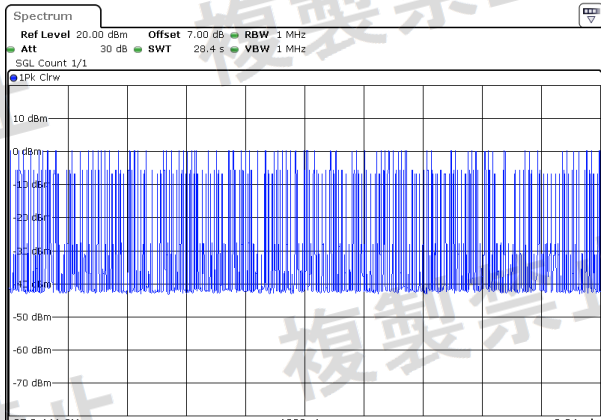
8DPSK_Hopping_3DH5



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang

Date: 5.NOV.2025 17:03:29

8DPSK_Hopping_3DH5



ProjectNo.:2501X79543E-RF Tester:Cheeb Huang

Date: 27.NOV.2025 12:02:58

Interference Prevention Function

Sample No.:	3AO6-3	Test Date:	2025/11/27
Test Site:	RF	Test Mode:	Transmitting
Tester:	Lee Li&Cheeb Huang	Test Result:	Good

Environmental Conditions:

Temperature: (°C)	26.1	Relative Humidity: (%)	55	ATM Pressure: (kPa)	101.1
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Test result: The EUT can transmit the identification automatically, the identification code is 26:BD:D4:3B:00:19.

CONSTRUCTION PROTECTION CONFIRMATION

Limit

The high-frequency section and modulation section of the radio equipment except for the antenna system shall not be capable of being opened easily.

Confirmation Result

The shell of EUT is sealed with buckles and glue, which will not be easily opened, please see the EUT photos.

EUT PHOTOGRAPHS

Please refer to the attachment 2501X79543E-RF-EXP External photo and 2501X79543E-RF-INP Internal photo.

TEST SETUP PHOTOGRAPHS

Please refer to the attachment 2501X79543E-RF-TSP Test Setup photo.

****END OF REPORT****